

BQ27Z561-R2 and BQ27Z558

Technical Reference Manual



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1.1 Read this First

This manual discusses the modules and peripherals of the BQ27Z561-R2 and BQ27Z558 device, and how each is used to build a complete battery pack gas gauge solution. *BQ27Z561-R2 Impedance Track™ Battery Gas Gauge Solution for 1-Series Cell Li-Ion Battery Packs Data Sheet* ([SLUSE22](#)).

1.2 Notational Conventions

The following notation is used if standard commands and data flash (DF) values are mentioned within a text block:

- Standard commands: *italics* with parentheses and no breaking spaces; for example, *RemainingCapacity()*
- Data flash (DF): *italics*, **bold**, and breaking spaces; for example, **Design Capacity**
- Register bits and flags: *italics* and brackets; for example, *[TDA]*
- Data flash bits: *italics* and **bold**; for example, **[LED1]**
- Modes and states: ALL CAPITALS; for example, UNSEALED

1.3 Trademarks

Impedance Track® is a registered trademark of Texas Instruments.
All trademarks are the property of their respective owners.

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The BQ27Z561-R2 and BQ27Z558 device provides a feature-rich gas gauging solution for single-cell battery pack applications. The device has extended capabilities, including:

- Fully integrated single-cell li-ion or li-polymer cell battery gauge solution
- Next-generation patented Impedance Track® technology accurately measures available charge in li-ion and li-polymer batteries
- Power modes:
 - NORMAL mode
 - SLEEP mode
 - DEEP SLEEP mode
 - OFF mode ($CE \leq V_{IL}$)
- Information available to external smart charger
 - JEITA
 - Charging current
 - Charging voltage
- Diagnostic lifetime data monitor
- Supports two-wire I²C interface
- Supports one-wire HDQ interface
- SHA-256 authentication
- Ultra-compact package: 12-ball DSBGA

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2.1 Introduction

The BQ27Z561-R2 and BQ27Z558 gauge contains an integrating analog-to-digital converter (ADC) for current measurement and a second order delta-sigma ADC for cell voltage and temperature measurements.

2.2 Current and Coulomb Counting

The integrating delta-sigma ADC in the gauge measures the charge/discharge flow of the battery by measuring the voltage drop across a small-value sense resistor between the SRP and SRN pins. The 16-bit integrating ADC measures bipolar signals from -0.10 V to 0.10 V with $3.74\text{-}\mu\text{V}$ resolution. The gauge reports charge activity when $VSR = V_{(SRP)} - V_{(SRN)}$ is positive, and discharge activity when $VSR = V_{(SRP)} - V_{(SRN)}$ is negative. This data is scaled and translated into mA using **CC Gain** and reported through *Current()*. The gauge uses this information for gauging and lifetime data logging functions. In NORMAL and SLEEP modes, the gauge continuously monitors the measured current and integrates the digital signal over time using an internal coulomb counter, which is also used for gauging.

In addition, the integrating ADC is sampled during voltage measurements and converted to mA in the same manner. This data is used for gauging (but not coulomb counting) and reported through Cell 1 Current in *DAStatus1()*.

The data reported through *Current()* can also have a deadband applied to it. This removes any noise or offset that has not been calibrated out from being reported as real current or from being accumulated by the coulomb counter in DOD0 Passed Q. This deadband value is programmed in **Deadband**.

2.3 Voltage

The second order delta-sigma ADC in the gauge measures the cell voltage at 1-s intervals in NORMAL mode, and **Voltage Time**-second intervals in SLEEP mode. This data is scaled and translated into mV using **Cell Gain** and reported through *Voltage()*. The gauge uses this information for gauging and lifetime data logging functions.

2.4 Temperature

2.4.1 Internal Temperature

The second order delta-sigma ADC in the gauge measures internal temperature at 1-s intervals in NORMAL mode and **Voltage Time**-second intervals in SLEEP mode. This data is translated into 0.1 K using the parameters in **Internal Temp Model** and reported through *InternalTemperature()*. The internal temperature can be used for gauging and lifetime data logging functions, and reported through *Temperature()* if **Temperature Enable[TSInt]** = 1.

2.4.2 Cell Temperature

The second order delta-sigma ADC in the gauge measures cell temperature via an external thermistor at 1-s intervals in NORMAL mode and **Voltage Time**-second intervals in SLEEP mode. This data is translated into 0.1 K using the parameters in **Cell Temp Model** and reported through *Temperature()* if **Temperature Enable[TS1]** = 1. The cell temperature can be used for gauging and lifetime data logging functions if **Temperature Enable[TS1]** = 1.

The cell temperature measurement requires an external 10-k Ω negative temperature coefficient (NTC) thermistor, such as the Semitec 103AT-2, connected between VSS and the TS pin.

2.4.3 Temperature Configuration

The following data flash parameter enables/disables the available temperature sensor options.

Class	Subclass	Name	Type	Min	Max	Default	Description
Settings	Configuration	Temperature Enable	H1	0x00	0x03	0x02	Determines whether the internal temperature (TSInt) or the external temperature (TS1 on TS pin) is reported with <i>Temperature()</i> . Bit 0: TSInt—Enables internal TS Bit 1: TS1—Enables external TS pin 0, 0: Neither enabled, <i>Temperature()</i> reports $-273.2K$. 0, 1: Enables internal TS, <i>Temperature()</i> reports the internal temperature. 1, 0: Enables TS1, <i>Temperature()</i> reports the value determined by thermistor on the TS pin. 1, 1: Both TSInt and TS1 are enabled, <i>Temperature()</i> reports the higher of the two values. Bits 7:2: Reserved



3.1 Introduction

To enhance battery life, the BQ27Z561-R2 and BQ27Z558 supports several power modes to minimize power consumption during operation.

3.2 NORMAL Mode

In NORMAL mode (also referred to as ACTIVE mode), the device takes voltage, current, and temperature readings every 1 s, performs gauging calculations, updates data, and makes status selections at 1-s intervals. Between these periods of activity, the device is in a reduced power state.

3.3 SLEEP Mode

3.3.1 Device Sleep

When the sleep conditions are met, the device goes into SLEEP mode with periodic wake-ups to reduce power consumption. The device returns to NORMAL mode if any exit sleep condition is met.

Status	Condition	Action
Activate	DA Config[SLEEP] = 1 AND Current() ≤ Sleep Current AND Voltage Time > 0 AND OperationStatusB()[DPSLEEP] = 0 AND Device in RELAX mode	The device goes to SLEEP mode. The device wakes up every Voltage Time to measure voltage and temperature. The device continues to coulomb count and update current every 4 s. Tip: Synchronize these two times to save power.
Exit	DA Config[SLEEP] = 0 OR Current() > Sleep Current OR Voltage Time = 0 OR OperationStatusB()[DPSLEEP] = 1	Return to NORMAL mode

The configuration options for SLEEP are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Power	Sleep	Sleep Current	I2	0	32767	15	mA	Current() threshold to enter SLEEP mode
Power	Sleep	Voltage Time	U1	1	20	5	s	Voltage sampling period in SLEEP mode

3.4 DEEP SLEEP Mode

DEEP SLEEP mode lowers power consumption and is entered through SLEEP mode. In DEEP SLEEP mode, the device takes data similar to SLEEP mode. The gauge's current consumption is reduced by measuring current periodically, instead of continuously. Exit from this mode is through a current level or a command, as indicated in the table below.

Status	Condition	Action
Activate	$(\text{Power Config}[\text{AUTO_DP_SLP_EN}] = 1 \text{ OR } \text{OperationStatusB}()[\text{DPSLEEP}M] = 1) \text{ AND } \text{wake comparator current} \leq \text{Deep Sleep Current}$	The device goes to DEEP SLEEP mode. The device wakes up every Deep Sleep Voltage Time to measure voltage, current, and temperature. The device updates <i>RemainingCapacity()</i> every 1 s, based on the last measured current. The device performs a low resolution measurement of wake comparator current every Wake Check Time . Wake comparator current is overwritten by the value of <i>Current()</i> when it updates at Deep Sleep Voltage Time (true for all modes).
Exit	$(\text{Power Config}[\text{AUTO_DP_SLP_EN}] = 0 \text{ AND } \text{OperationStatusB}()[\text{DPSLEEP}M] = 0) \text{ OR } \text{wake comparator current} > \text{Deep Sleep Current}$	Return to SLEEP mode

The configuration options for DEEP SLEEP are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Power	Sleep	Deep Sleep Voltage Time	U1	1	20	20	s	Determines the wake interval to measure voltage, current, and temperature in DEEP SLEEP mode
Power	Sleep	Wake Check Time	U1	0	20	1	s	Determines the wake interval to determine if required to return to SLEEP mode
Power	Sleep	Deep Sleep Current	I2	0	32767	10	mA	Wake Comparator Current must be lower than this value to allow DEEP SLEEP mode entry.

3.5 HIBERNATE Mode

This is the lowest power mode for the device. This mode can be entered only if the BQ27Z561-R2 has entered SLEEP mode. In this mode, all measurement and clocking circuits are turned off; thus, the mode should only be entered when no charging or discharging of the battery is expected (for instance, when the pack is out of the system). [Table 3-1](#) and [Table 3-2](#) show the conditions for entry and exit of the mode.

Table 3-1. Basic Hibernate

Status	Condition	Action
Activate	$(\text{Power Config}[\text{HIBERNATE}] = 1 \text{ AND } \text{OperationStatusB}()[\text{SLEEP}] = 1) \text{ AND } \text{OperationStatusB}().\text{HIBERNATE} = 1$	The device goes to HIBERNATE mode.
Exit	An I ² C message to the BQ27Z561-R2 is received.	The device returns to SLEEP mode.

The BQ27Z561-R2 can be configured to reenter HIBERNATE mode in the case of errant communication or noise on the I²C communication bus. [Table 3-2](#) shows the configuration items for the mode.

Table 3-2. Hibernate with Automatic Reentry

Status	Condition	Action
Activate	$(\text{Power Config}[\text{HIBERNATE}] = 1 \text{ AND } \text{Power Config}[\text{HIB_AUTO}] = 1 \text{ AND } \text{OperationStatusB}()[\text{SLEEP}] = 1) \text{ AND } \text{OperationStatusB}().\text{HIBERNATE} = 1$	The device goes to HIBERNATE mode.
Exit	Two I ² C messages to the BQ27Z561-R2 are received within Power.Auto Time seconds.	The device returns to SLEEP mode.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Power	Hibernate	Auto Time	U1	0	20	2	s	The device exits HIBERNATE mode if two I ² C communications are within the time window

3.6 Power Modes Configuration

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	Power Configuration	H1	0x00	0xFF	0x10	—	Bit 0: HIB_AUTO 0 = Disables automatic hibernation reentry 1 = Enables automatic hibernation reentry Bit 1: HIBERNATE 0 = Disables the Hibernate MAC 1 = Enables the Hibernate MAC Bits 3:2 Reserved Bit 4: SLP_ACCUM 0 = Disables CC accumulation during SLEEP mode 1 = Enables CC accumulation during SLEEP mode Bit 5: Reserved Bit 6: AUTO_DP_SLP_EN 0 = Automatic entry into DEEP SLEEP mode disabled 1 = Automatic entry into DEEP SLEEP mode enabled Bit 7: Reserved
Settings	Configuration	DA Configuration	H2	0x0000	0x0010	0x0010	—	Bits 3:0: Reserved Bit 4: SLEEP—SLEEP mode 0 = Disables SLEEP mode 1 = Enables SLEEP mode (default) Bits 15:5: Reserved

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4.1 Impedance Track (IT) Model

Predicting available energy from lithium-ion cells requires a number of measurable parameters. The Impedance Track (IT) model measures, records, and predicts available capacity or energy from these parameters. The model provides the means to accurately determine available energy over the life of a cell by accounting for aging and present environmental conditions. Aging can be accounted for by measuring QMax and cell impedances as the cell is cycled. QMax is the amount of charge available in a fully charged cell. The present conditions include consideration of cell and ambient temperature as well as the present or predicted power requirements. There are three major components of Impedance Track.

- One is measurement of QMax.
- Two is measurement of cell impedance.
- Three is the calculation of capacities.

All three components rely on the relationship of the open circuit voltage (OCV) versus depth of discharge (DOD). DOD is the percent of QMax removed from a cell during a no load discharge and goes to 100% when the cell is fully discharged. The OCV versus DOD relationship is fixed for each particular cell chemistry. QMax is determined by measuring the charge passed between two DOD points; the DOD points being determined from OCV measurements during Relax mode. Cell impedance is measured during constant load times during discharge from the difference of measured voltage to the OCV voltage based on the known DOD. The DOD determined from the most recent OCV reading and adjusted by the passed charge during the discharge. In general, capacities are recalculated based on changes in temperature, load or impedance. Capacity calculations use the known DOD, load, temperature, end-of-discharge voltage, **TermV**, and **QMax**.

4.2 Thermal Model

Because temperature changes significantly during the course of a discharge, the algorithm needs to be able to predict the future temperature. This is required for temperature correction of battery impedance during voltage simulation near the end of discharge. To achieve this, the algorithm collects temperature-time dependence data during discharge. This data is used to update parameters of a simple thermal model, including a heat exchange coefficient, **temp k**, and a thermal time constant, **temp k**. These parameters are updated at the same time as resistances. The algorithm also records the outside temperature during relaxation periods. These parameters are used to define a temperature function $T(t, T_{start})$ that calculates a temperature profile starting from the present temperature, T_{start} , and continuing until the end of discharge in the simulation calculation.

4.3 Gauging Capacities

The BQ27Z561-R2 measures individual cell voltages, pack voltage, temperature, and current. When at rest and *GaugingStatus[REST]* is set or when cell impedance is updated, the Impedance Track capacity calculation determines battery state-of-charge from DOD and temperature. The BQ27Z561-R2 measures charge and discharge activity by integrating the voltage across a small-value series sense resistor (1 mΩ typ.) between the negative terminal of the cell stack and the negative terminal of the battery pack. The battery state-of-charge is subsequently adjusted during load or charger application, using the integrated charge passed through the battery.

The device is capable of supporting a maximum battery pack capacity of 32 Ah. See the *Theory and Implementation of Impedance Track™ Battery Fuel-Gauging Algorithm in the bq20zxx Product Family Application Report (SLUA364)* for further details of the Impedance Track calculations.

The default for Impedance Track gauging is *off*. To enable the gauging function, set **Manufacturing Status[GAUGE_EN]** = 1. The gauging function will be enabled after a reset or a seal command is set. Alternatively, the MAC command *Gauging()* can be used to turn on and off the gauging function. *Gauging()* takes an immediate effect and the **[GAUGE_EN]** is also updated accordingly.

The *ITStatus1()*, *ITStatus2()*, and *ITStatus3()* commands return various gauging related information, which is useful to verify learned cell data was updated correctly, as well as problem analyses.

4.4 Learning Cycles

As described in [Section 4.3](#), IT is not enabled by default. When the BQ27Z561-R2 gauge receives an enable request, the gauge is then in its learning cycle mode. It is not necessary to use the gauge in this mode for all gauges during manufacture.

This mode helps to determine the golden image, which can be programmed into all gauges during the manufacture process. Learning cycles are generally run under lab conditions. When the golden image is learned by a gauge, the gauge is left in the IT learned mode of operation. Thus, when its data flash image is transferred to another gauge during manufacture, that gauge is then in learned mode; the gauge with this update will still need to receive an IT enable request. Requiring this request prevents the gauge from any unintended updates that could result from pack activity during manufacture. It would be one of the last commands to the pack before it is prepared for shipment. For more details, see the application note *Impedance Track™ Gas Gauge for Novices – bq20z70/z90 (SLUA397)*, which can be downloaded from Ti.com.

4.5 Impedance Track Configuration

Load Mode

During normal operation, the battery-impedance profile compensation of the Impedance Track algorithm can provide more accurate full-charge and remaining state-of-charge information if the typical load type is known. The two selectable options are constant current (**Load Mode** = 0) and constant power (**Load Mode** = 1).

Load Select

To compensate for the $I \times R$ drop near the end of discharge, the BQ27Z561-R2 must be configured for whatever current (or power) will flow in the future. While it cannot be exactly known, the BQ27Z561-R2 can use load history, such as the average current of the present discharge to make a sufficiently accurate prediction.

The BQ27Z561-R2 can be configured to use several methods of this prediction by setting the **Load Select** value. Because this estimate has only a second-order effect on remaining capacity accuracy, different measurement-based methods (methods 0–3, and method 7) result in only minor differences in accuracy. However, methods 4–6, where an estimate is arbitrarily assigned by the user, can result in a significant error if a fixed estimate is far from the actual load.

Constant Current (Load Mode = 0)	Constant Power (Load Mode = 1)
0 = Avg I Last Run	Avg P Last Run
1 = Present average discharge current	Present average discharge power
2 = <i>Current()</i>	<i>Current()</i> × <i>Voltage()</i>
3 = <i>AverageCurrent()</i>	<i>AverageCurrent()</i> × <i>Voltage()</i>
4 = Design Capacity mAh/5	Design Capacity cWh/5
5 = <i>AtRate()</i> (mA)	N/A
6 = User Rate-mA	User Rate-cW
7 = Max Avg I Last Run	Max Avg P Last Run

Pulsed Load Compensation and Termination Voltage

To take into account pulsed loads while calculating remaining capacity until **Term Voltage** threshold is reached, the BQ27Z561-R2 monitors not only average load, but also short load spikes. The maximum voltage deviation during a load spike is continuously updated during discharge and stored in **Delta Voltage**, with the minimum value allowed set in **Min Delta Voltage**. **Delta Voltage** is added to **Term Voltage** to determine end-of-discharge voltage (EDV).

Reserve Battery Capacity

The BQ27Z561-R2 allows an amount of capacity to be reserved in both mAh (**Reserve Cap-mAh**) and cWh (**Reserve Cap-cWh**) units between the point where the *RemainingCapacity()* function reports zero capacity and the absolute minimum pack voltage, **Term Voltage**. This enables a system to report zero capacity/energy, but still have enough reserve capacity/energy to perform a controlled shutdown or provide an extended sleep period for the host system.

Pack Based Termination Voltage

The BQ27Z561-R2 forces *RemainingCapacity()* to 0 mAh when the battery voltage discharges to **Term Voltage** for a period of **Term V Hold Time**.

A portion of the configuration options for Impedance Track is in the following data flash. Additional configuration options are located in the sections in which they are discussed.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Pack Resistance	I2	0	32767	0	mΩ	Value of the battery pack serial resistance that is NOT along the cell voltage measurement path of the gauge. This can include the resistance associated with FETs, traces, sense resistors, and any additional resistance in the path.
Gas Gauging	IT Cfg	System Resistance	I2	0	32767	0	mΩ	Value of the system serial resistance that is along the path from the battery pack to the system power converter input. This can include FETs, traces, sense resistors and any additional resistance in the path.
Gas Gauging	IT Cfg	Cell 1 Interconnect Resistance	I2	0	32767	0	2 ⁻¹⁰ Ω	Value of the battery pack serial resistance that is along the cell voltage measurement path of the gauge; that is, the negative rail to the bottom of the cell and the top of the cell to the gauge. This can include the resistance associated with FETs, traces, sense resistors, and any additional resistance in the path. The gauge will offset the measured resistance with this value to improve Ra accuracy.
Gas Gauging	IT Cfg	Term Voltage	I2	0	32767	3000	mV	Minimum pack voltage used in IT simulations. Term Voltage should be set to the minimum allowable voltage at the system power converter input. If it is desired to report 0% <i>RelativeStateOfCharge()</i> before the pack voltage reaches Term Voltage , it is recommended to increase Reserve Cap-mAh and Reserve Cap-cWh .
Gas Gauging	IT Cfg	Term V Hold Time	U1	0	255	2	s	When Term Voltage is met for Term V Hold Time , the <i>RemainingCapacity()</i> is set to 0 mAh.
Gas Gauging	IT Cfg	Max Simulation Iterations	U1	20	50	50	—	Enables the user to set the max number of simulation iterations IT is allowed to do. If the user finds that the watchdog is tripping, this number can be lowered.
Gas Gauging	IT Cfg	Simulation Near Term Delta	I2	0	32767	250	mV	Voltage delta from Term Voltage , which defines "near EDV" for IT simulations. If Term Voltage is increased, Simulation Near Term Delta should be decreased to keep Term Voltage + Simulation Near Term Delta around 3.2 V–3.5 V, the knee of the discharge curve.
Gas Gauging	IT Cfg	Min Delta Voltage	I2	-32768	32767	0	mV	The minimum Delta Voltage that is saved during discharge cycles
Gas Gauging	IT Cfg	Load Select	U1	0	7	1	—	Defines load compensation mode used by the gauging algorithm

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Load Mode	U1	0	1	1	—	Defines unit used by the gauging algorithm: 0 = Constant Current 1 = Constant Power
Gas Gauging	IT Cfg	User Rate-mA	I2	−9000	0	0	mA	Discharge rate used for capacity calculation selected by Load Select = 6
Gas Gauging	IT Cfg	User Rate-cW	I2	−32768	0	0	cW	Discharge rate used for capacity calculation selected by Load Select = 6
Gas Gauging	IT Cfg	Reserve Cap-mAh	I2	0	9000	0	mAh	Capacity reserved available when the gauging algorithm reports 0% <i>RelativeStateOfCharge()</i>
Gas Gauging	IT Cfg	Reserve Cap-cWh	I2	0	32000	0	cWh	Capacity reserved available when the gauging algorithm reports 0% <i>RelativeStateOfCharge()</i>
Gas Gauging	IT Cfg	Predict Ambient Time	U2	0	65535	2000	s	Wait time before the gauging algorithm starts to predict the ambient temperature during CHARGE and DISCHARGE modes (if [AMB_PRED] = 1). It is recommended to be set to 2× the value of Temp a to represent system thermal equilibrium.

The parameters updated by AND used for Impedance Track are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	State	Update Status	H1	0x00	0x0E	0x00	—	Bit 1:0: UPDATE1, UPDATE0 Update Status 0,0 = QMax NOT updated, Ra NOT updated 0,1 = QMax updated, Ra NOT updated 1,0 = QMax updated, Ra updated 1,1 = Unused Bit 2: Enables—Impedance Track gauging is enabled. This bit can only be changed via the <i>Gauging()</i> command. 0 = Disabled 1 = Enabled Bit 3: is_QMax_Field_Updated—QMax has updated in the field. 0 = Not updated 1 = Updated Bit 7:4: Reserved
Gas Gauging	State	Avg I Last Run	I2	−32768	32767	−500	mA	Average current last discharge cycle
Gas Gauging	State	Avg P Last Run	I2	−32768	32767	−192	cW	Average power last discharge cycle
Gas Gauging	State	Delta Voltage	I2	−32768	32767	0	mV	<i>Voltage()</i> delta between normal and short load spikes to optimize runtime calculation
Gas Gauging	State	Temp k	I2	0	32767	200	0.1°C/ 256 cW	Thermal model temperature factor
Gas Gauging	State	Temp a	I2	0	32767	1000	s	Thermal model temperature time constant
Gas Gauging	State	Max I Last Run	I2	−32768	32767	−500	mA	Max current last discharge cycle
Gas Gauging	State	Max P Last Run	I2	−32768	32767	−192	cW	Max power last discharge cycle

4.6 Gas Gauge Modes

Resistance updates take place only in DISCHARGE mode, while OCV and QMax updates only take place in RELAX mode. Fast QMax will update at the end of discharge (see [Section 4.7.2](#) for details). Entry and exit of each mode is controlled by data flash parameters in the subclass **Gas Gauging: Current Thresholds** section. When the device is determined to be in RELAX mode and OCV is taken, the *GaugingStatus()*[REST] flag is set. In RELAX mode or DISCHARGE mode, *BatteryStatus()*[DSG] is set. [Gas Gauge Operating Modes](#) shows the flow.

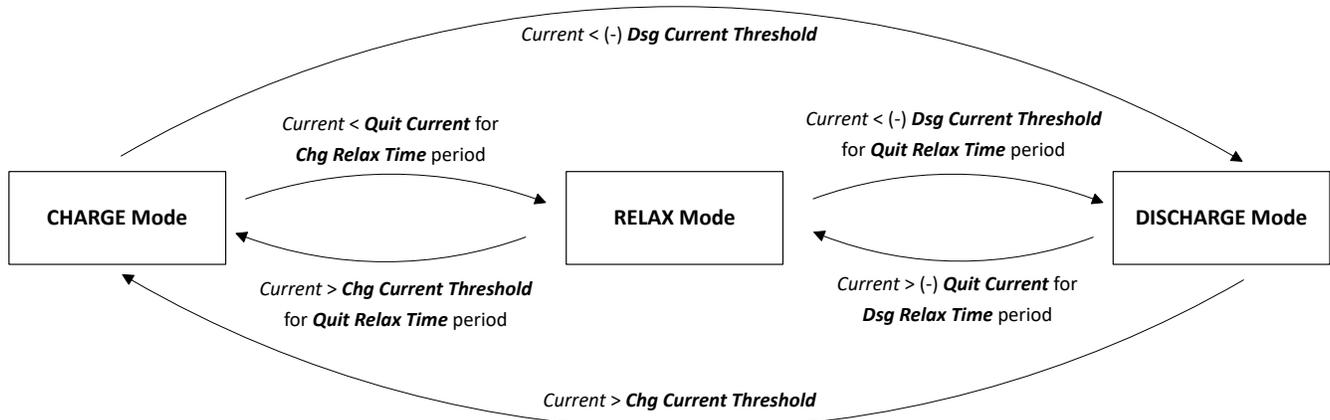


Figure 4-1. Gas Gauge Operating Modes

CHARGE mode is exited and RELAX mode is entered when *Current* goes below **Quit Current** for a period of **Chg Relax Time**. DISCHARGE mode is entered when *Current* goes below **(-)Dsg Current Threshold** for a period of **Quit Relax Time**. DISCHARGE mode is exited and RELAX mode is entered when *Current* goes above **(-)Quit Current** threshold for a period of **Dsg Relax Time**. CHARGE mode is entered when *Current* goes above **Chg Current Threshold** for a period of **Quit Relax Time**. Figure 4-2 shows an example of the operating modes.

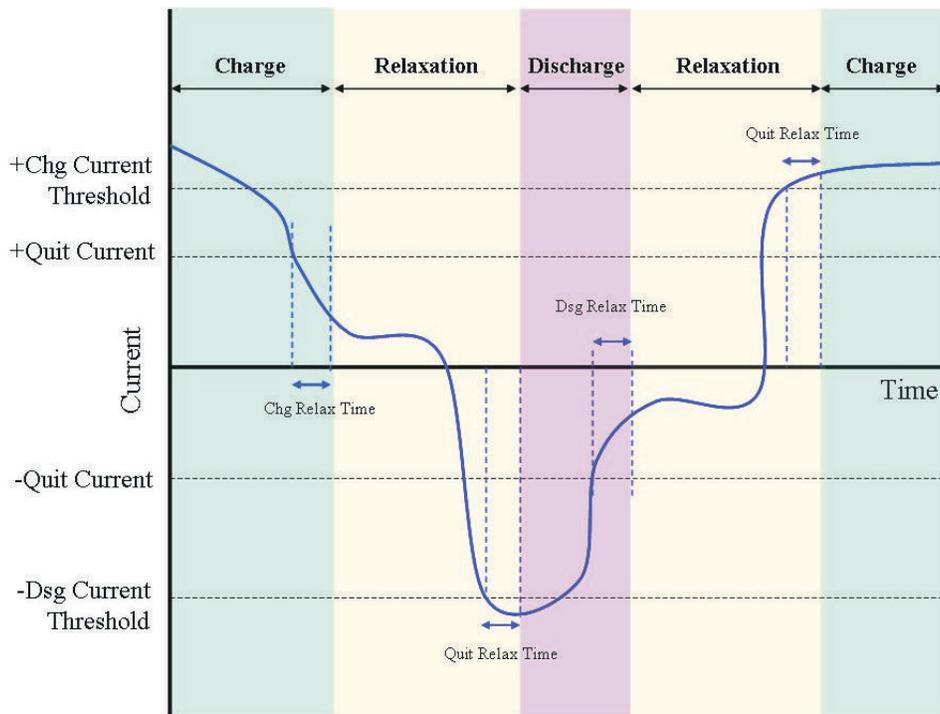


Figure 4-2. Gas Gauge Operating Mode Example

The configuration options for the gas gauge modes are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Current Thresholds	Dsg Current Threshold	I2	-32768	32767	60	mA	DISCHARGE mode <i>Current()</i> threshold
Gas Gauging	Current Thresholds	Chg Current Threshold	I2	-32768	32767	75	mA	CHARGE mode <i>Current()</i> threshold
Gas Gauging	Current Thresholds	Quit Current	I2	0	32767	40	mA	<i>Current()</i> threshold to enter RELAX mode

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Current Thresholds	Dsg Relax Time	U1	0	255	60	s	DISCHARGE to RELAX timeout
Gas Gauging	Current Thresholds	Chg Relax Time	U1	0	255	60	s	CHARGE to RELAX timeout
Gas Gauging	Current Thresholds	Quit Relax Time	U1	0	255	1	s	Relax to Discharge or Charge timeout

4.7 QMax and Ra

The total battery capacity is found by comparing states-of-charge before and after applying the load with the amount of charge passed. When an applications load is applied, the impedance of the cell is measured by comparing the open circuit voltage (OCV) obtained from a predefined function for the present state-of-charge with the measured voltage under load.

Measurements of OCV and charge integration determine the chemical state-of-charge (SOC) and chemical capacity (QMax). Ra is the impedance of the cell at 25°C at various states-of-charge.

The BQ27Z561-R2 acquires and updates the battery-impedance profile during normal battery usage. It uses this profile, along with the state-of-charge and QMax value, to determine *FullChargeCapacity()* and *RelativeStateOfCharge()* specifically for the configured load and present temperature. *FullChargeCapacity()* reports a capacity or energy available from a fully charged battery reduced by **Reserve Cap-mAh** or **Reserve Cap-cWh** under the configured load and present temperature until *Voltage()* reaches end-of-discharge voltage (EDV).

4.7.1 QMax Initial Values

The initial **QMax Cell 1** value should be taken from the cell manufacturers' data sheet multiplied by the number of parallel cells, and are also used for the **Design Capacity mAh** data flash value.

See the "Theory and Implementation of Impedance Track Battery Fuel-Gauging Algorithm" section in the *BQ20zxx Product Family Application Report (SLUA364)* for further details.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	State	QMax Cell 1	I2	0	32767	5359	mAh	QMax Cell 1
Gas Gauging	Design	Design Capacity mAh	I2	0	32767	5300	mAh	Design Capacity in mAh
Gas Gauging	Design	Design Capacity cWh	I2	0	32767	2040	cWh	Design Capacity in cWh
Gas Gauging	Design	Design Voltage	I2	0	32767	3850	mV	Design Voltage

4.7.2 QMax Update Conditions

4.7.2.1 Base Required Conditions

QMax learning/updates do not occur until the *GaugingStatus()[QEN]* flag is set by sending the *Gauging()* (0x0021) command to *AltManufacturerAccess()*.

The following conditions will prevent a QMax update when an OCV is taken.

Temperature If *Temperature()* is outside of the range 10°C to 40°C

Delta Capacity If the capacity change between suitable battery rest periods is less than 37%

Voltage If *Voltage()* is inside a flat voltage region. (See the *Support of Multiple Li-Ion Chemistries with Impedance Track Gas Gauges Application Report (SLUA372)* for the voltage ranges of other chemistries.) This flat region varies with different chemistries. The *GaugingStatus()[OCVFR]* flag indicates if the cell voltage is inside this flat region when *GaugingStatus()[REST]* is set. Prior to an exit from CHARGE or DISCHARGE mode, the *GaugingStatus()[QMAXDODOK]* flag can be checked to determine if the cell is in the flat zone.

Offset Error If the offset error accumulated during the time passed from the previous OCV reading exceeds 1.5% of **Design Capacity mAh**, the update is disqualified. Offset error current is calculated

as a function of **Coulomb Counter Deadband** and the sense resistor value. For applications with small battery capacities, an offset error of 1.5% of **Design Capacity mAh** can be reached in a short period of time, especially with a small sense resistor. Therefore, a minimum time of 11 hours from the last qualified OCV is enforced before disqualification, which facilitates QMax updates in such applications. Enforcing this minimum time can increase an offset error to as high as 5.5% of **Design Capacity mAh**.

4.7.2.2 Tracking QMax Updates

Several flags in *GaugingStatus()* are helpful to track QMax update conditions. The *[REST]* flag indicates an OCV is taken in RELAX mode. *[REST]* sets when the OCV is taken and clears when exiting RELAX mode. If the firmware has successfully made an OCV prediction, the *GaugingStatus[OCVPRED]* bit is set. The bit will clear if *GaugingStatus[REST]* gets set or when RELAX mode is exited. The *[VOK]* flag indicates the last OCV reading is qualified for the QMax update. *[VOK]* sets when exiting RELAX mode after an OCV that qualifies for QMax updates (including those that update QMax). *[VOK]* clears when a QMax update occurs, when a QMax update is disqualified based on an offset error (as described above), or upon a full reset. The *[QMAX]* flag toggles when a QMax update occurs. *ITStatus2()* and *ITStatus3()* return the QMax and DOD (the depth of discharge that corresponds to the OCV reading) data.

4.7.2.3 Relaxed Cell OCV

The BQ27Z561-R2 updates the no-load full capacity (QMax) when two open circuit voltage (OCV) readings are taken. These OCV readings are taken when the battery is in RELAX mode before and after a minimum charge or discharge activity. A relaxed state is achieved if the battery voltage has a dV/dt of $< 1 \mu V/s$. Typically, it can take up to two hours after charging and five hours after discharging to ensure that the dV/dt condition is satisfied. If five hours are exceeded, a reading is taken even if the dV/dt condition was not satisfied. This relaxed cell state is indicated when the *[REST]* flag is set.

4.7.2.4 OCV Prediction

Another method available in the BQ27Z561-R2 gauge is to estimate an accurate OCV reading. After a set wait time (**OCV Pred Transient T**) in RELAX mode, the gauge begins to accumulate voltage readings. Once **OCV Pred Measure Time** has passed, the gauge uses a fast OCV algorithm to predict the final OCV value. This fast OCV method is enabled by setting *IT Gauging Ext[FOCV_EN]* = 1. This method provides the benefit of reduced relaxation requirements for QMax updates. If at any time the requirements for the conventional OCV method are achieved (dV/dt of $< 1 \mu V/s$ requirement) after a fast OCV estimation, the device updates the OCV measurement accordingly. For a fast OCV estimate, entry into RELAX mode must be preceded by at least **OCV Pred Active T Limit** of a charge or discharge current large enough for the BQ27Z561-R2 to exit RELAX mode.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	OCV Pred Active T Limit	U2	100	65535	200	s	This is the minimum time the gauge must be in CHARGE or DISCHARGE mode before entering into RELAX mode for a fast OCV estimate.
Gas Gauging	IT Cfg	OCV Pred Transient T	U2	100	65535	300	s	This is the minimum time the gauge must be in RELAX mode before fast OCV voltage readings start to accumulate.
Gas Gauging	IT Cfg	OCV Pred Measure Time	U2	0	65535	200	s	This is the time in RELAX mode when fast OCV voltage readings are accumulated and fast OCV is predicted.

4.7.2.5 Cycle Count Based QMax Degradation

For a gauging situation that never or rarely meets the condition for any of the previously described QMax updates, QMax will update and diminish based on a cycle count. The gauge tracks full discharge cycles since the last QMax update was determined via one of the above methods. When this cycle count reaches **Cycle Adjust Threshold**, QMax updates as $QMax = QMax \times (1 - (Cycle Adj Incr \times Cycle Adjust Threshold / 10000))$.

4.7.2.6

Note

When there is a QMax update, the discharge cycle count since the last QMax update is set to 0. The discharge cycle count since the last QMax update is incremented each time *CycleCount()* is incremented.

4.7.2.7 Fast QMax Update Conditions

The Fast QMax update conditions are very similar to the QMax update conditions with the following differences:

- Instead of taking two OCV readings for a QMax update, a Fast QMax update requires only one OCV reading AND
- The battery pack should discharge below 10% RSOC.

The differences in requirements enable the Fast QMax feature to have a QMax update at the end of discharge (given one OCV reading is already available and discharge < 10% RSOC) without a longer relax time after a discharge event. The temperature, delta capacity, voltage, and offset error requirements for a QMax update are still required for the Fast QMax update.

This feature is particularly useful for reducing production QMax learning cycle time or for an application that is mostly in CHARGE or DISCHARGE state with infrequent relaxation. Setting **IT Gauging Configuration[FAST_QMAX_LRN] = 1** enables Fast QMax during production learning only (that is, **Update Status = 06**). When setting **IT Gauging Configuration[FAST_QMAX_FLD] = 1**, Fast QMax is enabled when Impedance Track is enabled and **Update Status = 06** or **0E**.

The DOD is taken for QMax at a high state-of-charge, then during discharge when at the steep portion of the voltage curve (92–96% DOD). This enables a good estimation of DOD. This DOD estimation during discharge is used to update QMax immediately instead of first needing a rest period. The actual update to QMax occurs when the discharge stops after verifying that no conditions are present to cause the QMax update to fail. The BQ27Z561-R2 device has an option to qualify DODEOC for QMax updates, which means it is possible to update QMax with no rest periods (by having a charge termination followed by a full discharge). Fast QMax can be enabled in either LEARN mode (**FAST_QMAX_LRN**) or FIELD mode (**FAST_QMAX_FLD**). The LEARN mode flag means Fast QMax is only enabled with **Update Status = 06**, and will be disabled when the status = 0x0E. FIELD mode means Fast QMax is enabled with **Update Status = 06** and **0E**.

4.7.2.8 QMax and Fast QMax Update Boundary Check

The BQ27Z561-R2 implements a QMax and Fast QMax boundary check prior to saving the value to data flash. This improves the robustness of the QMax update in case of potential QMax corruption during the update process.

The verifications are as follows:

1. Verify that the updating QMax or Fast QMax value is within **Qmax Delta** of the present QMax (above or below). **Qmax Delta** is the maximum allowed QMax change for each update, expressed as a percentage of **Design Capacity mAh**. If the updating value is outside of this range, the QMax change is capped to $(\mathbf{QMax\ Delta} \times \mathbf{Design\ Capacity\ mAh}) / 100$.
2. Bound the QMax value to a maximum of **Qmax Upper Bound**. **Qmax Upper Bound** is expressed as a percentage of **Design Capacity mAh**. If the updating value is above this maximum, the QMax update is capped to $(\mathbf{Qmax\ Upper\ Bound} \times \mathbf{Design\ Capacity\ mAh}) / 100$.
3. Ensure that QMax is greater than 0 mAh.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	QMax Delta	U1	3	100	5	%	Maximum allowed QMax change from its previous value. The QMax change will be capped by this setting if the delta from the previous QMax is larger than QMax Delta . QMax Delta is a percentage of Design Capacity mAh .

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Qmax Upper Bound	U1	100	255	130	%	Maximum QMax value over the lifetime of the pack. If the updated QMax value is larger than this setting, the updated QMax will be capped to Qmax Upper Bound . Qmax Upper Bound is a percentage of Design Capacity mAh .

4.7.3 Ra Table Initial Values

The Ra table is part of the impedance profile that updates during discharge when gauging is enabled. The initial **Cell0 R_a0...14** values should be programmed by selecting the correct chemistry data during data flash configuration. A chemistry database is constantly updating, and can be downloaded from the Gas Gauge Chemistry Updater product web page (<http://www.ti.com/tool/gasgaugechem-sw>). The initial **xCell0 R_a0...14** values are a copy of the non-x data set. Two sets of Ra tables are used alternatively when gauging is enabled to prevent wearing out the data flash.

The **Cell0 R_a flag** and the **xCell0 R_a flag** indicate the validity of the cell impedance table for the cell.

Note

Firmware updates these values: It is not recommended to change them manually.

4.7.3.1 R_a0 Table

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Ra Table	R_a0	Cell0 R_a flag	H2	0x0000	0xFFFF	0xFF55	—	High Byte: 0x00: Cell Impedance and QMax updated 0x05: RELAX mode and QMax update in progress 0x55: DISCHARGE mode and cell updated 0xFF: Cell impedance never updated Low-Byte: 0x00: Table not used and QMax updated 0x55: Table being used 0xFF: Table never used, no QMax or cell impedance update
Ra Table	R_a0	Cell0 R_a 0	I2	0	32767	159	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 0
Ra Table	R_a0	Cell0 R_a 1	I2	0	32767	58	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 1
Ra Table	R_a0	Cell0 R_a 2	I2	0	32767	65	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 2
Ra Table	R_a0	Cell0 R_a 3	I2	0	32767	79	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 3
Ra Table	R_a0	Cell0 R_a 4	I2	0	32767	90	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 4
Ra Table	R_a0	Cell0 R_a 5	I2	0	32767	63	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 5
Ra Table	R_a0	Cell0 R_a 6	I2	0	32767	76	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 6
Ra Table	R_a0	Cell0 R_a 7	I2	0	32767	82	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 7
Ra Table	R_a0	Cell0 R_a 8	I2	0	32767	82	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 8
Ra Table	R_a0	Cell0 R_a 9	I2	0	32767	87	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 9
Ra Table	R_a0	Cell0 R_a 10	I2	0	32767	87	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 10
Ra Table	R_a0	Cell0 R_a 11	I2	0	32767	101	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 11
Ra Table	R_a0	Cell0 R_a 12	I2	0	32767	118	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 12
Ra Table	R_a0	Cell0 R_a 13	I2	0	32767	191	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 13
Ra Table	R_a0	Cell0 R_a 14	I2	0	32767	282	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 14

4.7.3.2 R_a0x Table

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Ra Table	R_a0x	xCell0 R_a flag	H2	0x0000	0xFFFF	0xFFFF	—	High-Byte: 0x00: Cell Impedance and QMax updated 0x05: RELAX mode and QMax update in progress 0x55: DISCHARGE mode and cell updated 0xFF: Cell impedance never updated. Low-Byte: 0x00: Table is not used and QMax updated. 0x55: Table is being used. 0xFF: Table was never used and no QMax or cell impedance was updated.
Ra Table	R_a0x	xCell0 R_a 0	I2	0	32767	159	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 0
Ra Table	R_a0x	xCell0 R_a 1	I2	0	32767	58	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 1
Ra Table	R_a0x	xCell0 R_a 2	I2	0	32767	65	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 2

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Ra Table	R_a0x	xCell0 R_a 3	I2	0	32767	79	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 3
Ra Table	R_a0x	xCell0 R_a 4	I2	0	32767	90	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 4
Ra Table	R_a0x	xCell0 R_a 5	I2	0	32767	63	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 5
Ra Table	R_a0x	xCell0 R_a 6	I2	0	32767	76	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 6
Ra Table	R_a0x	xCell0 R_a 7	I2	0	32767	82	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 7
Ra Table	R_a0x	xCell0 R_a 8	I2	0	32767	82	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 8
Ra Table	R_a0x	xCell0 R_a 9	I2	0	32767	87	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 9
Ra Table	R_a0x	xCell0 R_a 10	I2	0	32767	87	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 10
Ra Table	R_a0x	xCell0 R_a 11	I2	0	32767	101	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 11
Ra Table	R_a0x	xCell0 R_a 12	I2	0	32767	118	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 12
Ra Table	R_a0x	xCell0 R_a 13	I2	0	32767	191	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 13
Ra Table	R_a0x	xCell0 R_a 14	I2	0	32767	282	2 ⁻¹⁰ Ω	Cell 0 resistance at grid point 14

4.7.4 Ra Table Update Conditions

The impedance is different across different DOD states. The cell has 15 Ra grid points representing the impedance from 0%–100% DOD. In general, the Ra table is updated during discharge. The *GaugingStatus()*[RX] flag will toggle when the Ra grid point is updated. The Ra update is disabled if any of the following conditions are met. The *GaugingStatus()*[RDIS] is set to indicate the Ra update is disabled.

- During the optimization cycle, the Ra update is disabled until QMax is updated (that is, Ra will not be updated if **Update Status** = 4).
- The Ra update is disabled if the charge accumulation error > 5% of **Design Capacity mAh**.
- During a discharge, a negative resistance is measured.

A valid OCV reading during RELAX mode or a Fast QMax update without an OCV read will clear the [RDIS] flag.

The configuration options related to Ra table updates are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Resistance Parameter Filter	U2	1	65535	65142	—	This is the filter coefficient on voltage, current, and temperature for resistance updates. Reducing this filter setting can improve low temperature performance at high rates. Examining the Term Voltage Delta setting and Fast Scale Start SOC should be done prior to adjusting this parameter when trying to improve the RSOC performance. The following is the formula to convert the DF setting into actual filter time constant: Filter time constant = $[1/(1 - (DF_Value / 65536))]$ - 1.
Gas Gauging	IT Cfg	Max Charge Current %	U1	0	100	10	%	If <i>AverageCurrent()</i> changes by more than this threshold from the previous resistance measurement to the present, the present resistance measurement and Ra scale update are not used. This protects resistance measurements from voltage transients after step changes in current, especially transitions to relaxation.
Gas Gauging	IT Cfg	Resistance Update Voltage	I2	0	32767	50	mV	The difference between the open circuit voltage based on DOD and the measured voltage is estimated as the IR drop. If this IR drop is greater than Resistance Update Voltage , then the resistance calculation is allowed. This can be helpful in applications with small battery packs and large resistances that do not meet the C/10 minimum current requirement for resistance updates.
Gas Gauging	IT Cfg	Ra Filter	U2	0	999	800	0.1%	Filter value used in Ra updates that specifies what percentage of the Ra update is from the new value (100%—setting) versus the old value (setting). The recommended setting is 80% if fast resistance scaling is enabled. Otherwise, the setting should be 50% as the default.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Ra Max Delta	U1	0	255	15	% of Design Resistance	Maximum value of allowed Ra change
Gas Gauging	IT Cfg	Design Resistance	I2	1	32767	90	mΩ	Cell resistance at grid point 4. Automatically updated during learning when Update Status is set by the gauge to 06 and 0E. To automatically update again, set Update Status to 04. Design Resistance could be set manually when Update Status = 0E.

4.7.5 Fast Resistance Scaling

At low temperatures and very high discharge rates, using cell resistance directly from interpolating Ra table grids can lead to higher errors in RSOC. This is especially true near the end of discharge when cell resistance is changing quickly, which could cause undesirable drops to 0% RSOC. Fast resistance scaling is an algorithm that improves RSOC convergence to 0% by scaling cell resistance values from Ra table interpolation to reflect the most recent measured resistance.

The following terms are defined to understand the operation of fast resistance scaling:

- True RSOC: The true relative state-of-charge of the battery pack, as determined by the gauge. It is computed as True Rem Q / True Full Chg Q.
- Resistance voltage: A filtered cell voltage used for resistance measurements with a time constant defined by **Near EDV Ra Param Filter** (or **Resistance parameter filter** if **IT Gauging Configuration[FF_NEAR_EDV]** = 0).
- Average voltage: A filtered pack voltage with the same time constant as *AverageCurrent()*.

4.7.5.1 Calculation of Resistance Scale

When enabled with **IT Gauging Configuration[RSOC_CONV]** = 1, fast resistance scaling becomes active once one of the following is true:

- True RSOC ≤ **Fast Scale Start SOC** OR
- Resistance voltage < **Term Voltage + Term Voltage Delta**.

For most applications, the default values of **Term Voltage Delta** and **Fast Scale Start SOC** are recommended. It is typically best to keep **Term Voltage + Term Voltage Delta** around 3.2 V–3.5 V, the knee of the discharge curve, for most battery applications.

Once active, every 30 seconds the algorithm calculates a new cell resistance scale as $(R_{\text{new}} / R_{\text{old}}) \times 1000$, where R_{new} is the most recent measured cell resistance and R_{old} is the interpolated cell resistance at the present DOD. The raw scale is reported on Cell 1 RaScale. After a scale is calculated, an IT simulation is triggered to utilize the new resistance information. In addition, the scale is used for ambient temperature prediction (if enabled).

As a safeguard, the scale is limited to a minimum of 200 and a maximum of 5000 when applied, but Cell 1 RaScale maintains the raw scale. For clarity, a scale of 200 corresponds to 0.2 (reducing cell resistance) and 5000 corresponds to 5.0 (increasing cell resistance).

4.7.5.2 Negative Resistance Scale

If a negative scale is calculated, it usually indicates significant error in QMax or an incorrect DOD0, which could be from system loading during initialization. When this occurs, Cell 1 RaScale resets to 1000 and **GaugingStatus()[NSFM]** sets to 1. The gauge attempts to correct the error in DOD by adjusting DOD0 such that $\text{DOD0} + (\text{DOD0 Passed Q} / \text{QMax})$ equals the DOD computed from voltage, current, and temperature used for resistance.

4.7.5.3 Reset of Resistance Scale

Cell 1 RaScale resets to 1000 under the following conditions:

- Initialization of the device
- IT is enabled (**GaugingStatus()[QEN]** changes to 1).

- In CHARGE mode when average voltage > **Term Voltage + Term V Delta** AND True RSOC > **Fast Scale Start SOC**.
- In RELAX mode when an OCV reading occurs with *Temperature()* > 15.0°C.
- In DISCHARGE mode when a negative resistance scale is calculated.

4.7.5.4 Application of Resistance Scale

The scale can be applied in two ways:

- If **IT Gauging Configuration[DOD_RSCALE_EN]** = 0, the resistance scale is applied across all DODs.
- If **IT Gauging Configuration[DOD_RSCALE_EN]** = 1, the resistance scale is only applied to DODs greater than or equal to the DOD at which it was calculated.

Setting **IT Gauging Configuration[DOD_RSCALE_EN]** = 1 is recommended because it reduces the sensitivity of FCC to large changes in the resistance scale.

4.7.5.5 Fast Resistance Scaling Configuration

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	IT Cfg	Term Voltage Delta	I2	0	32767	200	mV	Controls when fast resistance scaling becomes active when [RSOC_CONV] = 1. If Term Voltage is increased, Term Voltage Delta should be decreased to keep Term Voltage + Term Voltage Delta around 3.2 V–3.5 V, the knee of the discharge curve.
Gas Gauging	IT Cfg	Fast Scale Start SOC	U1	0	100	10	%	Controls the RSOC % that fast resistance scaling becomes active when [RSOC_CONV] = 1. The default value is recommended, however, it may be appropriate to adjust this value in certain applications to be around the knee of the discharge curve.
Gas Gauging	IT Cfg	Near EDV Ra Param Filter	U2	1	65535	62184	—	Ra filter used in the fast resistance scaling region if [FF_NEAR_EDV] = 1. The default value should be used.

4.8 FullChargeCapacity (FCC), RemainingCapacity (RemCap), and RelativeStateOfCharge (RSOC)

The Impedance Track algorithm applies QMax, impedance, temperature, voltage, and current data to predict the runtime *FullChargeCapacity()*, *RemainingCapacity()*, and *RelativeStateOfCharge()*. These values are updated if any of the following conditions are met, reflecting the battery capacity in real time:

- QMax update occurs
- Ra update occurs
- At onset of charge and discharge
- Valid charge termination
- Every 1 hour in RELAX mode after an OCV has been taken
- If temperature changes more than 5°C
- Every second when current is measured and passed charge is accumulated

4.8.1 Smoothing Engine

The gauge provides an engine that ensures *FullChargeCapacity()*, *RemainingCapacity()*, and *RelativeStateOfCharge()* change smoothly, which can be desirable in certain system applications. This smoothing engine is enabled when **IT Gauging Configuration[SMOOTH]** = 1. The true and smooth versions of FCC, RemCap, and RSOC are always available, but **IT Gauging Configuration[SMOOTH]** selects which version is reported on the standard commands.

When the smoothing engine is enabled, there are specific cases that can be handled differently based on user preference.

4.8.1.1 Smoothing to 0% in DISCHARGE Mode

When **IT Gauging Configuration**[*DSG_0_SMOOTH_OK*] = 1, smoothing to 0% in DISCHARGE mode is enabled. For preventing jumps to 0% in DISCHARGE mode, two data flash parameters are used: **Term Smooth Start Cell V Delta** and **Term Smooth Time**. If *Voltage()* is less than or equal to **Term Voltage + Term Smooth Start Cell V Delta** while in DISCHARGE mode, time-based smoothing to 0% is initiated. *RemainingCapacity()* smoothly converges to 0 mAh over the next **Term Smooth Time** seconds. Time-based smoothing to 0% will continue unless CHARGE mode is entered.

Term Smooth Final Cell V Delta ensures that the gauge reports 0% before voltage drops too low. If *Voltage()* is less than or equal to **Term Voltage – Term Smooth Final Cell V Delta** while in DISCHARGE mode, *RemainingCapacity()* will be forced to 0 mAh, even if time-based smoothing to 0% was active.

Note

Term Smooth Final Cell V Delta can be disabled by setting equal to **Term Voltage**, but is typically expected to be low enough to enable the system to shut down properly (without brownout).

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Smoothing	Term Smooth Start Cell V Delta	I2	0	32767	150	mV	If [<i>DSG_0_SMOOTH_OK</i>] = 1, then during DISCHARGE mode and once <i>Voltage()</i> is less than or equal to Term Voltage + Term Smooth Start Cell V Delta , time-based smoothing to 0% is initiated. This will smooth <i>RemainingCapacity()</i> to 0 mAh over the next Term Smooth Time seconds.
Gas Gauging	Smoothing	Term Smooth Final Cell V Delta	I2	0	32767	100	mV	If [<i>DSG_0_SMOOTH_OK</i>] = 1, then during DISCHARGE mode and once <i>Voltage()</i> is less than or equal to Term Voltage + Term Smooth Final Cell V Delta , <i>RemainingCapacity()</i> is forced to 0 mAh.
Gas Gauging	Smoothing	Term Smooth Time	U1	1	32767	20	s	If [<i>DSG_0_SMOOTH_OK</i>] = 1, then during DISCHARGE mode and once <i>Voltage()</i> is less than or equal to Term Voltage + Term Smooth Start Cell V Delta , time-based smoothing to 0% is initiated. This will smooth <i>RemainingCapacity()</i> to 0 mAh over the next Term Smooth Time seconds.

4.8.1.2 Smoothing to 100% in CHARGE Mode

When **IT Gauging Ext**[*CHG_100_SMOOTH_OK*] = 1, smoothing to 100% in CHARGE mode is enabled. For preventing jumps to 100% in CHARGE mode, this feature uses the valid charge termination logic to predict when charging will complete. Refer to [Valid Charge Termination](#) for the full set of details. The valid charge termination logic requires two consecutive 40-s windows that meet all taper conditions. After the first 40-s window is satisfied, time-based smoothing to 100% will be initiated. *RemainingCapacity()* smoothly converges to *FullChargeCapacity()* over the next 40-s window.

4.8.1.3 Smoothing in RELAX Mode

IT Gauging Configuration[*RELAX_JUMP_OK*] and **IT Gauging Configuration**[*RELAX_SMOOTH_OK*] determine the behavior of *RelativeStateOfCharge()* during RELAX mode.

When **IT Gauging Configuration**[*RELAX_JUMP_OK*] = 1, *RelativeStateOfCharge()* is allowed to jump during RELAX mode. When **IT Gauging Configuration**[*RELAX_JUMP_OK*] = 0, *RelativeStateOfCharge()* holds constant during RELAX mode and any RSOC jump will be passed onto CHARGE and DISCHARGE mode.

When **IT Gauging Configuration**[*RELAX_SMOOTH_OK*] = 1, *RelativeStateOfCharge()* is NOT allowed to jump during RELAX mode. Any RSOC jumps during RELAX mode are smoothed out over a period of **Smooth Relax Time**. If **Smooth Relax Time** is not reached, the remaining portion of the RSOC jump will be passed onto CHARGE and DISCHARGE mode.

If both bits are set to 1, **IT Gauging Configuration**[RELAX_JUMP_OK] takes higher priority and *RelativeStateOfCharge()* is allowed to jump during RELAX mode.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Smoothing	Smooth Relax Time	I2	1	32767	1000	s	If [RELAX_SMOOTH_OK] = 1, the delta remaining capacity and full charge capacity are smoothed over this set period of time. It is recommended to use the default setting.

4.9 Impedance Track (IT) Configuration Options

The BQ27Z561-R2 provides several Impedance Track configuration options to fine-tune the gauging performance. These configurations can be turned on or off through the corresponding flags in **Settings: IT Gauging Configuration** and **I2C Gauging Configuration**.

[LOCK0]: After a discharge event, cell voltage usually recovers to a slightly higher voltage during RELAX mode. A new OCV reading during this time can result in a slightly higher state-of-charge. This flag provides an option to keep *RemainingCapacity()* and *RelativeStateOfCharge()* locked during relaxation after 0% and *GaugingStatus()* [FD] are reached during discharge. The lock is removed once CHARGE mode is entered.

[1PERCENT_HOLD]: When enabled, holds the RSOC value at 1% until **Term Voltage** has been reached during discharge.

[RSOC_HOLD]: An IT simulation will run at the onset of discharge. If charge terminates at a low temperature and discharge occurs at a higher temperature, the difference in temperature could cause a small rise of RSOC for a short period of time at the beginning of discharge. This flag option prevents RSOC rises during discharge. RSOC will be held until the calculated value falls below the actual state.

[RSOCL]: When set, RSOC will be held to 99% until charge termination is detected.

[RFACTSTEP]: The gauge keeps track of the change in Ra over 15 updates. It is limited to 1.5 max. During an Ra update, if (new Ra)/(old Ra) > 1.5 or < 0.5, the gauge will take different actions based on the setting of this flag.

If the flag is set to 1 (default), the gauge allows Ra to update once using the max factor of 1.5 or min factor of 0.5, then disables the Ra update. If this flag is set to 0, the gauge will not update Ra, but will disable it. It is recommended to keep the default setting. In both cases, *GaugingStatus()*[RDIS] is set.

[OCVFR]: An OCV reading is taken when a dV/dt condition is met. This is not the case if charging stops within or below the flat voltage region, which varies with ChemID. The change of cell voltage in this region is very small; therefore, the same voltage error can correspond to a larger DOD error. This flag is set by default. The device waits 48 hours before taking an OCV reading if charging stops prematurely. A short discharge will not cancel this 48-hour wait. An OCV reading is taken when the dV/dt condition is met. To reduce test time during evaluation, it is helpful to remove the 48-hour wait-time requirement.

[DOD0EW]: DOD0 readings have an associated error based on the elapsed time since the reading, the conditions at the time of the reading (reset, charge termination, and so on), the temperature, and the amount of relax time at the time of the reading, among others. This flag provides an option to take into account both the previous and new calculated DOD0, which are weighted according to their respective accuracies. This can result in improved accuracy and in reduction of RSOC jumps after relaxation.

[LFP_RELAX]: When enabled, this bit activates an additional functionality only if the chemistry ID programmed indicates a LiFePO₄ chemistry (ID 0x4xxx or 0x04xx). Having this bit enabled with a non-LiFePO₄ cell type does not introduce any behavioral modifications.

LiFePO₄ has a unique, slow configuration relaxation near full charge. The slow decaying voltage causes RSOC to continue to drop every 5 hours. Depending on the full charge taper current, the fully settled voltage could be close to or even below **FlatVoltMax** in some cases. If **[LFP_RELAX]** is enabled and the LiFePO₄ chemID is selected, **[OCVFR]** will be set on exit from CHARGE mode regardless of voltage or state of charge. For **[OCVFR]** to clear, a relaxation of 48 hours or non-trivial discharge must occur. A non-trivial discharge is

indicated when the cell voltage in relaxation falls below **FlatVoltMin**. The QMax update is unlikely disabled because DOD will not update due to **[OCVFR]** forcing the 48-hour timeout, and voltage likely relaxing into the flat zone. Therefore, the QMax update takes an alternative approach: Once full charge occurs (**[FC]** bit set), DOD0 = Dod_at_EOC is automatically assigned and valid for a QMax update. **[VOK]** is set if there is no QMax update. If QMax is updated, **[VOK]** is cleared. The DOD error, as a result of this action, is zero or negligible because in the LiFePO₄ table, the OCV voltage corresponding to DOD = 0 is much lower. **[RSOC_CONV]**: This function is also called fast resistance scaling. It is an option to address the convergence of RSOC to 0% at a low temperature and a very high rate of discharge. See [Fast Resistance Scaling](#) for more details.

[FAST_QMAX_LRN] and **[FAST_QMAX_FLD]**: The first flag enables Fast QMax during the learning cycle when **Update Status** = 06. The second bit enables Fast QMax in the field when **Update Status** ≥ 06. See [Fast QMax Update Conditions](#) for more details on Fast QMax.

[FF_NEAR_EDV]: Fast filter near EDV. If this flag is set to 1, the gauge applies an alternative filter, **Near EDV Ra Param Filter**, for an Ra update in the fast scaling region (starting around 10% RSOC). This flag should be kept to 1 as a default. If this flag is set to 0, the gauge uses the regular Ra filter, **Resistance Parameter Filter**. Both DF filters should not be changed from the default value.

[SMOOTH]: If this bit is set to 1, the smoothing engine is enabled. For more details, see [Smoothing Engine](#), which covers **[RELAX_JUMP_OK]**, **[RELAX_SMOOTH_OK]**, **[CHG_100_SMOOTH_OK]**, and **[DSG_0_SMOOTH_OK]** as further configuration to the smoothing engine.

[TDELTA_V]: This bit determines how the **Delta Voltage** is calculated. By setting this bit, the gauge calculates **Delta Voltage** that corresponds to the power spike defined in **Min Turbo Power**. This bit must be set to 1 if TURBO BOOST mode is used. Otherwise, leaving this bit cleared as a default enables the gauge to calculate **Delta Voltage** by using the maximum difference between instantaneous and average voltages.

[CSYNC]: If this bit is set to 1, the gauge synchronizes *RemainingCapacity()* to *FullChargeCapacity()* at valid charge termination.

[CCT]: This bit provides an option to use *FullChargeCapacity()* (when **[CCT]** = 1) or *DesignCapacity()* (when **[CCT]** = 0) for cycle count threshold calculation. If *FullChargeCapacity()* is selected for cycle count threshold calculation, the minimum cycle count threshold is always 10% of *DesignCapacity()*. This helps to avoid any erroneous cycle count increment caused by an extremely low *FullChargeCapacity()*.

[TAMB_SYNC_SIM]: If this bit is set to 1, the gauge performs an IT simulation after the *TambientSync()* command is received to use the newly recorded ambient temperature. This IT simulation could produce a change in *RelativeStateOfCharge()* if **[SMOOTH]** = 0. If **[SMOOTH]** = 1, *RelativeStateOfCharge()* behaves according to the configuration of the smoothing engine.

[AMB_PRED]: If this bit is set to 1, ambient temperature can be predicted during DISCHARGE and CHARGE modes. This can be useful in system applications that experience large increases in ambient temperature during discharges and/or charges without entry to RELAX mode. Ambient temperature prediction is triggered after being in DISCHARGE/CHARGE for **Predict Ambient Time**, when the system is assumed to be at thermal equilibrium.

[THERM_IV]: If this bit is set to 1, battery heat is held constant near the end of an IT simulation. This helps prevent overestimation of temperature towards the end of discharge, and applies to SOH simulations.

[THERM_SAT]: If this bit is set to 1, IT simulations occurring near termination in a sustained discharge (when thermal saturation is reached) assume simulated temperature to be equal to measured cell temperature. This behavior does NOT apply to SOH simulations.

[FOCV_EN]: If this bit is set to 1, the gauge enables a fast OCV algorithm to predict the final OCV value, which reduces relaxation requirements for QMax updates.

Class	Subclass	Name	Type	Min	Max	Default	Description
Settings	Configuration	I2C Gauging Configuration	H1	0x00	0x0F	0x08	<p>Bit 0: RSOC_L—<i>RelativeStateOfCharge()</i> and <i>RemainingCapacity()</i> behavior at end of charge 0 = Actual value shown (default) 1 = Held at 99% until valid charge termination. On entering valid charge termination, updates to 100%</p> <p>Bit 1: RSOC_HOLD—Prevents RSOC from increasing during discharge 0 = RSOC is not limited. 1 = RSOC is not allowed to increase during discharge.</p> <p>Bit 2: LOCK0—Keeps <i>RemainingCapacity()</i> and <i>RelativeStateOfCharge()</i> from jumping back during relaxation after 0 was reached during discharge 0 = Disabled (default) 1 = Enabled</p> <p>Bit 3: RSVD</p> <p>BIT 4: 1PERCENT_HOLD 0 = Disabled 1 = Enabled</p> <p>Bit 5: TAMB_SYNC_SIM—Ambient Temperature Synchronization Simulation 0 = Disabled 1 = Enabled (default)</p> <p>Bit 7:6: Reserved</p>
Settings	Configuration	IT Gauging Configuration	H2	0x0000	0xFFFF	0xD5FE	<p>Bit 0: CCT—Cycle count threshold 0 = Use <i>DesignCapacity()</i> for cycle count threshold (default) 1 = Use <i>FullChargeCapacity()</i> for cycle count threshold</p> <p>Bit 1: CSYNC—Syncs <i>RemainingCapacity()</i> with <i>FullChargeCapacity()</i> at valid charge termination 0 = Not synchronized 1 = Synchronized (default)</p> <p>Bit 2: RFACTSTEP—Ra factor step 0 = Disabled 1 = Enabled (default)</p> <p>Bit 3: OCVFR—Open circuit voltage flat region 0 = Disabled 1 = Enabled (default)</p> <p>Bit 4: DOD0EW—DOD0 error weighting 0 = Disabled 1 = Enabled (default)</p> <p>Bit 5: TDELTA—Use Turbo power to calculate TermV Delta 0 = Disabled 1 = Enabled (default)</p> <p>Bit 6: RSOC_CONV—RSOC convergence (fast resistance scaling) 0 = Disabled 1 = Enabled (default)</p> <p>Bit 7: FAST_QMAX_LRN—Fast QMax LEARN mode 0 = Disabled 1 = Enabled (default)</p> <p>Bit 8: FAST_QMAX_FLD—Fast QMax FIELD mode 0 = Disabled 1 = Enabled (default)</p> <p>Bit 9: RSVD</p> <p>Bit 10: FF_NEAR_EDV—Fast filter near EDV 0 = Disabled 1 = Enabled (default)</p> <p>Bit 11: RELAX_JUMP_OK—Enables RSOC Jumps in RELAX mode 0 = Disabled (default) 1 = Enabled</p> <p>Bit 12: SMOOTH—Smoothing engine 0 = Disabled 1 = Enabled (default)</p> <p>Bit 13: LFP_RELAX—Lithium iron phosphate relax 0 = Disabled 1 = Enabled</p> <p>Bit 14: RELAX_SMOOTH_OK—Smoothing in RELAX 0 = Disabled 1 = Enabled (default)</p> <p>Bit 15: DOD_RSCALE_EN—Configures which DOD the new RaScale is to be applied. 0 = The RaScale is applied to all DODs during IT simulations. 1 = The RaScale is only applied to DODs higher than the DOD where the RaScale is calculated. (default)</p>

Class	Subclass	Name	Type	Min	Max	Default	Description
Settings	Configuration	IT Gauging Ext	H2	0x0000	0x003F	0x003B	Bit 0: DSG_0_SMOOTH_OK—Smoothing to 0% 0 = Disabled 1 = Enabled (default) Bit 1: CHG_100_SMOOTH_OK—Smoothing to 100% 0 = Disabled 1 = Enabled (default) Bit 2: AMB_PRED—Ambient temperature prediction 0 = Disabled (default) 1 = Enabled Bit 3: THERM_IV—Thermal model IV heat 0 = Disabled 1 = Enabled (default) Bit 4: THERM_SAT—Thermal model saturation 0 = Disabled 1 = Enabled (default) Bit 5: FOCV_EN—Enables fast OCV feature 0 = Disabled 1 = Enabled (default) Bits 15:6: RSVD

4.10 State-Of-Health (SOH)

The BQ27Z561-R2 device implements an updated version of the battery state-of-health (SOH), which is reported by the *StateOfHealth()* command. In the previous version (in the BQ27Z561 device), the *StateOfHealth()* was calculated using a special 25°C version of *FullChargeCapacity()* as a fraction of **Design Capacity**. However, this calculation still included some parameters that were updated during operation based on the loading and use of the battery, separate from the battery status itself. This could lead to varying calculations of state-of-health for the same battery, depending on how the battery was used in the system. The updated version of *StateOfHealth()* addresses this by calculating a special *FCC_SOH()*, with the initial ambient temperature fixed at 25°C, using a current load specified by **SOH Load Rate**, and using the thermal model parameters, **SOH Temp a** and **SOH Temp k**.

The **SOH Load Rate** can be set to the typical current of the application, and it is specified in units of hour-rate (that is, **Design Capacity / SOH Load Rate** will be the current used for the SOH simulation). The **SOH Temp a** and **SOH Temp k** can be set to expected values for the system during operation. These data flash settings are used only for the *StateOfHealth()* calculation. The SOH full charge capacity is updated whenever QMax or the impedance table is updated. Because this implementation removes the variation of load current, temperature, and learned parameters, it is a better representation of the battery's state-of-health. The SOH full charge capacity is available on the MAC command *FCC_SOH()*.

The configuration options for state-of-health (SOH) are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	SoH	SOH Load Rate	U1	1	255	50	0.1 Hr rate	Rate used in SOH simulation
Advanced Charge Algorithm	Rec Temp Charging	Voltage	I2	0	32767	4400	mV	Constant value for charge terminate voltage for the SOH calculation only
Gas Gauging	State	SOH Temp k	I2	0	32767	1	0.1°C/256 cW	Thermal model temperature factor for SOH
Gas Gauging	State	SOH Temp a	I2	0	32767	1000	s	Thermal model temperature factor for SOH
Gas Gauging	It Cfg	Min Delta Voltage	I2	-32768	32767	0	mV	Constant added to terminate voltage for the SOH simulation

4.11 TURBO Mode 3.0

The BQ27Z561-R2 TURBO Mode 3.0 helps the system to adjust the power level by providing information about maximum power, depending on the battery state-of-charge, temperature, and present battery impedance. The gauge informs the system about the power level above which would cause the system voltage to drop below termination after the 10-s pulse, which is called the sustained peak power (SPP). In addition, the gauge also reports the maximum power for the combined 10-s and 10-ms pulses called the maximum peak power (MPP).

A system with TURBO Mode 3.0 applies short high-power load pulses (for example, up to 4 C-rate for as long as 10 ms). In addition, 10-s load pulses of 2 C-rate can occur in some cases prior to 10-ms pulses,

resulting in a combined effect during the turbo boost operation. The 10-s pulse support is new in TURBO Mode 3.0. Additionally, TURBO Mode 3.0 provides R_{hf} effective and V_{load} parameters for the host to use to make power-level decisions.

These high-power pulses may drop down battery voltage. If the battery voltage drops below **Shutdown Voltage**, the system will shut down. To avoid shutting down the system during turbo boost operation, the system should never apply a pulse that would cause the system voltage to drop below the termination voltage (or exceed the recommended current threshold) that could result in a shutdown, reducing the total available run time.

The SPP is computed using a 10-s effective resistance that is temperature- and DOD-dependent. The computation of MPP uses the high-frequency resistance along with the 10-s effective resistance. Both of these resistances are chemistry-specific. In addition, the **Pack Resistance** and **System Resistance** are important parameters used in the calculation of these two powers. The computed TURBO mode currents, the sustained peak current, and the maximum peak current are capped to their respective maximum discharge rates. Depending on how often the system polls the peak power data and how fast the system can switch to a lower power mode, it is possible to exceed the reported peak power levels during the present power consumption. To avoid any system shutdown, the gauge provides a *Reserve Energy %* setting that can serve as a buffer to ensure there is available energy at the present average discharge rate. These calculations occur on the cell level using **Term Min Cell V**, on the pack level using **Term Voltage**, and on the system level using **Min System Voltage**, **Pack Resistance**, and **System Resistance** with the most conservative prediction reported.

Note

Min System Voltage should be set lower than **Term Voltage**.

Table 4-1. TURBO Mode Configuration

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Turbo Cfg	Min System Voltage	I2	0	32567	3000	mV	The minimum voltage at the pack terminal to be used for TURBO mode.
Gas Gauging	Turbo Cfg	Ten Second Max C Rate	I1	0	1127	-20	.1 hr	A 10-second load value to be used by the TURBO Mode calculation
Gas Gauging	Turbo Cfg	Ten Millisecond Max C Rate	I2	0	-127	-40	.1 hr	A 10-ms load value to be used by the TURBO Mode calculation
Gas Gauging	Turbo Cfg	High Frequency Resistance	I2	0	32767	36	mΩ	The high-frequency resistance related to the specific cell chemistry and pack configuration
Gas Gauging	Turbo Cfg	Reserve Energy %	U1	0	100	0	%	This sets the % of remaining energy at the present average discharge rate (as defined in Load Select) until the maximum peak power reaches the value reported by <i>MaxPeakPower()</i> .
Gas Gauging	Turbo Cfg	Turbo Adjustment Factor	U1	0	255	100	—	This is a resistance correction factor that, if used, would be a one-time adjustment the user computes from a 10-s pulse test.

4.12 Battery Trip Point (BTP)

Used with WIN8 OS and later, the battery trip point (BTP) feature indicates when the RSOC of a battery pack has depleted to a certain value set in a DF register.

The BTP feature enables a host to program two capacity- or RSOC-based thresholds that govern triggering a BTP interrupt on the BTP_INT pin, and setting or clearing of the *OperationStatus()[BTP_INT]* on the basis of *RemainingCapacity()* or *RelativeStateOfCharge()*. The source of programmed thresholds (capacity or RSOC) is selected via **Settings.Configuration.IO Config[BTP_SRC]**. The interrupt is enabled or disabled via **Settings.Configuration.IO Config[BTP_EN]**. Similarly, the polarity of the interrupt is configurable based on the value set in **Settings.Configuration.IO Config[INT_POL]**.

- *OperationStatus()[BTP_INT]* is set when:
 - Current > 0 and RemCap/RSOC > “clear” threshold as set by *BTP Chg Set()* This threshold is initialized at reset from **Settings.BTP.Init Charge Set** or **Settings.BTP.Init Charge Set RSOC**.

- Current ≤ 0 and RemCap < “set” threshold as set by *BTP Dsg Set()*. This threshold is initialized at reset from **Settings.BTP.Init Discharge Set** or **Settings.BTP.Init Discharge Set RSOC**.
- When *OperationStatus()[BTP_INT]* is set and if **Settings.Configuration.IO Config[BTP_EN]** is set, then the BTP_INT pin output is asserted.
 - If **Settings.Configuration.IO Config[INT_POL]** is set, it will assert high; otherwise, it will assert low.
- When either *BTPDischargeSet()* or *BTPChargeSet()* commands are received, *OperationStatus()[BTP_INT]* will clear and the pin will be deasserted. The new threshold is written to either *BTPDischargeSet()* or *BTPChargeSet()*.
- At reset, the pin is set to the deasserted state.
 - If **[INT_POL]** is changed, one of the BTP commands must be reset or sent to “clear” the state.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	BTP	Init Discharge Set	I2	0	32767	150	mAh	Initial value for <i>BTPDischargeSet()</i> , for Settings.Configuration.IO Config[BTP_SRC] = 0
Settings	BTP	Init Charge Set	I2	0	32767	175	mAh	Initial value for <i>BTPChargeSet()</i> , for Settings.Configuration.IO Config[BTP_SRC] = 0
Settings	BTP	Init Discharge Set RSOC	U1	0	255	10	%	Initial value for <i>BTPDischargeSet()</i> , for Settings.Configuration.IO Config[BTP_SRC] = 1
Settings	BTP	Init Charge Set RSOC	U1	0	255	15	mAh	Initial value for <i>BTPChargeSet()</i> , for Settings.Configuration.IO Config[BTP_SRC] = 1

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5.1 Description

The device has the capability to log events over the life of the battery, which is useful for analysis. Lifetime data collection is enabled by setting **ManufacturingStatus[LF_EN]** = 1. The data is collected in RAM and only written to data flash under the following conditions to avoid wear out of the data flash:

- Every 10 hours if RAM content is different from data flash.
- A reset counter increments. The lifetime RAM data is reset; therefore, only the reset counters are updated to data flash.

The lifetime data stops collecting under the following conditions:

- Lifetime data collection is disabled by setting **ManufacturingStatus[LF_EN]** = 0.

When the gauge is unsealed, the following *ManufacturingStatus()* can be used for testing lifetime data.

- *LifetimeDataReset()* can reset the lifetime data (RAM and data flash) to the default values.
- *LifetimeDataFlush()* can force an update of the RAM lifetime data to data flash.
- *LifetimeDataSpeedupMode()* can increase the rate the lifetime data is incremented.

The following lifetime data is collected when **ManufacturingStatus[LF_EN]** = 1.

- Voltage
 - Maximum/minimum cell voltage
- Current
 - Max charge/discharge current
 - Maximum average discharge current
- Temperature
 - Max/min cell temp
- Charging Events
 - Number of valid charge terminations (That is, the number of times [VCT] is set.)
 - Cycle count at last charge termination
- Gauging events
 - Number of QMax updates
 - Cycle Count at Last QMax update
 - Number of RA updates and disable
 - Cycle Count at Last RA update and disable
- Time based data collection feature. (This data is stored with a resolution of 1 second up to over 100 years.)
 - Total runtime
 - Time spent in different *RelativeStateOfCharge()* versus *Temperature()* ranges. shows the organization of the binned data that is collected by this Lifetimes feature.
 - Eight *RelativeStateOfCharge()* columns for each of the seven charge temperature ranges
 - Seven rows of *Temperature()* runtime values

Table 5-1. Time Spent in *RelativeStateOfCharge()* – *Temperature()* Ranges

	RSOC ≥ 95% [default]	RSOC ≥ 90%	RSOC ≥ 80%	RSOC ≥ 60%	RSOC ≥ 40%	RSOC ≥ 20%	RSOC ≥ 10%	RSOC ≥ 0%
Undertemperature								
Low Temperature								
Standard Temperature Low								
Recommended Temperature								
Standard Temperature High								
High Temperature								
Over Temperature								

5.2 Reset

In addition to the *ManufacturerAccess()* 0x0028 *Lifetime Data Reset*, **Lifetime Data Collection** can also be reset when **[SEALED_RESET]** is set using a two-word MAC sequence available in SEALED and UNSEALED modes. The two-word key is programmable using *ManufacturerAccess()* 0x0035 *Security Keys*. Both keys must be sent within 4 seconds of each other for **Lifetimes** data to reset.



6.1 Description

The device can be enabled to generate an interrupt to the host processor on the INT pin under various voltage, temperature, and RSOC conditions. The **IO Config[INT_EN]** bit is used to enable or disable the interrupt function, and its polarity can be set to active high (**IO Config[INT_POL] = 1**) or active low (**IO Config[INT_POL] = 0**). The **IO Config[INT_TYPE]** bit is used to select if interrupt is a pulse on the INT pin with an approximate width of 1 ms (**IO Config[INT_TYPE] = 1**) or level-based interrupt (**IO Config[INT_TYPE] = 0**). The **IO Config[INT_PUP]** bit is to select if INT output is open-drain (**IO Config[INT_PUP] = 0**) or push-pull (**IO Config[INT_PUP] = 1**).

6.2 Voltage and Temperature Interrupts

The device can be enabled to generate an interrupt on the INT pin to indicate an overvoltage, undervoltage, overtemperature, or undertemperature condition. The thresholds to set and clear each event are configurable through data flash for the initial values, and later by writing to the standard commands referenced below:

- The voltage for the overvoltage set interrupt threshold is *VoltHiSetThreshold()*.
- The voltage for the overvoltage clear interrupt threshold is *VoltHiClearThreshold()*.
- The voltage for the undervoltage set interrupt threshold is *VoltLoSetThreshold()*.
- The voltage for the undervoltage clear interrupt threshold is *VoltLoClearThreshold()*.
- The temperature for the overtemperature set interrupt threshold is *TempHiSetThreshold()*.
- The temperature for the overtemperature clear interrupt threshold is *TempHiClearThreshold()*.
- The temperature for the undertemperature set interrupt threshold is *TempLoSetThreshold()*.
- The temperature for the undertemperature clear interrupt threshold is *TempLoClearThreshold()*.

The interrupts are indicated in *InterruptStatus()*.

Table 6-1 summarizes the interrupt flags, which are [VOLT_HI], [VOLT_LO], [TEMP_HI], and [TEMP_LO].

Table 6-1. Interrupt Flags (Interrupt Status)

Flag	Set Criteria	Clear Criteria
[VOLT_HI]	<i>Voltage() > VoltHiSetThreshold()</i>	<i>Voltage() < VoltHiClearThreshold()</i>
[VOLT_LO]	<i>Voltage() < VoltLoSetThreshold()</i>	<i>Voltage() > VoltLoClearThreshold()</i>
[TEMP_HI]	<i>Temperature() > TempHiSetThreshold()</i>	<i>Temperature() < TempHiClearThreshold()</i>
[TEMP_LO]	<i>Temperature() < TempLoSetThreshold()</i>	<i>Temperature() > TempLoClearThreshold()</i>

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	Init Voltage High Set	I2	0	5000	4500	mV	Initial value for <i>VoltHiSetThreshold()</i> , the high cell voltage set threshold
Settings	Configuration	Init Voltage High Clear	I2	0	5000	4400	mV	Initial value for <i>VoltHiClearThreshold()</i> , the high cell voltage clear threshold
Settings	Configuration	Init Voltage Low Set	I2	0	5000	2500	mV	Initial value for <i>VoltLoSetThreshold()</i> , the low cell voltage set threshold
Settings	Configuration	Init Voltage Low Clear	I2	0	5000	2600	mV	Initial value for <i>VoltLoClearThreshold()</i> , the low cell voltage clear threshold
Settings	Configuration	Init Temperature High Set	I1	-128	127	60	°C	Initial value for <i>TempHiSetThreshold()</i> , the high temperature set threshold

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	Init Temperature High Clear	I1	-128	127	55	°C	Initial value for <i>TempHiClearThreshold()</i> , the high temperature clear threshold
Settings	Configuration	Init Temperature Low Set	I1	-128	127	0	°C	Initial value for <i>TempLoSetThreshold()</i> , the low temperature set threshold
Settings	Configuration	Init Temperature Low Clear	I1	-128	127	5	°C	Initial value for <i>TempLoClearThreshold()</i> , the low temperature clear threshold

6.3 RSOC Interrupts

The device can be enabled to generate an interrupt on the INT pin at configurable RSOC intervals. The threshold setting is configurable through **SOC Delta** for the initial value, and later by writing to the standard command *SOCSetDeltaThreshold()*. Setting **SOC Delta** to 0 disables RSOC interrupts; otherwise, interrupts will be generated at the following RSOC points:

- 100%
- $100\% - n \times \text{SOC Delta}$, where n is an integer from 1 to $\text{INT}(100 / \text{SOC Delta})$
- 0%

The RSOC interrupt is indicated in *InterruptStatus()* by [SOC_DELTA] flag.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	SOC Delta	U1	0	100	1	%	Initial value for <i>SOCSetDeltaThreshold()</i> , RSOC delta set threshold. It is the interval for generating RSOC-based interrupts on the INT pin. Set to 0 to disable these RSOC-based interrupts. Otherwise, interrupts are generated at the following RSOC points: 0%, 100%, $100\% - n \times \text{SOC Delta}$, where n is an integer from 1 to $\text{INT}(100 / \text{SOC Delta})$.

6.4 Host Interrupts Configuration

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	IO Config	H1	0x00	0x3C	0x00	—	Bit 0: BTP_EN 0 = Disables assertion of the INT pin when BTP is triggered 1 = Enables assertion of the INT pin when BTP is triggered Bit 1: = BTP_SRC 0 = BTP interrupts use capacity-based thresholds 1 = BTP interrupts use RSOC-based thresholds Bit 2: INT_EN 0 = Disables interrupt function on pin INT 1 = Enables interrupt function on pin INT Bit 3: INT_POL 0 = Interrupt (INT) is active LOW. 1 = Interrupt (INT) is active HIGH. Bit 4: INT_PUP 0 = Interrupts on the INT pin are open-drain type (pull up required), 1 = Interrupts on the INT pin are push-pull type (internal pull up used), Bit 5: INT_TYPE 0 = Interrupts enabled on INT pin as level-type 1 = Interrupts enabled on INT pin as pulse-type Bit 6: GPIO_POL 0 = Pulse (PULS) is active LOW. 1 = Pulse (PULS) is active HIGH. Bit 7: GPIO_LEVEL_EN 0 = Pulse (PULS) is pulse only. 1 = Pulse (PULS) is level set.

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7.1 Description

The device can be enabled to generate a single pulse on the PULS pin with a programmable width. The polarity can also be set for active high or active low with **IO Config[GPIO_POL]**. The PULS pin can be used to signal other system components, via a command to the gauge, without a connection to the host processor.

The PULS pin is open-drain so a resistor must be tied to a pullup voltage. The pulse width can be set in **GPIO Pulse Width** in steps of 25 ms. Setting the width to 0 effectively disables the pulse. A single pulse is generated each time the *PulseGPIO()* command is sent.

Additionally, the PULS pin can be programmed to a level (high or low) with the **IO Config[GPIO_LEVEL_EN]** bit. When **IO Config[GPIO_LEVEL_EN]** is set, the *ClearGPIO()* command will clear the state of the PULS pin and *SetGPIO()* will set the state of the PULS pin.

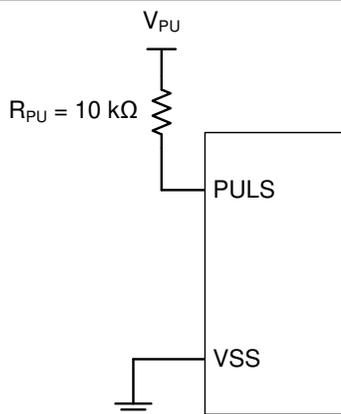
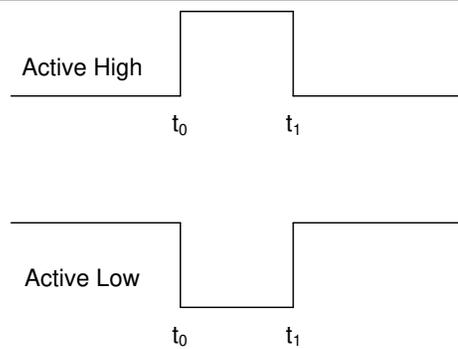


Figure 7-1. PULS Open-Drain Configuration



$t_1 - t_0 = \text{GPIO Pulse Width}$
Active High / Low set with [GPIO_POL]
Figure 7-2. Pulse Width and Polarity

7.2 Programmable Pulse Width Configuration

Class	Subclass	Name	Type	Min	Max	Default	Description
Settings	Configuration	IO Config	H1	0x0	0x3C	0x00	Bit 0: BTP_EN 0 = Disables assertion of the INT pin when BTP is triggered. 1 = Enables assertion of the INT pin when BTP is triggered. Bit 1: BTP_SRC 0 = BTP interrupts use capacity-based thresholds. 1 = BTP interrupts use RSOC-based thresholds. Bit 2: INT_EN 0 = Disables the interrupt function on the INT pin 1 = Enables the interrupt function on the INT pin Bit 3: INT_POL 0 = Interrupt (INT) is active LOW. 1 = Interrupt (INT) is active HIGH. Bit 4: INT_PUP 0 = Interrupts on the INT pin are open-drain type (pull up required). 1 = Interrupts on the INT pin are push-pull type (internal pull up used). Bit 5: INT_TYPE 0 = Interrupts enabled on INT pin as level-type 1 = Interrupts enabled on INT pin as pulse-type Bit 6: GPIO_POL 0 = Pulse (PULS) is active LOW. 1 = Pulse (PULS) is active HIGH. Bit 7: GPIO_LEVEL_EN 0 = Pulse (PULS) is pulse only. 1 = Pulse (PULS) is level set.
Settings	Configuration	GPIO Pulse Width	U1	—	255	7	Pulse width of PULS (7 indicates 7 × 25 ms = 175 ms)



8.1 Description

There are three levels of secured operation within the device: SEALED, UNSEALED, and FULL ACCESS. To switch between the levels, different operations are needed with different access keys. The device also supports SHA-256 HMAC authentication with the host system. Additionally, lifetime data is protected by an access key.

8.2 SHA-256 Authentication

The BQ27Z561-R2 uses SHA-256 for authentication.

- SHA-256 preprocessing is described in the *SHA-1 Preprocessing* section in [FIPS 180-4](#).
- The hash computation is described in the *SHA-1 Hash Computation* section in [FIPS 180-4](#).
- The HMAC implementation is described in [FIPS 198-1](#).

Detailed information about the SHA-256 algorithm can be found here:

- <http://www.nist.gov/itl/>
- <http://csrc.nist.gov/publications/fips>
- www.faqs.org/rfcs/rfc3174.html

The random number should be a 32-byte random number generated from the host processor system. Once this number is generated, it is used to generate the HMAC value using the random number as the message and the secure key as the secret key for SHA-256.

8.2.1 Secure Key

The secure key is stored in the secured memory of the BQ27Z561-R2 device. It is located in secure memory, which can store up to four secure keys.

Auth Config selects which of the four keys to be used with KEY_SEL0 and KEY_SEL1.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	Auth Config	H1	0x0	0x03	0x00	—	Bit 0: KEY_SEL0 Bit 1: KEY_SEL1 00 = Enables KEY 1 01 = Enables KEY 2 10 = Enables KEY 3 11 = Enables KEY 4

8.2.2 Authentication Flow

The authentication procedure is described in the following steps:

1. The host writes 0x00 to 0x3E.
2. The host writes 0x00 to 0x3F.
3. Write the random challenge should be written in a 32-byte block to address 0x40–0x5F.
4. Write the checksum (1's complement sum of (1), (2), and (3)) to address 0x60.
5. Write the length 0x24 to address 0x61.
6. The gauge will compute the HMAC using SHA-256 after step (5). Wait 200 ms. (60 ms is how long authentication takes, but extra margin is added).
7. The `MACData()` command will contain the computed HMAC result using SHA-256.
8. `[AUTH] = 1` in `OperationStatusB()`.

8.3 Security Modes

As shipped, the device is in FULL ACCESS mode. For device security after manufacture, the device should be set to the SEALED access operational mode. To do this, send the MAC seal 0x0030 to the gauge. After the device is set to the SEALED mode, any device resets will cause the device to enter the SEALED mode. See the following sections for instructions on how to return to the other access modes.

For security mode access keys, the device ships with factory defaults. The manufacturer should change the keys to their proprietary keys using the MAC 0x0035. See [Section 12.8.19](#).

8.3.1 SEALING and UNSEALING Data Flash

The gas gauge has a key access scheme to transition between SEALED, UNSEALED, and FULL ACCESS modes. Each transition requires that a unique set of two keys be sent to the gas gauge via the *AltManufacturerAccess()* command. The keys must be sent consecutively, with no other data being written to the *AltManufacturerAccess()* register. The *Seal Device* command instructs the device to limit access to the registers, functions, and data flash space, and sets the *[SEC1][SEC0]* flags. In SEALED mode, standard register information is accessible. Extended MAC Command functions and data flash are not accessible. Once in SEALED mode, the device can never permanently return to UNSEALED or FULL ACCESS modes. [Section 12.8.33](#), the *OperationStatusB()* register, shows the status of the device using the *[SEC1][SEC0]* bits.

8.3.2 SEALED to UNSEALED

SEALED to UNSEALED instructs the device to extend access to the standard and extended registers and data flash space and clears the *[SEC1][SEC0]* flags. In UNSEALED mode, all data, standard and extended registers and DF have read/write access. Unsealing is a two-step command performed by writing the first word of the unseal key to *AltManufacturerAccess()* (MAC), followed by the second word of the unseal key to *AltManufacturerAccess()*. The unseal key can be read and changed via the *MAC SecurityKey()* command when in FULL ACCESS mode. To return to the SEALED mode, either a hardware reset is needed, or the *MAC Seal Device()* command is needed to transit from FULL ACCESS or UNSEALED to SEALED.

8.3.3 UNSEALED to FULL ACCESS

UNSEALED to FULL ACCESS instructs the device to allow full access to all standard and extended registers and data flash. The device is shipped from TI in this mode. The keys for UNSEALED to FULL ACCESS can be read and changed via the MAC command *SecurityKey()* when in FULL ACCESS mode. Changing from UNSEALED to FULL ACCESS is performed by using the *AltManufacturerAccess()* command, by writing the first word of the Full Access Key to *AltManufacturerAccess()*, followed by the second word of the Full Access Key to *AltManufacturerAccess()*. In FULL ACCESS mode, the command to go to boot ROM can be sent.



9.1 Introduction

The BQ27Z561-R2 device does not control the charge directly. It can interact with a smart charger to enhance its performance. The device can change the values of *ChargingVoltage()* and *ChargingCurrent()* based on *Temperature()* and *Voltage()*. Its flexible charging algorithm is JEITA-compatible and can also meet other specific cell manufacturer charge requirements. The *ChargingStatus()* register shows the state of the charging algorithm.

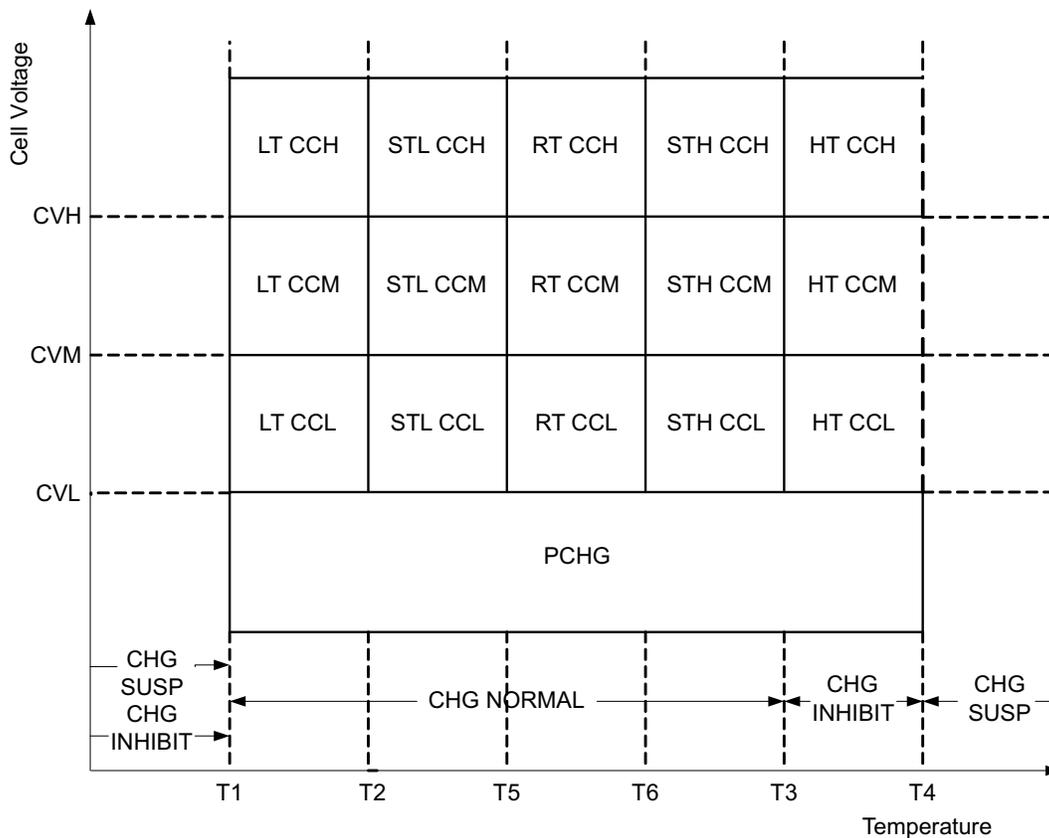


Figure 9-1. Charging Matrix

9.2 Charge Temperature Ranges

The measured temperature is segmented into several temperature ranges. The charging algorithm adjusts *ChargingCurrent()* and *ChargingVoltage()* according to the temperature range. The temperature ranges set in data flash should adhere to the following format:

$$T1 \leq T2 \leq T5 \leq T6 \leq T3 \leq T4$$

Temp Range bit definitions can be found in *ChargingStatus()*.

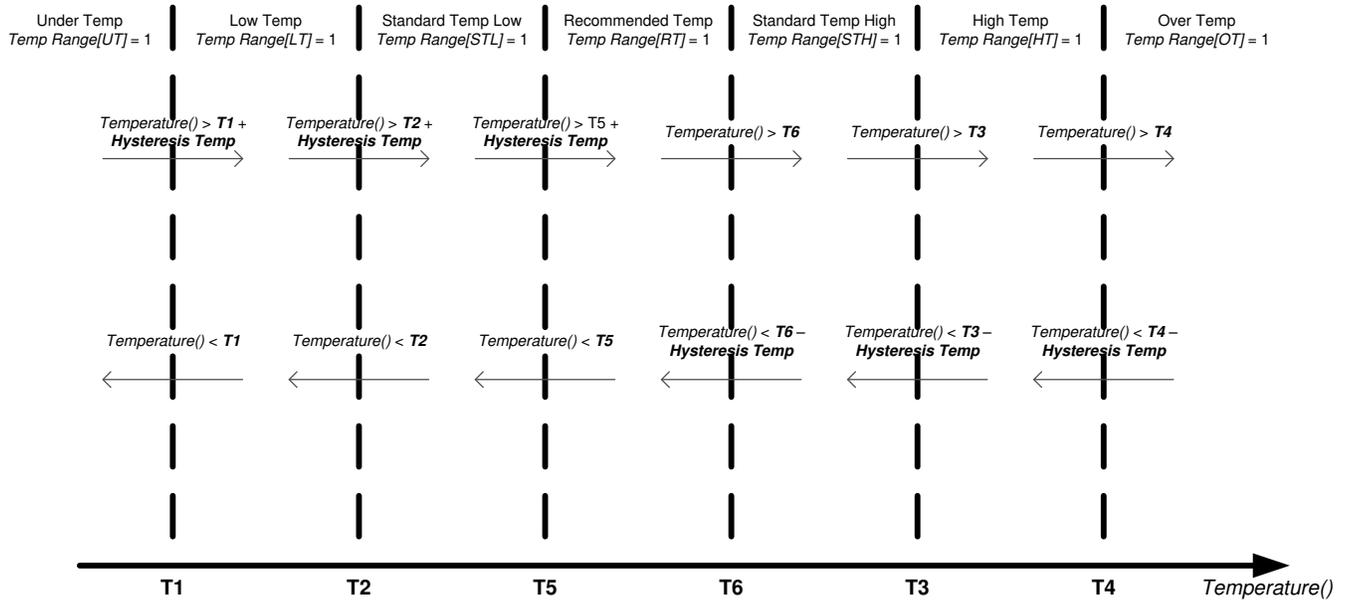


Figure 9-2. Charging Across Temperature

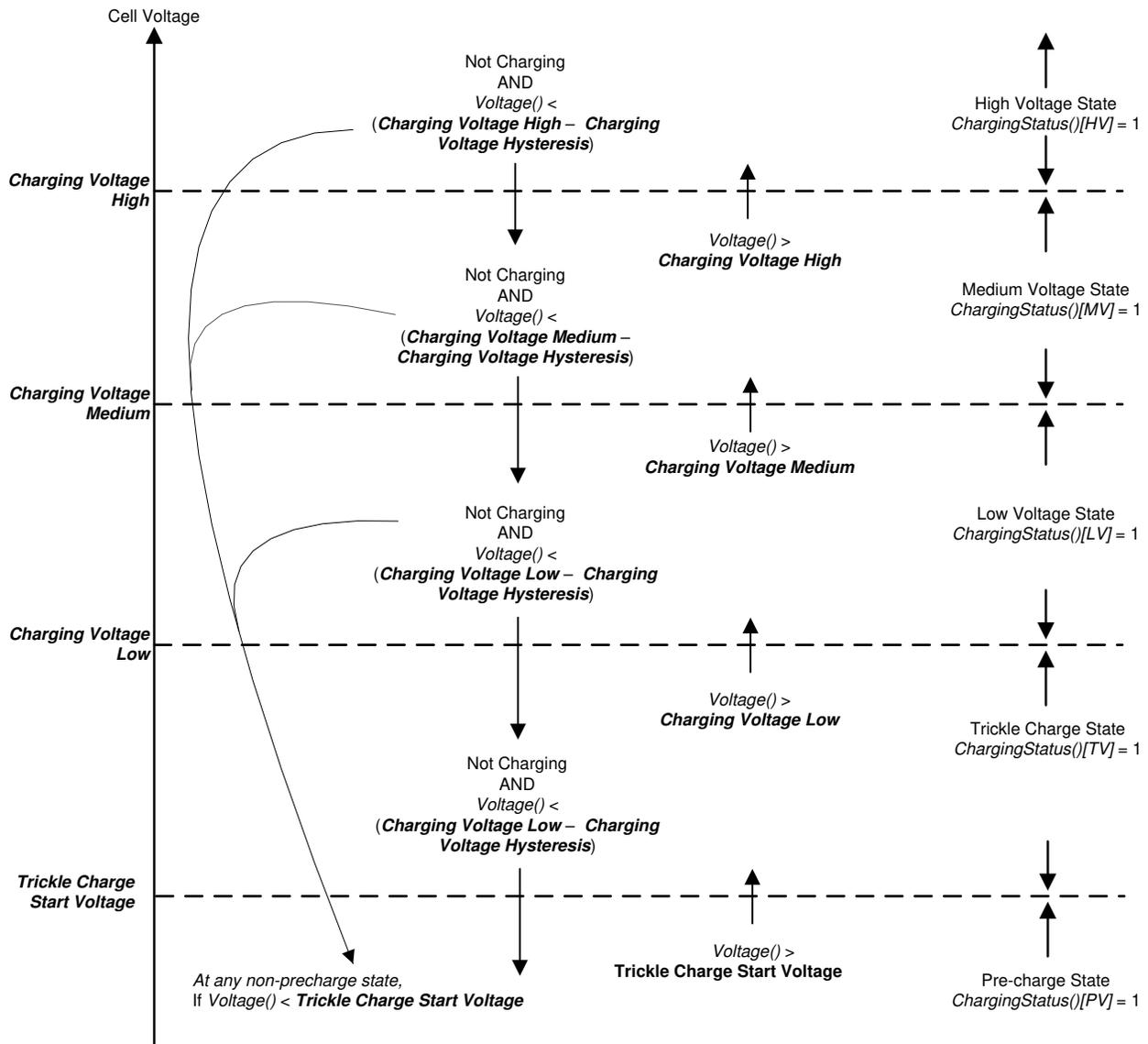
Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Advanced Charge Algorithms	Temperature Ranges	T1	l1	-128	127	0	°C	T1 low temperature range lower limit
Advanced Charge Algorithms	Temperature Ranges	T2	l1	-128	127	10	°C	T2 low temperature range to standard temperature range
Advanced Charge Algorithms	Temperature Ranges	T5	l1	-128	127	20	°C	T5 recommended temperature range lower limit
Advanced Charge Algorithms	Temperature Ranges	T6	l1	-128	127	25	°C	T6 recommended temperature range upper limit
Advanced Charge Algorithms	Temperature Ranges	T3	l1	-128	127	45	°C	T3 standard temperature range to high temperature range
Advanced Charge Algorithms	Temperature Ranges	T4	l1	-128	127	55	°C	T4 high temperature range upper limit
Advanced Charge Algorithms	Temperature Ranges	Hysteresis	l1	-128	127	1	°C	Temperature hysteresis, applied when temperature is decreasing.

9.3 Voltage Range

The measured cell voltage is segmented into several voltage ranges. The charging algorithm adjusts *ChargingCurrent()* according to the temperature range and voltage range. The voltage ranges set in data flash should adhere to the following format:

$$\text{Charging Voltage Low} \leq \text{Charging Voltage Med} \leq \text{Charging Voltage High} \leq [\text{Standard or Rec}] \text{Temp Charging:Voltage}$$

Depending on the specific charging profile, the **Low Temp Charging:Voltage** and **High Temp Charging:Voltage** settings do not necessarily have the highest setting values.


Figure 9-3. Charging Voltage Ranges

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Advanced Charging Algorithms	Voltage Range	Precharge Start Voltage	I2	0	32767	2500	mV	Minimum cell voltage to enter PRECHARGE mode
Advanced Charging Algorithms	Voltage Range	Charging Voltage Low	I2	0	32767	2900	mV	Precharge Start Voltage range to Charging Voltage Low range
Advanced Charging Algorithms	Voltage Range	Charging Voltage Med	I2	0	32767	3600	mV	Charging Voltage Low range to Charging Voltage Med range
Advanced Charging Algorithms	Voltage Range	Charging Voltage High	I2	0	32767	4000	mV	Charging Voltage Med to Charging Voltage High range
Advanced Charging Algorithms	Voltage Range	Charging Voltage Hysteresis	U1	0	255	0	mV	Charging Voltage Hysteresis is applied when voltage is decreasing.

9.3.1 RelativeStateOfCharge() Range

If **[SOC_CHARGE]** in **Charging Configuration** is set, then the voltage-based threshold control, as described in [Section 9.3](#), is replaced with *RelativeStateOfCharge()* control.

With this method, the following changes in the control transitions occur:

1. [LV] state and *RelativeStateOfCharge()* > **Charging SOC Mid**; move to [MV].
2. [MV] state and *RelativeStateOfCharge()* > **Charging SOC High**; move to [HV].
3. [MV] state [DSG] = 1, and *RelativeStateOfCharge()* < **Charging SOC Mid – SOC Hysteresis**; move to [LV].
4. [HV] state [DSG] = 1, and *RelativeStateOfCharge()* < **Charging SOC High – Charging SOC Hysteresis**; move to [MV].

Table 9-1. RelativeStateOfCharge() Range

Class	Subclass	Name	Type	Min Value	Max Value	Default Value	Unit
Advanced Charge Algorithm	SOC Range	Charging SOC Mid	U1	0	100	50	%
Advanced Charge Algorithm	SOC Range	Charging SOC High	U1	0	100	75	%
Advanced Charge Algorithm	SOC Range	Charging SOC Hysteresis	U1	0	100	1	%

9.4 Charging Current

The *ChargingCurrent()* value changes depending on the detected temperature and voltage per the charging algorithm.

The **Charging Configuration[CRATE]** bit provides an option to adjust the *ChargingCurrent()* based on *FullChargeCapacity()/DesignCapacity()*.

For example, with **[CRATE] = 1**, if *FullChargeCapacity()/DesignCapacity()* = 90% and **Rec Temp Charging: Current Med** is active per the charging algorithm, the *ChargingCurrent()* = **Rec Temp Charging: Current Med** × 90%.

Note

Table priority is top to bottom.

Temp Range	Voltage Range	Condition	Action
UT or OT	Any	—	<i>ChargingCurrent()</i> = 0
Any	PV	—	<i>ChargingCurrent()</i> = Pre-Charging:Current
Any	LV, MV, or HV	<i>ChargingStatus()[MCHG] = 1</i>	<i>ChargingCurrent()</i> = Maintenance Charging:Current
LT	LV	—	<i>ChargingCurrent()</i> = Low Temp Charging:Current Low
	MV	—	<i>ChargingCurrent()</i> = Low Temp Charging:Current Med
	HV	—	<i>ChargingCurrent()</i> = Low Temp Charging:Current High
STL	LV	—	<i>ChargingCurrent()</i> = Standard Temp Low Charging:Current Low
	MV	—	<i>ChargingCurrent()</i> = Standard Temp Low Charging:Current Med
	HV	—	<i>ChargingCurrent()</i> = Standard Temp Low Charging:Current High
STH	LV	—	<i>ChargingCurrent()</i> = Standard Temp High Charging:Current Low
	MV	—	<i>ChargingCurrent()</i> = Standard Temp High Charging:Current Med
	HV	—	<i>ChargingCurrent()</i> = Standard Temp High Charging:Current High
RT	LV	—	<i>ChargingCurrent()</i> = Rec Temp Charging:Current Low
	MV	—	<i>ChargingCurrent()</i> = Rec Temp Charging:Current Med
	HV	—	<i>ChargingCurrent()</i> = Rec Temp Charging:Current High

Temp Range	Voltage Range	Condition	Action
HT	LV	—	<i>ChargingCurrent()</i> = High Temp Charging:Current Low
	MV	—	<i>ChargingCurrent()</i> = High Temp Charging:Current Med
	HV	—	<i>ChargingCurrent()</i> = High Temp Charging:Current High

The configuration options for charging current are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	Charging Configuration	H2	0x00	0x3F85	0x00	—	Bit 0: CRATE— <i>ChargingCurrent()</i> rate 0 = No adjustment to <i>ChargingCurrent()</i> (default) 1 = <i>ChargingCurrent()</i> adjusted based on <i>FullChargeCapacity()/DesignCapacity()</i> Bit 1: Reserved Bit 2: SOC_CHARGE 0 = Uses voltage thresholds (CVL, CVM, and CVH) in Advanced Charging Algorithms 1 = Enables the SOC threshold to replace voltage thresholds (CVL, CVM, and CVH) in Advanced Charging Algorithms Bits 6:3: Reserved Bit 7: CS_CV 0 = Cell swelling voltage degradation disabled 1 = Cell swelling voltage degradation enabled Bit 8: COMP_IR 0 = Disables voltage compensation for system resistance 1 = Enables voltage compensation for system resistance Bit 9: DEGRADE_CC 0 = Disables <i>Charging Current()</i> degradation based on the charging degradation mode 1 = Enables <i>Charging Current()</i> degradation based on the charging degradation mode Bit 10: CHGV_DEGRADE 0 = Disables <i>Charging Voltage()</i> degradation based on the charging degradation mode 1 = Enables <i>Charging Voltage()</i> degradation based on the charging degradation mode Bit 11: HIBAT_CHG 0 = Disables the high battery voltage feature 1 = Enables the high battery voltage feature Bit 12: SLEEPCHG 0 = <i>ChargingCurrent()</i> = 0 and <i>ChargingVoltage()</i> = 0 in SLEEP mode 1 = <i>ChargingCurrent()</i> and <i>ChargingVoltage()</i> are determined by Advanced Charging Algorithms in SLEEP mode. Bit 13: TAPER_VOLT 0 = Uses <i>ChargingVoltage()</i> for charge termination detection 1 = Uses fixed Charge Term Charging Voltage for charge termination Bits 14:15 RSVD
Advanced Charging Algorithms	Pre-Charging	Current	I2	0	32767	88	mA	Precharge <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Maintenance Charging	Current	I2	0	32767	44	mA	Maintenance <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Low Temp Charging	Current Low	I2	0	32767	132	mA	Low temperature range low voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Low Temp Charging	Current Med	I2	0	32767	352	mA	Low temperature range medium voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Low Temp Charging	Current High	I2	0	32767	264	mA	Low temperature range high voltage range <i>ChargingCurrent()</i>

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Advanced Charging Algorithms	Standard Temp Low Charging	Current Low	I2	0	32767	1980	mA	Standard temperature low range low voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Standard Temp Low Charging	Current Med	I2	0	32767	4004	mA	Standard temperature low range medium voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Standard Temp Low Charging	Current High	I2	0	32767	2992	mA	Standard temperature low range high voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Standard Temp High Charging	Current Low	I2	0	32767	1980	mA	Standard temperature high range low voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Standard Temp High Charging	Current Med	I2	0	32767	4004	mA	Standard temperature high range medium voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Standard Temp High Charging	Current High	I2	0	32767	2992	mA	Standard temperature high range high voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	High Temp Charging	Current Low	I2	0	32767	1012	mA	High temperature range low voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	High Temp Charging	Current Med	I2	0	32767	1980	mA	High temperature range medium voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	High Temp Charging	Current High	I2	0	32767	1496	mA	High temperature range high voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Rec Temp Charging	Current Low	I2	0	32767	2508	mA	Recommended temperature range low voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Rec Temp Charging	Current Med	I2	0	32767	4488	mA	Recommended temperature range medium voltage range <i>ChargingCurrent()</i>
Advanced Charging Algorithms	Rec Temp Charging	Current High	I2	0	32767	3520	mA	Recommended temperature range high voltage range <i>ChargingCurrent()</i>

9.5 Charging Voltage

The *ChargingVoltage()* changes depending on the detected temperature per the charge algorithm. If cell temperature reduces *ChargingVoltage()* below the cell voltage, setting **[HIBAT_CHG]** can hold it unchanged while *ChargingCurrent()* is held at 0. This action continues until the desired *ChargingVoltage()* is above the cell voltage.

Note

Table priority is top to bottom.

Temp Range	Condition	Action
UT or OT	—	<i>ChargingVoltage()</i>
LT	—	<i>ChargingVoltage()</i> = Low Temp Charging:Voltage
STL	—	<i>ChargingVoltage()</i> = Standard Temp Low Charging:Voltage
STH	—	<i>ChargingVoltage()</i> = Standard Temp High Charging:Voltage
RT	—	<i>ChargingVoltage()</i> = Rec Temp Charging:Voltage
HT	—	<i>ChargingVoltage()</i> = High Temp Charging:Voltage

Table 9-2 shows the configurations for the charging voltages. They can be changed with the *ChargingVoltageOverride* MAC.

Table 9-2. JEITA Charging Voltages

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Advanced Charging Algorithms	Low Temp Charging	Voltage	I2	0	32767	4400	mV	Low temperature range <i>ChargingVoltage()</i>
Advanced Charging Algorithms	Standard Temp Low Charging	Voltage	I2	0	32767	4400	mV	Standard temperature low range <i>ChargingVoltage()</i>
Advanced Charging Algorithms	Standard Temp High Charging	Voltage	I2	0	32767	4400	mV	Standard temperature high range <i>ChargingVoltage()</i>
Advanced Charging Algorithms	High Temp Charging	Voltage	I2	0	32767	4100	mV	High temperature range <i>ChargingVoltage()</i>
Advanced Charging Algorithms	Rec Temp Charging	Voltage	I2	0	32767	4400	mV	Recommended temperature range <i>ChargingVoltage()</i>

9.5.1 Charge Voltage Compensation for System Impedance

The design of some battery charging systems may have a not insignificant impedance between the charger and battery terminals. In this case, a voltage compensation feature handles system level IR drops to ensure the correct charging voltage is supplied at the battery terminals. Program the **System Resistance** register with the measured resistance in milliohms (mΩ) between the battery terminals and charger terminals. To enable this feature, set the configuration bit [**COMP_IR**] in (default 0) the **Charging Configuration** register.

This feature works as follows:

$$\text{ChargingVoltage}() = \text{charging_voltage} + \text{ChargingCurrent}() \times \text{System Resistance}$$

where *charging_voltage* was computed as a result of a selected configuration; from the JEITA table and any applied degradations.

9.6 Charging Degradation Modes

This optional feature can be used to reduce charging voltages and/or currents based on measured parameters that reflect the aging of cells.

Here is an example of charging degradation using **Cycle Count** (although it is the same for the other aging parameters as itemized below):

In NORMAL mode (there is no reduction of *ChargingCurrent()* or *ChargingVoltage()*), *ChargingCurrent()* is reduced by CC Degradation Mode 1 (assuming the Cycle Count 1 entry conditions are met), then moving to Cycle Count Mode 2, *ChargingCurrent()* is further reduced by CC Degradation Mode 2 (assuming Cycle Count 2 entry conditions are met). This is similar for Cycle Count Mode 3.

Care should be taken to set the degradation mode thresholds such that each threshold is increased for each mode. The fact that any of the other measured aging parameters have not passed a degradation mode threshold would not cause the lower mode to be used.

This charging current degradation scheme (if enabled) works in conjunction with any other existing degradation/increments (such as charge loss compensation).

The following table shows the default values for how charging voltage and charging current are degraded for each degradation mode:

[CHGV_DEGRADE] is set.)	Charging Voltage (CV) (CV degradation is available if enabled.)	Charging Current (CC) (CC degradation is available if enabled [DEGRADE_CC]). ⁽¹⁾
Normal	No CV Degradation	No CC Degradation
Mode 1	CV Degradation (default 10 mV / cell)	CC Degradation (default 10%)
Mode 2	CV Degradation (default 40 mV / cell)	CC Degradation (default 20%)

[CHGV_DEGRADE] is set.)	Charging Voltage (CV) (CV degradation is available if enabled.)	Charging Current (CC) (CC degradation is available if enabled [DEGRADE_CC]). ⁽¹⁾
Mode 3	CV Degradation (default 70 mV / cell)	CC Degradation (default 40%)

(1) Only [DEGRADE_CC] or [CRATE] can be used at a time. Both must not be enabled together.

A degrade mode is entered when any measured parameter exceeds the thresholds set in data flash. The following thresholds are defined for each mode (see [Data Flash Summary](#) for threshold value settings and addresses).

- **Cycle Threshold** checked against *CycleCount()*
- **SOH Threshold** checked against *StateOfHealth()*
- **Runtime Threshold** checked against **Total FW Runtime**
- **High SOC Threshold** checked against the sum of all the high SOC times recorded in **Lifetimes**
- **High Temp Threshold** checked against the sum of all the high temperature times recorded in **Lifetimes**
- **High Temp SOC Threshold** checked against **Time Spent in HT RSOC A**

CycleCount() must be greater than **Cycle Count Start Runtime** before any degradation modes are detected.

The current degradation mode can be determined from the value of [CV_DGRD].

Total FW Runtime is updated to data flash every **LF Update Time**.

Note

A threshold can be set to an unobtainable value for a particular aging parameter to be disabled.

9.7 Cell Swelling Control (via Charging Voltage Degradation)

Cell swelling can occur when the cell temperature and cell voltage are above certain thresholds. In these situations, the charging voltage can be stepped down gradually until the cell temperature moves back down.

This scheme works (as shown in [Figure 9-4](#)) when enabled by setting [CS_CV] (default is cleared) in the **Charging Configuration** register. When the max cell voltage^{1..4} and cell temperature are above the **Voltage Threshold** and **Temperature Threshold**, respectively, for the period defined by **Time Interval**, then the charging voltage is stepped down by **Delta Voltage**. This step down continues until either the max cell voltage^{1..4} and cell temperature conditions go away (that is, cell swelling reduces) or the step down reaches **Min CV**.

The charging voltage reduction/degradation resulting from this feature is reset when exiting CHARGE mode.

Note

This degradation works in conjunction with other degradation features; therefore, use with care.

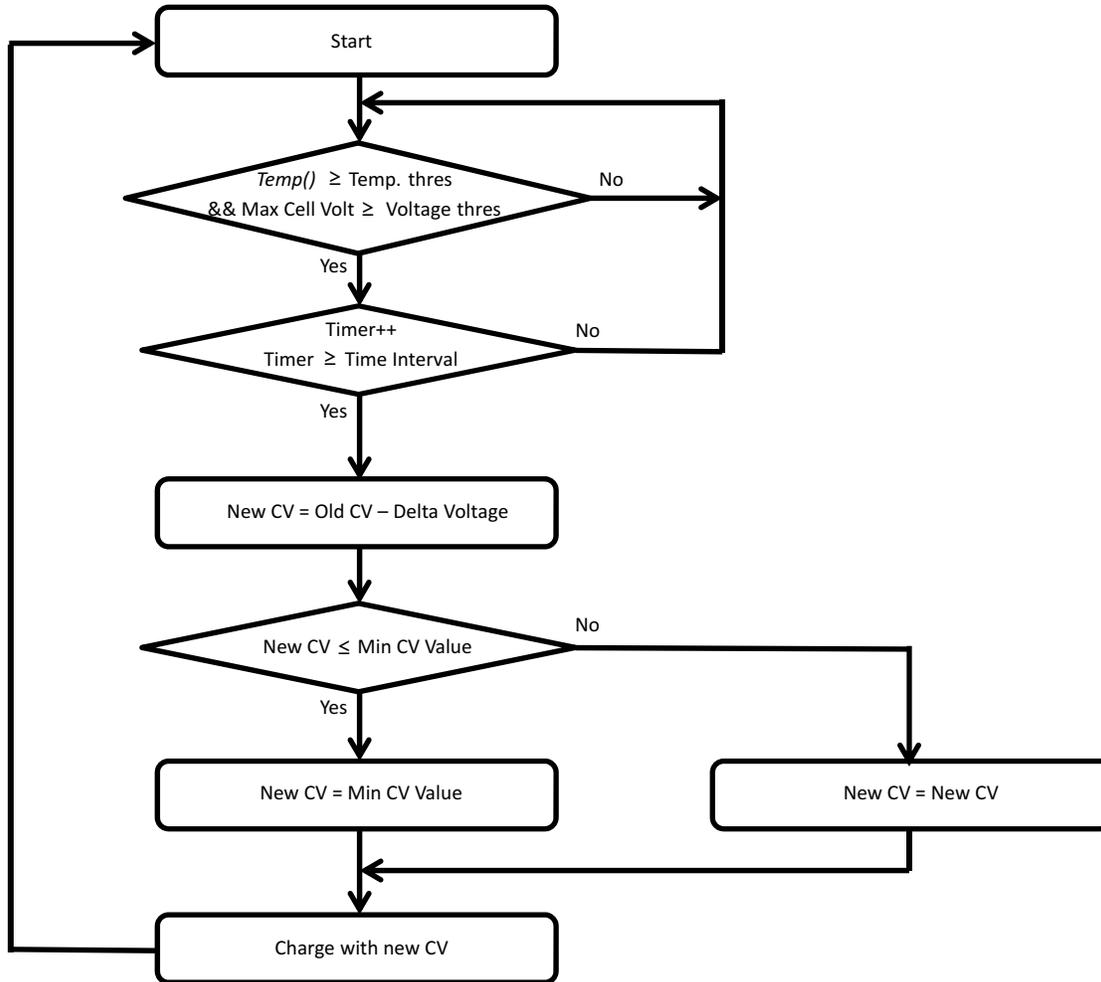


Figure 9-4. Cell Swelling Control

9.8 Valid Charge Termination

The charge termination condition must be met to enable valid charge termination. The device has the following actions at charge termination, based on the bits settings:

- If **IT Gauging Configuration[CSYNC] = 1**, *RemainingCapacity()* = *FullChargeCapacity()*.
- If **I2C Gauging Configuration[RSOCL] = 1**, *RelativeStateOfCharge()* and *RemainingCapacity()* are held at 99% until charge termination occurs. Only on entering charge termination is 100% displayed.
- If **I2C Gauging Configuration[RSOCL] = 0**, *RelativeStateOfCharge()* and *RemainingCapacity()* are not held at 99% until charge termination occurs. Fractions of percentages greater than 99% are rounded up to display 100%.

Status	Condition	Action
Charging	<i>GaugingStatus()[REST] = 0 AND BatteryStatus()[DSG] = 0</i>	Charge Algorithm active

Status	Condition	Action
Valid Charge Termination	All of the following conditions must occur for two consecutive 40-s periods: Charging (that is, <i>BatteryStatus()</i> [DSG] = 0) AND <i>AverageCurrent()</i> < Charge Term Taper Current AND <i>Voltage()</i> + Charge Term Voltage ≥ <i>ChargingVoltage()</i> AND [TAPER_VOLT] = 0 AND The accumulated change in capacity > 0.25 mAh	<i>ChargingStatus()</i> [VCT] = 1 <i>ChargingStatus()</i> [MCHG] = 1 <i>ChargingVoltage()</i> = Charging Algorithm <i>ChargingCurrent()</i> = Charging Algorithm <i>BatteryStatus()</i> [FC] = 1 and <i>GaugingStatus()</i> [FC] = 1 if SOC Flag Config A [FCSETVCT] = 1 <i>BatteryStatus()</i> [TCA] = 1 and <i>GaugingStatus()</i> [TC] = 1 if SOC Flag Config A [TCSETVCT] = 1 Cell 1 Chg Voltage at EoC = <i>Voltage()</i> Current at EoC = <i>Current()</i> Calculate Cell 1 DODEOC Trigger IT simulation

Note

After valid charge termination, *RemainingCapacity()* and *FullChargeCapacity()* will reflect any change in capacity due to any difference in *ChargingVoltage()* from the previous valid charge termination.

Note

Setting **[TAPER_VOLT]** causes **Charge Term Charging Voltage** to be used in place of *ChargingVoltage()*.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Advanced Charging Algorithms	Termination Config	Charge Term Taper Current	I2	0	32767	100	mA	Valid charge termination taper current qualifier threshold
Advanced Charging Algorithms	Termination Config	Charge Term Voltage	I2	0	32767	100	mV	Valid charge termination delta voltage qualifier, max cell based
Gas Gauging	State	Cell 1 Chg Voltage at EoC	I2	0	32767	4375	mV	Cell 1 Voltage value at end of charge
Gas Gauging	State	Current at EoC	I2	—	32767	100	mA	Current at end of charge

9.9 Charge and Discharge Alarms

The *[TC]* and *[FC]* bits in *GaugingStatus()* can be set at charge termination and based on RSOC or cell voltage. If multiple set and clear conditions are selected, then the corresponding flag is set whenever a valid set or clear condition is met. If the set and clear conditions are true at the same time, the flag will clear. The same functionality is applied to the *[TD]* and *[FD]* bits in *GaugingStatus()*.

Note

GaugingStatus()[TC][TD][FC][FD] are the status flags based on the gauging conditions only. These flags are set and cleared based on **SOC Flag Config A** and **SOC Flag Config B**.

The *BatteryStatus()*[TCA][TDA][FC][FD] flags are set and cleared according to the *GaugingStatus()* [TC][TD][FC][FD] flags.

The table below summarizes the options to set and clear the *[TC]* and *[FC]* flags in *GaugingStatus()*.

Flag	Set Criteria	Set Condition	Enable
<i>[TC]</i>	Cell Voltage	<i>Voltage()</i> > TC: Set Voltage Threshold	SOC Flag Config A [TCSETV] = 1
	RSOC	<i>RelativeStateOfCharge()</i> > TC: Set % RSOC Threshold	SOC Flag Config A [TCSETRSOC] = 1
	Valid Charge Termination (enable by default)	When <i>ChargingStatus</i> [VCT] = 1	SOC Flag Config A [TCSETVCT] = 1

Flag	Set Criteria	Set Condition	Enable
[FC]	Cell Voltage	$Voltage() > FC: \text{ Set Voltage Threshold}$	SOC Flag Config B[FCSETV] = 1
	RSOC	$RelativeStateOfCharge() > FC: \text{ Set \% RSOC Threshold}$	SOC Flag Config B[FCSETRSOC] = 1
	Valid Charge Termination (enable by default)	When $ChargingStatus[VCT] = 1$	SOC Flag Config A[FCSETVCT] = 1

Flag	Clear Criteria	Clear Condition	Enable
[TC]	Cell Voltage	$Voltage() \leq TC: \text{ Clear Voltage Threshold}$	SOC Flag Config A[TCCLEARV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() \leq TC: \text{ Clear \% RSOC Threshold}$	SOC Flag Config A[TCCLEARRSOC] = 1
[FC]	Cell Voltage	$Voltage() \leq FC: \text{ Clear Voltage Threshold}$	SOC Flag Config B[FCCLEARV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() \leq FC: \text{ Clear \% RSOC Threshold}$	SOC Flag Config B[FCCLEARRSOC] = 1

The tables below summarize the various options to set and clear the [TD] and [FD] flags in *GaugingStatus()*.

Flag	Set Criteria	Set Condition	Enable
[TD]	Cell Voltage	$Voltage() < TD: \text{ Set Voltage Threshold}$	SOC Flag Config A[TDSETV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() < TD: \text{ Set \% RSOC Threshold}$	SOC Flag Config A[TDSETRSOC] = 1
[FD]	Cell Voltage	$Voltage() < FD: \text{ Set Voltage Threshold}$	SOC Flag Config B[FDSETV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() < FD: \text{ Set \% RSOC Threshold}$	SOC Flag Config B[FDSETRSOC] = 1

Flag	Clear Criteria	Clear Condition	Enable
[TD]	Cell Voltage	$Voltage() \geq TD: \text{ Clear Voltage Threshold}$	SOC Flag Config A[TDCLEARV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() \geq TD: \text{ Clear \% RSOC Threshold}$	SOC Flag Config A[TDCLEARRSOC] = 1
[FD]	Cell Voltage	$Voltage() \geq FD: \text{ Clear Voltage Threshold}$	SOC Flag Config B[FDCLEARV] = 1
	RSOC (enable by default)	$RelativeStateOfCharge() \geq FD: \text{ Clear \% RSOC Threshold}$	SOC Flag Config B[FDCLEARRSOC] = 1

The configuration options for the charge and discharge alarms are in the following data flash.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	SOC Flag Config A	H2	0x0000	0x0FFF	0x0C8C	—	Bit 0: TDSETV—Enables the TD flag set by cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 1: TDCLEARV—Enables the TD flag cleared by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 2: TDSETRSOC—Enables the TD flag set by the RSOC threshold 0 = Disabled 1 = Enabled (default) Bit 3: TDCLEARRSOC—Enables the TD flag cleared by the RSOC threshold 0 = Disabled 1 = Enabled (default) Bit 4: TCSETV—Enables the TC flag set by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 5: TCCLEARV—Enables the TC flag cleared by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 6: TCSETRSOC—Enables the TC flag set by the RSOC threshold 0 = Disabled (default) 1 = Enabled Bit 7: TCCLEARRSOC—Enables the TC flag cleared by the RSOC threshold 0 = Disabled 1 = Enabled (default) Bit 8: Reserved Bit 9: Reserved Bit 10: FCSETVCT—Enables the FC flag set by valid charge termination 0 = Disabled 1 = Enabled (default) Bit 11: TCSETVCT—Enables the TC flag set by valid charge termination 0 = Disabled 1 = Enabled (default) Bit 15: 12: Reserved
Settings	Configuration	SOC Flag Config B	H1	0x00	0xFF	0x8C	—	Bit 0: FDSETV—Enables the FD flag set by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 1: FDCLEARV—Enables the FD flag cleared by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 2: FDSETRSOC—Enables the FD flag set by the RSOC threshold 0 = Disabled 1 = Enabled (default) Bit 3: FDCLEARRSOC—Enables the FD flag cleared by the RSOC threshold 0 = Disabled 1 = Enabled (default) Bit 4: FCSETV—Enables the FC flag set by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 5: FCCLEARV—Enables the FC flag cleared by the cell voltage threshold 0 = Disabled (default) 1 = Enabled Bit 6: FCSETRSOC—Enables the FC flag set by the RSOC threshold 0 = Disabled (default) 1 = Enabled Bit 7: FCCLEARRSOC—Enables the FC flag cleared by the RSOC threshold 0 = Disabled 1 = Enabled (default)
Gas Gauging	FD	Set Voltage Threshold	I2	0	5000	3000	mV	<i>GaugingStatus()</i> [FD] and <i>BatteryStatus()</i> [FD] cell voltage set threshold
Gas Gauging	FD	Clear Voltage Threshold	I2	0	5000	3100	mV	<i>GaugingStatus()</i> [FD] and <i>BatteryStatus()</i> [FD] cell voltage clear threshold
Gas Gauging	FD	Set RSOC % Threshold	U1	0	100	0	%	<i>GaugingStatus()</i> [FD] and <i>BatteryStatus()</i> [FD] <i>RelativeStateOfCharge()</i> set threshold
Gas Gauging	FD	Clear RSOC % Threshold	U1	0	100	5	%	<i>GaugingStatus()</i> [FD] and <i>BatteryStatus()</i> [FD] <i>RelativeStateOfCharge()</i> clear threshold
Gas Gauging	FC	Set Voltage Threshold	I2	0	5000	4400	mV	<i>GaugingStatus()</i> [FC] and <i>BatteryStatus()</i> [FC] cell voltage set threshold

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	FC	Clear Voltage Threshold	I2	0	5000	4300	mV	<i>GaugingStatus()</i> [FC] and <i>BatteryStatus()</i> [FC] cell voltage clear threshold
Gas Gauging	FC	Set RSOC % Threshold	U1	0	100	100	%	<i>GaugingStatus()</i> [FC] and <i>BatteryStatus()</i> [FC] <i>RelativeStateOfCharge()</i> set threshold
Gas Gauging	FC	Clear RSOC % Threshold	U1	0	100	95	%	<i>GaugingStatus()</i> [FC] and <i>BatteryStatus()</i> [FC] <i>RelativeStateOfCharge()</i> clear threshold
Gas Gauging	TD	Set Voltage Threshold	I2	0	5000	3200	mV	<i>GaugingStatus()</i> [TD] cell voltage set threshold
Gas Gauging	TD	Clear Voltage Threshold	I2	0	5000	3300	mV	<i>GaugingStatus()</i> [TD] cell voltage clear threshold
Gas Gauging	TD	Set RSOC % Threshold	U1	0	100	6	%	<i>GaugingStatus()</i> [TD] <i>RelativeStateOfCharge()</i> set threshold
Gas Gauging	TD	Clear RSOC % Threshold	U1	0	100	8	%	<i>GaugingStatus()</i> [TD] <i>RelativeStateOfCharge()</i> clear threshold
Gas Gauging	TC	Set Voltage Threshold	I2	0	5000	4400	mV	<i>GaugingStatus()</i> [TC] cell voltage set threshold
Gas Gauging	TC	Clear Voltage Threshold	I2	0	5000	4300	mV	<i>GaugingStatus()</i> [TC] cell voltage clear threshold
Gas Gauging	TC	Set RSOC % Threshold	U1	0	100	100	%	<i>GaugingStatus()</i> [TC] <i>RelativeStateOfCharge()</i> set threshold
Gas Gauging	TC	Clear RSOC % Threshold	U1	0	100	95	%	<i>GaugingStatus()</i> [TC] <i>RelativeStateOfCharge()</i> clear threshold

9.10 Terminate Charge and Discharge Alarms

The *BatteryStatus()*[TCA][TDA][FC][FD] flags are set according to *GaugingStatus()*. The following is a summary of the set conditions and their various alarm flags:

[TCA] = 1

- *GaugingStatus()*[TC] = 1 AND in CHARGE mode

[FC] = 1

- *GaugingStatus()*[FC] = 1

[TDA] = 1 if

- *GaugingStatus()*[TD] = 1 AND in DISCHARGE mode

[FD] = 1 if

- *GaugingStatus()*[FD] = 1

9.11 Precharge

The device enters PRECHARGE mode if the cell voltage falls below **Precharge Start Voltage**.

9.12 Maintenance Charge

Maintenance charge [MCHG] can allow charge after termination has been reached. This is only possible if the *GaugingStatus()*[TC] flag is not set. This means to use maintenance charge. [TCSETVCT] and [TCSETSOC] should not be enabled, and instead [TCSETV] can be used to stop maintenance charge based on voltage.

Status	Condition	Action
Set	<i>ChargingStatus()</i> [IN] = 0 AND <i>ChargingStatus()</i> [SU] = 0 AND <i>ChargingStatus()</i> [PV] = 0 AND <i>GaugingStatus()</i> [TCA] = 1	<i>ChargingStatus()</i> [MCHG] = 1 <i>ChargingVoltage()</i> = Charging Algorithm <i>ChargingCurrent()</i> = Charging Algorithm
Clear	<i>ChargingStatus()</i> [IN] = 1 OR <i>ChargingStatus()</i> [SU] = 1 OR <i>ChargingStatus()</i> [PV] = 1 OR <i>GaugingStatus()</i> [TCA] = 0	<i>ChargingStatus()</i> [MCHG] = 0 <i>ChargingVoltage()</i> = Charging Algorithm <i>ChargingCurrent()</i> = Charging Algorithm

9.13 Charge Inhibit

The BQ27Z561-R2 device can provide information to the smart charger to enable it to inhibit the start of charging at high and low temperatures to prevent damage of the cells. This feature is intended to enable the charger to

prevent the start of charging when the temperature is at the inhibit range; therefore, if charging is in progress, the charger must determine its actions. *Temp Range* bit definitions can be found in *ChargingStatus()*.

Status	Condition	Action
Normal	<i>Temp Range[LT]</i> = 1 OR <i>Temp Range[STL]</i> = 1 OR <i>Temp Range[RT]</i> = 1 OR <i>Temp Range[STH]</i> = 1	<i>ChargingStatus()[IN]</i> = 0 <i>ChargingVoltage()</i> = charging algorithm <i>ChargingCurrent()</i> = charging algorithm
Trip	Not charging AND <i>Temp Range[HT]</i> = 1	<i>ChargingStatus()[IN]</i> = 1 <i>ChargingStatus()[SU]</i> = 0 <i>ChargingVoltage()</i> = 0 <i>ChargingCurrent()</i> = 0



10.1 HDQ Single-Pin Serial Interface

The HDQ interface is an asynchronous return-to-one protocol where a processor sends the command code to the fuel gauge. With HDQ, the least significant bit (LSB) of a data byte (command) or word (data) is transmitted first.

Note

The HDQ pin (A3) is open-drain and requires an external pullup resistor.

The 8-bit command code consists of two fields: the 7-bit HDQ command code (bits 0:6) and the 1-bit RW field (MSB bit 7). The RW field directs the fuel gauge either to:

- Store the next 8 or 16 bits of data to the specified register or
- Output 8 bits of data from the specified register.

The HDQ peripheral can transmit and receive data as either an HDQ master or slave.

The host processor initiates HDQ serial communication by sending a break command to the fuel gauge. A break is detected when the DATA pin is driven to a logic-low state for a time $t_{(B)}$ or greater. The DATA pin should then be returned to its normal ready high logic state for a time $t_{(BR)}$. The fuel gauge is now ready to receive information from the host processor.

The *HDQ Communication Basics Application Report (SLUA408)* provides details of HDQ communication basics, including an alternative method to use a standard two-wire UART for single-wire HDQ communication.

The BQ27Z561-R2 gauge is shipped in I²C mode, but TI provides a method to switch to HDQ mode via *SwitchToHDQ()* (see [AltManufacturerAccess\(\) 0x7C40](#) for details).

10.2 I²C Interface

The gauge supports the standard I²C read, incremental read, one-byte write, quick read, and functions. The 7-bit device address (ADDR) is the most significant 7 bits of the hex address and is fixed as 1010101, or 0x55. The 8-bit device address is therefore 0xAA or 0xAB for write or read, respectively.

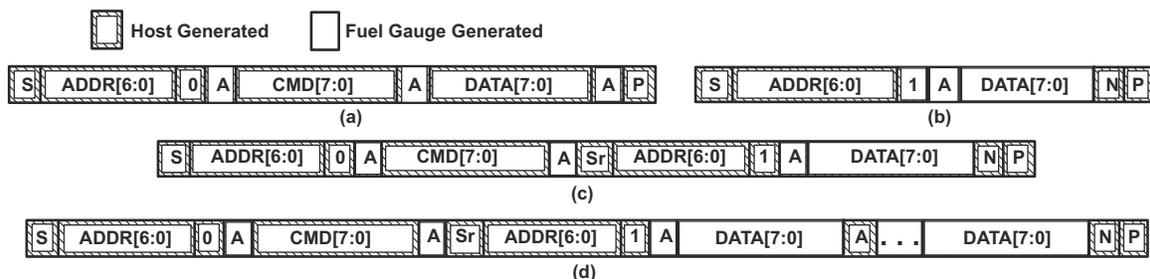
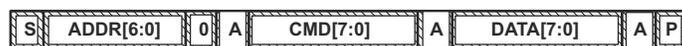


Figure 10-1. Supported I²C Formats

(S = Start, Sr = Repeated Start, A = Acknowledge, N = No Acknowledge, and P = Stop)

The quick read returns data at the address indicated by the address pointer. The address pointer, a register internal to the I²C communication engine, increments when data is acknowledged by the fuel gauge or the I²C master. Quick writes function in the same way and are a convenient means of sending multiple bytes to consecutive command locations (such as two-byte commands that require two bytes of data).

Attempt to write a read-only address (NACK after data sent by master):



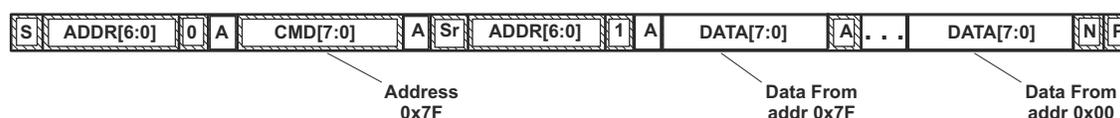
Attempt to read an address above 0x7F (NACK command):



Attempt at incremental writes (NACK all extra data bytes sent):



Incremental read at the maximum allowed read address:



10.2.1 I²C Clock Frequency

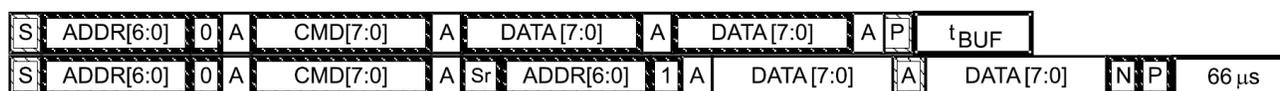
The gauge supports different maximum clock frequencies for the I²C engine. The desired maximum clock frequency can be configured via **Settings.Configuration.I2C Configuration**.

10.2.2 I²C Time Out

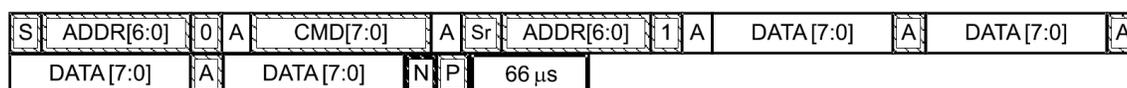
The I²C engine releases SDA and SCL if the I²C bus is held low for about two seconds. If the fuel gauge were holding the lines, releasing them frees the master to drive the lines.

10.2.3 I²C Command Waiting Time

To ensure the correct results of a command with the 400-kHz I²C operation, there must be a proper waiting time between issuing the command and reading the results. For *AltManufacturerAccess()* commands, the following diagram shows the waiting time required between issuing the *AltManufacturerAccess()* command and reading the status. For read-only standard commands, there is no waiting time required, but the host must not issue all standard commands more than two times per second. If thousands of I²C transactions are sent to the gauge in one second, then it could adversely impact the CPU and cause a watchdog reset.



Waiting time between control subcommand and reading results



Waiting time between continuous reading results

Table 10-1. Command Waiting Times

Command	t _{BUF}
Data flash signature commands: <i>StaticDFSSignature()</i> , <i>StaticChemDFSSignature()</i> , or <i>AllDFSSignature()</i>	250 ms

Table 10-1. Command Waiting Times (continued)

Command	t _{BUF}
All other writes to <i>AltManufacturerAccess()</i>	66 μ s

10.2.4 I²C Clock Stretching

I²C clock stretches can occur during all modes of fuel gauge operation. In SLEEP mode, a short clock stretch occurs on all I²C traffic, as the device must wake up to process the packet. In NORMAL and SLEEP modes, clock stretching only occurs for packets addressed for the fuel gauge. The timing of stretches varies as interactions between the communicating host and the gauge are asynchronous. The I²C clock stretches may occur after start bits, the ACK/NACK bit, and first data bit transmit on a host read cycle. The majority of clock stretch periods are small (≤ 4 ms), as the I²C interface peripheral and CPU firmware perform normal data flow control. However, less frequent but more significant clock stretch periods may occur when data flash is written by the CPU to update the Ra tables and other data flash parameters, such as QMax. Due to the organization of data flash, updates need to be written in data blocks consisting of multiple data bytes.

For example, an Ra table update requires erasing a single page of data flash and programming the updated Ra table. The potential I²C clock stretching time is 40.08 ms maximum. This includes a 40-ms page erase and 40- μ s row programming time ($\times 2$ rows). The Ra table updates occur during the discharge cycle and at up to 15 resistance grid points that occur during the discharge cycle.

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11.1 Manufacture Testing

To improve the manufacture testing flow, the gas gauge device allows certain features to be toggled on or off through *AltManufacturerAccess()* commands (for example, *LifetimeDataCollection()*, *CalibrationMode()*, and *Gauging()*). Enabling only the feature under test can simplify the test flow in production by avoiding any feature interference. The *AltManufacturerAccess()* command that toggles *ManufacturingStatus()[CAL_EN]*, *[LT_TEST]* will only set the RAM data, meaning the conditions set by this command will be cleared if a reset or seal is issued to the gauge. The *AltManufacturerAccess()* commands that toggle *ManufacturingStatus()[LF_EN]*, *[GAUGE_EN]* will be updated to data flash and synchronized between *ManufacturingStatus()* and *Mfg Status Init*. *ManufacturingStatus()* keeps track of the status (enabled or disabled) of each feature.

Mfg Status Init provides the option to enable or disable individual features for normal operation. Upon a reset or a seal command, *ManufacturingStatus()* will be reloaded from *Mfg Status Init*. This means if an update is made to *Mfg Status Init* to enable or disable a feature, the gauge will only take the new setting if a reset or seal command is sent.

11.1.1 Manufacturing Status Configuration

Class	Subclass	Name	Type	Min	Max	Default	Description
Settings	Manufacturing	Mfg Status Init	H2	0x0000	0xFFFF	0x0000	Bit 0: Reserved Bit 1: Reserved Bit 2: Reserved Bit 3: GAUGE_EN—Gauging 0 = Disabled (default) 1 = Enabled Bit 4: Reserved Bit 5: LF_EN—Lifetime data collection 0 = Disabled (default) 1 = Enabled Bit 15:6: Reserved

11.2 I²C Configuration

The following table describes the bit settings for I²C communication options.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Settings	Configuration	I ² C Configuration	H1	0x00	0xFF	0x08	—	Bit 0: Reserved Bit 1: MFG_C_SEALED—Set to allow <i>AltManufacturerAccess()</i> 0x007A <i>ManufacturerInfoB</i> to write data flash when the gauge is sealed. Bit 2: Reserved Bit 3: XL—Enables 400-kHz I ² C max clock frequency 0 = 100-kHz max clock frequency 1 = 400-kHz max clock frequency (default) Bits 6–4: Reserved Bit 7: FLASH_BUSY_WAIT—Set this bit to avoid NACKs on legal commands. Note there will be long clock stretches if the gauge is updating data flash.

11.3 Manufacturer Information Blocks

There are three 32-byte manufacturer information blocks in data flash that record details related to the manufacture of a battery pack. The gauge does not use this data; it is available for the manufacturer to use and interpret the data. No formatting of data written in these blocks is imposed by the gauge firmware. These blocks can be accessed by either the regular data flash access methods or by using *ManufacturerAccess()* commands. See the entries for **Manufacturer Data**, **Manufacturer Info B**, and **Manufacturer Info C** in the [Section 14.1](#) to *AltManufacturerAccess() 0x007A ManufacturerInfoB* access by [Section 12.8.53](#).

The manufacturer information blocks can also be read or written when the gauge is in the UNSEALED mode, using the associated MACs *AltManufacturerAccess() 0x0070 ManufacturerInfo* and *AltManufacturerAccess() 0x007B ManufacturerInfoC*. *AltManufacturerAccess() 0x007B ManufacturerInfoC* can be used to write to manufacturer information block c when the gauge is sealed if **[MFG_C_SEALED]** is set in **Settings.Configuration.I²C Configuration**.

11.4 Verification of Data Flash

During manufacture, the configuration of the gauge in data flash will be updated. Typically, a known good data flash image is loaded to the device. To avoid the time needed to read back to verify the data flash, a number of data flash signature Manufacturer Access commands are available (see [Section 12.8](#)). The BQ27Z561-R2 has both static and non-static sections in the data flash memory. The static memory areas are only changed by host writes to data flash commands. Non-static memory may be modified by the gauge firmware.

11.5 Calibration

The device has integrated routines that support calibration of current and voltage readings, accessible after writing 0xF081 to *AltManufacturerAccess()* when the *ManufacturingStatus()[CAL_EN]* bit is ON. While the calibration is active, the raw ADC data is available on *MACData()*. The device stops reporting calibration data on *MACData()* if any other MAC commands are sent or the device is reset or sealed.

Note

The *ManufacturingStatus()[CAL_EN]* bit must be turned OFF after calibration is completed. The *ManufacturingStatus()[CAL_EN]* bit is set by default when **Mfg Status Init** is set to 0. This bit is cleared at reset or after sealing.

Table 11-1. AltManufacturerAccess() Descriptions

AltManufacturerAccess()	Description
0x002D	Enables/disables <i>ManufacturingStatus()[CAL_EN]</i>
0xF080	Disables raw ADC data output on <i>MACData()</i>
0xF081	Outputs raw ADC data of voltage and current <i>MACData()</i>

The *MACData()* output format is: ZZYyaaAAabbBBccCCddDDeeEEfffGgGghhHHiiIjJkkKK,

where:

Table 11-2. MACData() Format Descriptions

Value	Format	Description
ZZ	byte	8-bit counter, increments when raw ADC values are refreshed (every 1000 ms).
YY	byte	Output status <i>AltManufacturerAccess() = 0xF081: 1</i>
AAaa	2's comp	Current (coulomb counter)
BBbb	2's comp	Cell Voltage
CCcc	2's comp	Reserved
DDdd	2's comp	Reserved
EEee	2's comp	Reserved

Table 11-2. MACData() Format Descriptions (continued)

Value	Format	Description
FFff	2's comp	Reserved
GGgg	2's comp	Reserved
HHhh	2's comp	Cell Current
Iiii	2's comp	Reserved
JJjj	2's comp	Reserved
KKkk	2's comp	Reserved

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Note

All calibration steps that require accessing data on *MACData()* must begin read operations starting at *AltManufacturerAccess()* to ensure the data portion of the block is properly refreshed per the intended *AltManufacturerAccess()* subcommand (in this case 0xF081). The first two bytes returned are the *AltManufacturerAccess()* subcommand followed by the counter, status, and raw ADC values, as shown in [Table 11-1](#).

12.1 Cell (BAT) Voltage Calibration

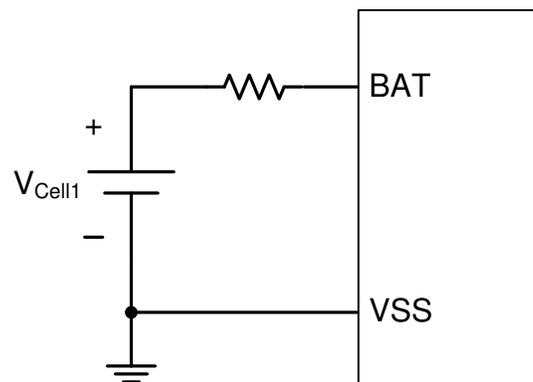


Figure 12-1. Cell Voltage Calibration

1. Apply known voltage in mV to the cell voltage inputs:
 - V_{CELL1} between BAT terminal and VSS terminal
2. If *ManufacturingStatus()*[CAL_EN] = 0, send 0x002D to *AltManufacturerAccess()* to enable the [CAL_EN] flag.
3. Send 0xF081 to *AltManufacturerAccess()* to enable raw cell voltage output on *MACData()*.
4. Poll *MACData()* until the 8-bit counter value increments by 2 before reading data.
5. Read the ADC conversion readings of cell voltages from *MACData()*:
 - $ADC_{CELL1} = \text{BBbb of } MACData()$
6. Average several readings for higher accuracy. Poll *MACData()* until ZZ increments, to indicate that updated values are available:
 - $ADC_{CELL1} = [ADC_{CELL1}(\text{reading } n) + \dots + ADC_{CELL1}(\text{reading } 1)]/n$

7. Calculate gain value:

$$\text{Cell Gain} = \frac{V_{\text{Cell}}}{\text{ADC}_{\text{Cell}}} \times 2^{16}$$

8. Write the new **Cell Gain** value to data flash.
9. Recheck the voltage reading and if it is not accurate, repeat Steps 5 and 6.
10. Send 0x002D to *AltManufacturerAccess()* to clear the [CAL_EN] flag if all calibration is complete.

12.1.1 Voltage Calibration Data Flash

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Calibration	Voltage	Cell Gain	I2	-32768	32767	12101	—	BAT – VSS gain

12.2 Current Calibration

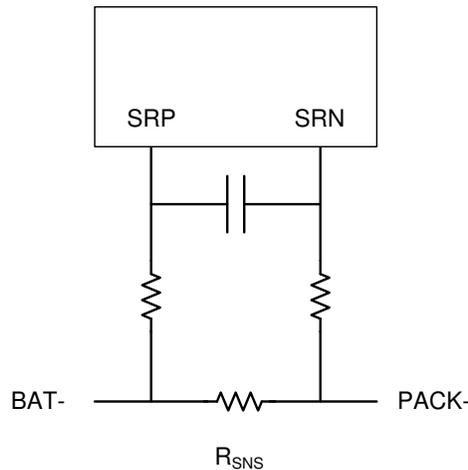


Figure 12-2. Current Calibration (Charge Current Flow Is BAT– to PACK–)

Note

CC offset and board offset are no longer calibrations required by the BQ27Z561-R2 due to hardware improvements.

12.2.1 CC Gain/Capacity Gain Calibration

- Apply a known current (typically 1 A to 2 A), and ensure I_{CC} is flowing through the sense resistor connected between the SRP and SRN pins.
- If *ManufacturingStatus()[CAL_EN]* = 0, send 0x002D to *AltManufacturerAccess()* to enable the [CAL_EN] flag.
- Send 0xF081 to *AltManufacturerAccess()* to enable raw CC output on *MACData()*.
- Poll *MACData()* until ZZ increments by 2 before reading data.
- Check the ADC conversion current output from *MACData()*:
 - $\text{ADC}_{CC} = \text{AAaa of } \text{MACData}()$

Is $\text{ADC}_{CC} < 0x8000$? If yes, use ADC_{CC} ; otherwise, $\text{ADC}_{CC} = -(0xFFFF - \text{AAaa} + 0x0001)$.

- Average several readings for higher accuracy. Poll *MACData()* until ZZ increments to indicate that updated values are available:
 - $\text{ADC}_{CC} = [\text{ADC}_{CC}(\text{reading } n) + \dots + \text{ADC}_{CC}(\text{reading } 1)]/n$

7. Calculate gain values:

$$\text{CC Gain} = I_{CC} / \text{ADC}_{CC}$$

$$\text{Capacity Gain} = \text{CC Gain} \times 1193046.4712$$

8. Write the new **CC Gain** and **Capacity Gain** values to data flash.
9. Recheck the current reading. If the reading is not accurate, repeat the steps.
10. Send 0x002D to `AltManufacturerAccess()` to clear the `[CAL_EN]` flag if all calibration is complete.

12.2.2 Deadbands

The gauge can be configured to ignore current and coulomb measurements below individually programmable levels.

12.2.2.1 Current Deadband

When current measures to a value less than the value programmed in **Deadband, Current()** will report 0. This has no effect on the coulomb counting for the gas gauging functionality. The value of **Deadband** should be selected based on the characterization of the battery electronics design combined with the environment in which the battery will be used. If the PCB senses noise causing a real no-current condition to report a non-zero value, then **Deadband** could be adjusted accordingly.

12.2.2.2 Coulomb Counter Deadband

During normal operation, there could be noise generated in the battery electronics environment that could cause the gauge to accumulate incorrectly (positively or negatively). To filter out this noise, the **Coulomb Counter Deadband** setting is used. Any input below this threshold is not accumulated.

12.2.3 Current Calibration Data Flash

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Calibration	Current	CC Gain	F4	1.00E-001	4.00E+000	3.68	—	Coulomb Counter Gain
Calibration	Current	Capacity Gain	F4	2.98262E+004	1.193046E+006	4390411.01	—	Capacity Gain
Calibration	Current Deadband	Deadband	U1	0	255	3	mA	Cell-based deadband to report 0 mA
Calibration	Current Deadband	Coulomb Counter Deadband	U1	0	255	9	116 nV	Coulomb counter deadband to report 0 charge (This setting should not be modified.)

12.3 Temperature Calibration

Note

For temperature calibration, only an offset is determined and then applied to the gauge's measured temperatures.

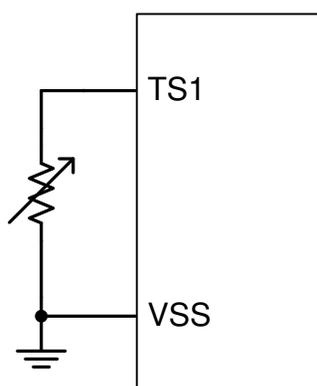


Figure 12-3. Temperature Calibration

12.3.1 Internal Temperature Sensor Calibration

1. Apply a known temperature in 0.1°C, and ensure that temperature $Temp_{TINT}$ is applied to the device.
2. Read the TINT offset_{old} from **Internal Temp Offset**.
3. Read the reported temperature from `DAStatus2()`:
 - $TINT = AA_{aa}$ of `DAStatus2()`

Is TINT > 0? If yes, TINT = AAaa – 2732.

- Calculate temperature offset:

$$TINT\ offset = TEMP_{TINT} - TINT + TINT\ offset_{old}$$

- Write the new **Internal Temp Offset** value to data flash.
- Recheck the *DAStatus2()* reading. If the reading is not accurate, repeat the steps.

12.3.2 TS Calibration

- Apply a known temperature in 0.1°C, and ensure the temperature TEMP_{TS} is applied to the thermistor connected to the TS terminal.
- Read the TS offset_{old} from **External1 Temp Offset**.
- Read the appropriate temperature from the *DAStatus2()* block as TS.
- Calculate the temperature offset:

$$TS\ offset = TEMP_{TS} - TS + TS\ offset_{old}$$

- Write the new **External1 Temp Offset** value to data flash.
- Recheck the *DAStatus2()* reading. If the reading is not accurate, repeat the steps.

12.3.3 Temperature Calibration Data Flash

It is usually not necessary to adjust these offsets. These offsets can be used to improve temperature accuracy at temperatures away from the calibration temperature of the models below; owever, they can reduce accuracy across the range of temperatures.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Calibration	Temperature	Internal Temp Offset	I1	-128	127	0	0.1 °C	Internal temperature sensor reading offset
Calibration	Temperature	External1 Temp Offset	I1	-128	127	0	0.1 °C	TS pin temperature sensor reading offset

12.3.4 Cell Temp Model

The parameters in the following table are used for the Semitec 103AT-2 thermistor. These parameters will only need to be updated if a different thermistor is used. See the application report to calculate coefficients for other thermistors.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Calibration	Cell Temp Model	Coefficient a1	I2	-32768	32767	-17447	—	Cell Temperature calculation polynomial a1
Calibration	Cell Temp Model	Coefficient a2	I2	-32768	32767	29332	—	Cell Temperature calculation polynomial a2
Calibration	Cell Temp Model	Coefficient a3	I2	-32768	32767	-25430	—	Cell Temperature calculation polynomial a3
Calibration	Cell Temp Model	Coefficient a4	I2	-32768	32767	29836	—	Cell Temperature calculation polynomial a4
Calibration	Cell Temp Model	Coefficient a5	I2	-32768	32767	1200	—	Cell Temperature calculation polynomial a5
Calibration	Cell Temp Model	Coefficient b1	I2	-32768	32767	-293	—	Cell Temperature calculation polynomial b1
Calibration	Cell Temp Model	Coefficient b2	I2	-32768	32767	552	—	Cell Temperature calculation polynomial b2
Calibration	Cell Temp Model	Coefficient b3	I2	-32768	32767	-2887	—	Cell Temperature calculation polynomial b3
Calibration	Cell Temp Model	Coefficient b4	I2	-32768	32767	4591	—	Cell Temperature calculation polynomial b4
Calibration	Cell Temp Model	Rc0	I2	-32768	32767	11703	—	Resistance at 25°C
Calibration	Cell Temp Model	Adc0	I2	-32768	32767	11703	—	ADC reading at 25°C
Calibration	Cell Temp Model	Rpad	I2	-32768	32767	0 ⁽¹⁾	Ω	Pad Resistance (0 to use factory calibration)
Calibration	Cell Temp Model	Rint	I2	-32768	32767	0 ⁽¹⁾	Ω	Pullup resistor resistance (0 to use factory calibration)

(1) Setting this value to 0 causes the gauge to use the internal factory calibration default.

12.3.5 Internal Temp Model

Values in this table should not be modified, as the voltage-based sensor in the device was factory trimmed for these model parameters.

Calibration

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Calibration	Internal Temp Model	Int Gain	I2	-32768	32767	-13908	—	Internal temperature gain
Calibration	Internal Temp Model	Int Base Offset	I2	-32768	32767	6959	—	Internal temperature base offset
Calibration	Internal Temp Model	Int Minimum AD	I2	-32768	32767	0	—	Minimum AD count used for calculation
Calibration	Internal Temp Model	Int Maximum Temp	I2	-32768	32767	6959	0.1 K	Maximum Temperature boundary



12.1 Standard Data Commands

The BQ27Z561-R2 device uses a series of 2-byte standard commands to enable system reading and writing of battery information. Each standard command has an associated command code pair, as indicated in [Table 12-1, Standard Commands](#). The LSB of the command code corresponds to the LSB register data. The LSB should be read first to keep the register data synchronized. For some host systems, the host should change the byte order so that the order corresponds to the host's native endianness. Both the I²C and HDQ protocols have methods to access the data for each command code. The gauge updates and/or reads the standard command registers once per second.

Table 12-1. Standard Commands

Name	Register Code (LSB/MSB)	Description
<i>ManufacturerAccess/ControlStatus()</i>	CNTL 0x00/0x01	Control Register (See Section 12.1.1.)
<i>AtRate()</i>	AR 0x02/0x03	Read/write. The value is a signed integer with the negative value indicating a discharge current value. The default value is 0 and forces <i>AtRateTimeToEmpty()</i> to return 65,535.
<i>AtRateTimeToEmpty()</i>	ARTTE 0x04/0x05	This read-only function returns an unsigned integer value to predict remaining operating time based on battery discharge at the <i>AtRate()</i> value in minutes with a range of 0 to 65,534. A value of 65,535 indicates <i>AtRate()</i> = 0. The gas gauge updates the <i>AtRateTimeToEmpty()</i> within 1 s after the system sets the <i>AtRate()</i> value. The gas gauge updates these parameters every 1 s. The commands are used in NORMAL mode.
<i>Temperature()</i>	TEMP 0x06/0x07	This read-only function returns an unsigned integer value of temperature measured by the gas gauge and is used for the gauging algorithm. Values are reported in units 0.1 K. It reports either internal temperature or external thermistor temperature, depending on the setting of the <i>[TS1]</i> and <i>[TSInt]</i> bits in Temperature Enable .
<i>Voltage()</i>	VOLT 0x08/0x09	This read-only function returns an unsigned integer value of the measured cell pack in mV with a range of 0 to 6000 mV.
<i>BatteryStatus()</i>	FLAGS 0x0A/0x0B	This read-only function returns various battery status information.
<i>Current()</i>	INSTCURR 0x0C/0x0D	This read-only function returns a signed integer value that is the instantaneous current flow through the sense resistor. The value is updated every 1 s. Units are mA.
<i>RemainingCapacity()</i>	RM 0x10/0x11	This read-only command returns the predicted remaining capacity, based on rate (per configured Load Select), temperature, present depth-of-discharge, and stored impedance. Values are reported in mAh.
<i>FullChargeCapacity()</i>	FCC 0x12/0x13	This read-only command returns the predicted capacity of the battery at full charge, based on rate (per configured Load Select), temperature, present depth-of-discharge, and stored impedance. Values are reported in mAh.
<i>AverageCurrent()</i>	AI 0x14/0x15	This read-only function returns a signed integer value that is the average current flow through the sense resistor. The value is updated every 1 s. Units are mA.
<i>AverageTimeToEmpty()</i>	TTE 0x16/0x17	Uses average current value with a time constant of 15 s for this method. A value of 65,535 means the battery is not being discharged.
<i>AverageTimeToFull()</i>	TTF 0x18/0x19	This read-only function returns a signed integer value, predicting time to reach full charge for the battery in units of minutes based on <i>AverageCurrent()</i> . The computation accounts for the taper current time extension from a linear TTF computation based on a fixed <i>AverageCurrent()</i> rate of charge accumulation. A value of 65,535 indicates the battery is not being charged.
<i>MaxLoadCurrent()</i>	MLI 0x1E/0x1F	This read-only function returns a signed integer value in units of mA of the maximum load current. The <i>MaxLoadCurrent()</i> is an adaptive measurement which is initially reported as the maximum load current programmed in Max Load Current . If the measured current is ever greater than Max Load Current , then the <i>MaxLoadCurrent()</i> updates to the new current. <i>MaxLoadCurrent()</i> is reduced to the average of the previous value and Max Load Current whenever the battery is charged to full after a previous discharge to an RSOC of less than Max Load Rsoc . This will prevent the reported value from maintaining an unusually high value.
<i>MaxLoadTimeToEmpty()</i>	MLTTE 0x20/0x21	This read-only function returns an unsigned integer value, predicting remaining battery life at the maximum discharge load current rate in units of minutes. A value of 65,535 indicates that the battery is not being discharged.
<i>AveragePower()</i>	AP 0x22/0x23	This read-only function returns a signed integer value of average power during battery charging and discharging. It is negative during discharge and positive during charge. A value of 0 indicates that the battery is not being discharged. The value is reported in units of mW.
<i>BTPDischargeSet()</i>	BTP 0x24/0x25	This read/write-word command updates the BTP set threshold for DISCHARGE mode for the next BTP interrupt, deasserts the present BTP interrupt, and clears the <i>OperationStatus()[BTP_INT]</i> bit.
<i>BTPChargeSet()</i>	BTP 0x26/0x27	The read/write-word command updates the BTP set threshold for CHARGE mode for the next BTP interrupt, deasserts the present BTP interrupt, and clears the <i>OperationStatus()[BTP_INT]</i> bit.

Table 12-1. Standard Commands (continued)

Name	Register Code (LSB/MSB)	Description
<i>InternalTemperature()</i>	INT_TEMP 0x28/0x29	This read-only function returns an unsigned integer value of the measured internal temperature of the device in 0.1 K units measured by the gas gauge.
<i>CycleCount()</i>	CC 0x2A/0x2B	This read-only function returns an unsigned integer value of the number of cycles the battery has experienced a discharge (range 0 to 65,535). One cycle occurs when accumulated discharge greater than or equal to the cycle count threshold.
<i>RelativeStateOfCharge()</i>	RSOC 0x2C/0x2D	This read-only function returns an unsigned integer value of the predicted remaining battery capacity expressed as percentage of <i>FullChargeCapacity()</i> with a range of 0% to 100%.
<i>StateOfHealth()</i>	SOH 0x2E/0x2F	This read-only function returns an unsigned integer value of the battery state-of-health expressed as a percentage of the ratio of predicted FCC (simulated with SOH Load Rate at 25°C) over the <i>DesignCapacity()</i> . The range is 0% to 100%.
<i>ChargingVoltage()</i>	CV 0x30/0x31	Returns the desired charging voltage in mV to the charger
<i>ChargingCurrent()</i>	CC 0x32/0x33	Returns the desired charging current in mA to the charger
<i>TerminateVoltage()</i>	0x34/0x35	Returns or updates the value of Terminate Voltage
<i>TimeStampUpper()</i>	0x36/0x37	Returns or updates the upper 16 bits of the time stamp in seconds
<i>TimeStampLower()</i>	0x38/0x39	Returns or updates the lower 16 bits of the time stamp in seconds
<i>QmaxCycles()</i>	0x3A/0x3B	Returns cycle count at the last QMax update
<i>DesignCapacity()</i>	0x3C/0x3D	In SEALED and UNSEALED access: This command returns the value stored in Design Capacity mAh . This is intended to be a theoretical or nominal capacity of a new pack, but should have no bearing on the operation of the gas gauge functionality.
<i>AltManufacturerAccess()</i>	0x3E/0x3F	MAC data block command
<i>MACData()</i>	0x40/0x5F	MAC data block
<i>MACDataSum()</i>	0x60	MAC data block checksum
<i>MACDataLen()</i>	0x61	MAC data block length
<i>VoltHiSetThreshold()</i>	0x62/0x63	This read/write function is a signed integer in units of mV for the high voltage level threshold, which sets <i>InterruptStatus()[VOLT_HI]</i> .
<i>VoltHiClearThreshold()</i>	0x64/0x65	This read/write function is a signed integer in units of mV for the high voltage level threshold, which clears <i>InterruptStatus()[VOLT_HI]</i> .
<i>VoltLoSetThreshold()</i>	0x66/0x67	This read/write function is a signed integer in units of mV for the low voltage level threshold, which sets <i>InterruptStatus()[VOLT_LO]</i> .
<i>VoltLoClearThreshold()</i>	0x68/0x69	This read/write function is a signed integer in units of mV for the low voltage level threshold, which clears <i>InterruptStatus()[VOLT_LO]</i> .
<i>TempHiSetThreshold()</i>	0x6A	This read/write function is a signed integer in units of °C for the high temperature level threshold, which sets <i>InterruptStatus()[TEMP_HI]</i> .
<i>TempHiClearThreshold()</i>	0x6B	This read/write function is a signed integer in units of °C for the high temperature level threshold, which clears <i>InterruptStatus()[TEMP_HI]</i> .
<i>TempLoSetThreshold()</i>	0x6C	This read/write function is a signed integer in units of °C for the low temperature level threshold, which sets <i>InterruptStatus()[TEMP_LO]</i> .
<i>TempLoClearThreshold()</i>	0x6D	This read/write function is a signed integer in units of °C for the low temperature level threshold, which clears <i>InterruptStatus()[TEMP_LO]</i> .
<i>InterruptStatus()</i>	0x6E	This read-only function returns the status of the interrupt including cause of interrupt.
<i>SOCDeltaSetThreshold()</i>	0x6F	This read/write function is an unsigned char in units of % for the SOC delta level threshold, which clears <i>InterruptStatus()SOC_DELTA</i> .

12.1.1 0x00/01 ManufacturerAccess()/ControlStatus()

This read/write word function returns the control bits when read and is an interface to the manufacturer access system (MAC) when written. This command is provided for backward compatibility/ease of use, as all of the control bits except *ControlStatus()[ChecksumValid]* are available in *OperationStatusA()* and *OperationStatusB()* in addition to *AltManufacturerAccess()* being the recommended interface for MAC (as discussed in [Section 12.8](#)).

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

RSVD	FAS	SS	RSVD	RSVD	RSVD	Check Sum Valid	RSVD	RSVD	RSVD	RSVD	RSVD	LDMD	RDIS	VOK	QEN
------	-----	----	------	------	------	-----------------	------	------	------	------	------	------	------	-----	-----

RSVD (Bit 15): Reserved

FAS, SS (Bits 14–13): Legacy SECURITY mode

0, 0 = Full Access

0, 1 = Reserved

1, 0 = Unsealed

1, 1 = Sealed

RSVD (Bit 12): Reserved

RSVD (Bits 11–10): Reserved

ChecksumValid (Bit 9): Checksum valid

1 = Flash Writes are enabled.

0 = Flash Writes are disabled due to low voltage or PF condition.

RSVD (Bits 8–4): Reserved

LDMD (Bit 3): LOAD mode

1 = Constant power

0 = Constant current

RDIS (Bit 2): Resistance updates

1 = Disabled

0 = Enabled

VOK (Bit 1): Voltage OK for QMax update

1 = Detected

0 = Not detected

QEN (Bit 0): Impedance Track Gauging (Ra and QMax updates are enabled.)

12.1.2 0x02/03 AtRate()

This read/write word function sets the value used in calculating *AtRateTimeToEmpty()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Default	Unit
		SE	US	FA						
0x02/03	<i>AtRate()</i>	R/W			Word	I2	-32768	32767	0	mA

12.1.3 0x04/05 AtRateTimeToEmpty()

This read-word function returns the remaining time to fully discharge the battery based on *AtRate()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x04/05	<i>AtRateTimeToEmpty()</i>	R			Word	U2	0	65535	min	65535 indicates not being charged

12.1.4 0x06/07 Temperature()

This read-word function returns the temperature in units 0.1 K.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x06/07	<i>Temperature()</i>	R			Word	I2	0	32767	0.1 K

12.1.5 0x08/09 Voltage()

This read-word function returns the measured cell voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x08/09	<i>Voltage()</i>	R			Word	I2	0	32767	mV

12.1.6 0x0A/0B BatteryStatus()

This read-word function returns various battery status information.

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

RSVD	TCA	RSVD	RSVD	TDA	RSVD	RCA	RSVD	INIT	DSG	FC	FD	RSVD	RSVD	RSVD	RSVD
------	-----	------	------	-----	------	-----	------	------	-----	----	----	------	------	------	------

RSVD (Bit 15): Reserved

TCA (Bit 14): Terminate Charge Alarm

0 = Inactive

1 = Active

RSVD (Bits 13–12): Reserved

TDA (Bit 11): Terminate Discharge Alarm

0 = Inactive

1 = Active

RSVD (Bit 10): Reserved

RCA (Bit 9): Remaining Capacity Alarm

0 = Inactive

1 = Active

RSVD (Bit 8): Reserved

INIT (Bit 7): Initialization

0 = Complete

1 = Active

DSG (Bit 6): Discharging

0 = The battery is charging.

1 = The battery is discharging.

FC (Bit 5): Fully Charged

0 = The battery is not fully charged.

1 = The battery is fully charged.

FD (Bit 4): Fully Discharged

0 = The battery is okay.

1 = The battery is fully depleted.

RSVD (Bits 3–0): Reserved

12.1.7 0x0C/0D Current()

This read-word function returns the measured current from the coulomb counter.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x0C/0D	Current()	R			Word	I2	-32768	32767	mA

12.1.8 0x10/11 RemainingCapacity()

This read-word function returns the predicted remaining battery capacity.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x10/11	<i>RemainingCapacity()</i>		R		Word	U2	0	32767	mAh

12.1.9 0x12/13 FullChargeCapacity()

This read-word function returns the predicted battery capacity when fully charged.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x12/13	<i>FullChargeCapacity()</i>		R		Word	I2	0	32767	mAh

12.1.10 0x14/15 AverageCurrent()

This read-word function provides the filtered/average current.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x14/15	<i>AverageCurrent()</i>		R		Word	I2	-32767	32768	mA

12.1.11 0x16/17 AverageTimeToEmpty()

This read-word function returns the predicted remaining time to fully discharge the battery based on *AverageCurrent()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x16/17	<i>AverageTimeToEmpty()</i>		R		Word	U2	0	65535	min	65535 = The battery is not being discharged.

12.1.12 0x18/19 AverageTimeToFull()

This read-word function returns the predicted remaining time to achieve full charge based on *AverageCurrent()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x18/19	<i>AverageTimeToFull()</i>		R		Word	U2	0	65535	min	

12.1.13 0x1E/1F MaxLoadCurrent()

This read-word function returns the maximum load current.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x1E/1F	<i>MaxLoadCurrent()</i>		R		Word	I2	0	65535	mA

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Max Load	Max Load Current	I2	-32768	0	-500	mA	Initial value reported on <i>MaxLoadCurrent()</i>
Gas Gauging	Max Load	Max Load Rsoc	U1	0	100	50	%	Threshold that RSOC must fall below to average <i>MaxLoadCurrent()</i> with Max Load Current on the next valid charge termination

12.1.14 0x20/21 MaxLoadTimeToEmpty()

This read-word function returns the remaining time to fully discharge the battery based on *MaxLoadCurrent()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x20/21	<i>MaxLoadTimeToEmpty()</i>		R		Word	I2	0	65535	min

12.1.15 0x22/23 AveragePower()

This read-word function returns the average power [$Voltage() \times AverageCurrent()$] during battery charging or discharging. It is negative due to discharge and positive due to charge. A 0 value indicates the battery is not being discharged.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x22/23	<i>AveragePower()</i>		R		Word	I2	-32768	32767	mW

12.1.16 0x28/29 InternalTemperature()

This read-word function returns the internal die temperature in units 0.1 K.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x28/29	<i>InternalTemperature()</i>		R		Word	I2	0	32767	0.1 K

12.1.17 0x2A/2B CycleCount()

This read-word function returns the number of discharge cycles the battery has experienced.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x2A/2B	<i>CycleCount()</i>	R	R		Word	U2	0	65535	cycles

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Gas Gauging	Cycle	Cycle Count Percentage	U1	0	100	90	%	Percentage of <i>DesignCapacity()</i> or <i>FullChargeCapacity()</i> (determined by <i>IT Gauging Configuration[CTJ]</i>) to be used for the cycle count threshold
Gas Gauging	State	Cycle Count	U2	0	65535	0	—	Value reported by <i>CycleCount()</i> . Updated by the gauge automatically based on Cycle Count Percentage
Gas Gauging	State	QMax Cycle Count	U2	0	65535	0	—	The <i>CycleCount()</i> when QMax last updated

12.1.18 0x2C/2D RelativeStateOfCharge()—RSOC

This read-word function returns the predicted remaining battery capacity as a percentage of *FullChargeCapacity()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x2C/2D	<i>RelativeStateOfCharge()</i>		R		Word	U1	0	100	%

12.1.19 0x2E/2F StateOfHealth()

This command returns the state-of-health (SOH) information of the battery in percentage of **Design Capacity mAh**. It is a read-only command.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x2E/2F	<i>StateOfHealth()</i>		R		Word	U1	0	100	%

12.1.20 0x30/31 ChargingVoltage()

This read-word function returns the desired charging voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x30/31	<i>ChargingVoltage()</i>	R	R	R	Word	I2	0	32767	mV	32767 = Request maximum voltage

12.1.21 0x32/33 ChargingCurrent()

This read-word function returns the desired charging current.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x32/33	<i>ChargingCurrent()</i>	R	R	R	Word	I2	0	32767	mA	32767 = Request maximum current

12.1.22 0x34/35 TerminateVoltage()

This reads or writes the voltage level at which the state-of-charge goes to 0. See **Term Voltage** in [Section 4.5](#).

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x34/35	<i>TerminateVoltage()</i>	RW	RW	RW	Word	I2	0	32767	mV	

12.1.23 0x36/0x37/0x38/0x39 Timestamp()

This 4-byte value, which is the system runtime in seconds, can be read or written. Always begin the read operation at 0x36 (the LSB) to keep the bytes synchronized during the read by copying the gauge clock to the time stamp registers. The host should read bytes into its 32-byte unsigned integer format in the appropriate endianness. When written by the host, the gauge will update its internal clock on the write to register 0x39.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x36/37	<i>TimeStampUpper()</i>	R	RW	RW	Word	U2	0	65535	s	

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x38/39	<i>TimeStampLower()</i>	R	RW	RW	Word	U2	0	65535	s	

12.1.24 QMax Cycles() 0x3A/3B

This returns the cycle count when QMax was last updated. It is helpful for a host system to compare this to the present *CycleCount()*.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit	Note
		SE	US	FA						
0x3A/3B	<i>QmaxCycles()</i>	R	R	R	Word	U2	0	65535	—	

12.1.25 0x3C/3D DesignCapacity()

This read-word function returns the theoretical or nominal maximum pack capacity.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Default	Unit
		SE	US	FA						
0x3C/3D	<i>DesignCapacity()</i>	R	R/W	R/W	Word	I2	0	32767	5300	mAh
									2040	cWh

12.1.26 0x3E/3F AltManufacturerAccess()

Writes to this command are interchangeable with *AltManufacturerAccess()*. This command is provided to enable an easy way to verify the active MAC command while reading the *MACData()* returned by the MAC. The host may simply read from *AltManufacturerAccess()* to *MACDataLength()* with one block read. For a description of returned data values, see the *AltManufacturerAccess()* version of same command in [Section 12.8](#).

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Default	Unit
		SE	US	FA						
0x3E/3F	<i>AltManufacturerAccess()</i>	R	R	R	Word	—	—	—	—	—

12.1.27 0x40/0x5F MACData()

This is the data block for *AltManufacturerAccess()* or *AltManufacturerAccess()* commands.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Default	Unit
		SE	US	FA						
0x40/5F	<i>MACData()</i>	R	R	R	Block	—	—	—	—	—

12.1.28 0x60 MACDataChecksum()

This is the checksum of the *AltManufacturerAccess()* and *MACData()* bytes.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x60	<i>MACDataChecksum()</i>	R	R	R	Byte	—	—	—	—	—

The checksum is the 8-bit sum of the MSB and LSB of the command + the (command length) bytes in the buffer. The final sum is the bitwise inversion of the result. Because the length is part of the checksum, the verification cannot take place until the length is written. The checksum and length must be written together as a word to be valid.

12.1.29 0x61 MACDataLength()

This is the length for *AltManufacturerAccess()* and *MACData()*.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x61	<i>MACDataLength()</i>	R	R	R	Byte	—	—	—	—	—

The length byte for all MAC commands includes the 2-byte command, the 1-byte checksum, the 1-byte length, and 1 to 32 bytes of data. This means the minimum length value is 5 for a valid block (no length or checksum is used for command only writes, so a block of 0 size is not necessary). For proper write command validation, the checksum and length must be written in order (word access triggered).

12.1.30 0x62/63 VoltHiSetThreshold

This read/write-word function returns the desired interrupt set threshold for a high battery voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x62/63	<i>VoltHiSetThreshold()</i>	R/W	R/W	R/W	Word	I2	0	5000	mV

12.1.31 0x64/65 VoltHiClearThreshold

This read/write-word function returns the desired interrupt clear threshold for a high battery voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x64/65	<i>VoltHiClearThreshold()</i>	R/W	R/W	R/W	Word	I2	0	5000	mV

12.1.32 0x66/67 VoltLoSetThreshold

This read/write-word function returns the desired interrupt set threshold for a low battery voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x66/67	<i>VoltLoSetThreshold()</i>	R/W	R/W	R/W	Word	I2	0	5000	mV

12.1.33 0x68/69 VoltLoClearThreshold

This read/write-word function returns the desired interrupt clear threshold for a low battery voltage.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x68/69	<i>VoltLoClearThreshold()</i>	R/W	R/W	R/W	Word	I2	0	5000	mV

12.1.34 0x6A TempHiSetThreshold

This read/write-byte function returns the desired interrupt set threshold for a high battery temperature.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x6A	<i>TempHiSetThreshold()</i>	R/W	R/W	R/W	Byte	I1	-128	127	°C

12.1.35 0x6B TempHiClearThreshold

This read/write-byte function returns the desired interrupt clear threshold for a high battery temperature.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x6B	<i>TempHiClearThreshold()</i>	R/W	R/W	R/W	Byte	I1	-128	127	°C

12.1.36 0x6C TempLoSetThreshold

This read/write-byte function returns the desired interrupt set threshold for a low battery temperature.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x6C	<i>TempLoSetThreshold()</i>	R/W	R/W	R/W	Byte	I1	-128	127	°C

12.1.37 0x6D TempLoClearThreshold

This read/write-byte function returns the desired interrupt clear threshold for a low battery temperature.

I ² C Cmd	Name	Access			Proto- col	Type	Min	Max	Unit
		SE	US	FA					
0x6D	<i>TempLoClearThreshold()</i>	R/W	R/W	R/W	Byte	I1	-128	127	°C

12.1.38 0x6E InterruptStatus()

This read-byte function returns the status of the interrupt bits for high/low voltage and temperature.

Status	Condition	Action
Activate	0x0057 to <i>AltManufacturerAccess()</i>	Outputs <i>ManufacturingStatus()</i> flags on <i>MACData()</i>

7 6 5 4 3 2 1 0

RSVD	RSVD	RSVD	SOC_DELTA	TEMP_LO	TEMP_HI	VOLT_LO	VOLT_HI
------	------	------	-----------	---------	---------	---------	---------

RSVD (Bits 7–5): Reserved

SOC_DELTA (Bit 4): RSOC interrupt

- 1 = RSOC interrupt set
- 0 = RSOC interrupt cleared

TEMP_LO (Bit 3): Low temperature interrupt

- 1 = Low temperature interrupt set
- 0 = Low temperature interrupt cleared

TEMP_HI (Bit 2): High temperature interrupt

- 1 = High temperature interrupt set
- 0 = High temperature interrupt cleared

VOLT_LO (Bit 1): Low voltage interrupt

- 1 = Low voltage interrupt set
- 0 = Low voltage interrupt cleared

VOLT_HI (Bit 0): High voltage interrupt

- 1 = High voltage interrupt set
- 0 = High voltage interrupt cleared

12.1.39 0x6F SOCSetDeltaThreshold

This read/write-byte function returns the desired interrupt set threshold for battery RSOC delta.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Unit
		SE	US	FA					
0x6F	<i>SOCSetDeltaThreshold()</i>	R/W	R/W	R/W	Byte	U1	0	100	%

12.2 0x70, 0x71 SusTurboPwr()

This command reads the maximum peak power value for 10-s pulse, sustained turbo power, in cW.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x70/71	<i>SusTurboPwr()</i>	R/W	R/W	R/W	Word	I2	0	32767	na	cW

12.3 0x72, 0x73 MaxTurboPwr()

This command reads the maximum peak power value for 10-ms pulse occurring on top of 10-s 2 C-rate pulse.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x72/73	<i>MaxTurboPwr()</i>	R/W	R/W	R/W	Word	I2	0	32767	na	cW

12.4 0x74, 0x75 SusTurboCurr()

This command reads the sustained peak current value, sustained turbo current, in mA. The gauge computes a new RAM value sustained turbo current every second. Sustained turbo current is initialized to the present value of max turbo current on reset or power up.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x74/75	<i>SusTurboCurr()</i>	—	R/W	R/W	Word	I2	0	32767	—	mA

12.5 0x76, 0x77 MaxTurboCurr()

This command reads the maximum peak current value, max turbo current, in mA. The gauge computes a new RAM value of max turbo current every second. Max turbo current is initialized to present the value of max turbo current on reset or power up.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x76/77	<i>MaxTurboCurr()</i>	R/W	R/W	R/W	Word	I2	0	32767	—	mA

12.6 0x78, 0x79 TurboSysR()

This command sets the **System Resistance** value of the system serial resistance along the path from the battery to the system power converter input that includes FETs, traces, sense resistors, and so on.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x78/79	<i>TurboSysR()</i>	R/W	R/W	R/W	Word	I2	0	32767		mΩ

12.7 0x7A, 0x7B TurboEdv()

This command sets the minimal voltage at the system power converter input at which the system will still operate. This command writes to the data flash value **Min System Voltage**. It writes it once on the first use to adjust for possible changes in the system design from the time the battery pack was designed.

I ² C Cmd	Name	Access			Protocol	Type	Min	Max	Default	Unit
		SE	US	FA						
0x7A/7B	<i>TurboEdv()</i>	R/W	R/W	R/W	Word	I2	0	32767		mV

12.8 0x00, 0x01 ManufacturerAccess() and 0x3E, 0x3F AltManufacturerAccess()

AltManufacturerAccess() provides a method of reading and writing data in the Manufacturer Access System (MAC). The MAC command is sent via *AltManufacturerAccess()* by a block protocol. The result is returned on *AltManufacturerAccess()* via a block read.

Commands are sent by writing to registers 0x00/0x01 or 0x3E/0x3F. 0x3E and 0x3F work the same as 0x00 and 0x01, but are primarily intended for block writes and reads.

Example: Send a MAC *Gauging()* to enable IT via *AltManufacturerAccess()*.

- With Impedance Track disabled, send *Gauging()* (0x0021) to *AltManufacturerAccess()*
 - Command Write, start address = 0x3E (or 0x00). Data = 21 00 (data must be sent in little endian).
- IT is enabled, *ManufacturingStatus()[GAUGE_EN]* = 1.

Example: Read *Chemical ID()* (0x0006) via *AltManufacturerAccess()*.

- Send *Chemical ID()* to *AltManufacturerAccess()*.
 - Command Write, start address = 0x3E (or 0x00). Data sent = 06 00 (data must be sent in little endian).
- Read the result from *AltManufacturerAccess()* and *MACData()*.
 - Command Read, start address = 0x3E length = 36 bytes. The first 4 bytes of the response will be 06 00 10 12.
 - The first two bytes "06 00" is the MAC command (for verification).
 - The second two bytes "10 12" are the Chem ID in little endian. That is, 0x1210 for ChemID 1210.
 - The last two bytes of the 36-byte block will be the checksum and length. The length in this case will be 6. The checksum is 0xFF – (sum of the first length – 2 bytes). The length and checksum are used to validate the block response.

It is recommended to send “command only” operations to 0x00 and 0x01, and to set the command for a read back in the same way. The reason for this is that it can always reset any legacy support options that may be in effect; whereas, some legacy support options use 0x3E and 0x3F for other purposes. However, 0x3E and 0x3F can always safely be used for block reads. For backward compatibility, a request of the device number or version reports a value for a read on 0x00/0x01. The response word for the MAC commands DEV and VERSION (0x0001 and 0x0002) should report 0xFFA5 as the legacy response. This is meant as a token to indicate to the host that the real response is on the extended block. “Command only” operations take place immediately after the word write.

Table 12-2. AltManufacturerAccess() Command List

Command	Function	Access	Format	Data Read on MACData()	Not Available in SEALED Mode	Type	Units
0x0001	DeviceType	R	Block	√	—	hex	—

Table 12-2. AltManufacturerAccess() Command List (continued)

Command	Function	Access	Format	Data Read on MACData()	Not Available in SEALED Mode	Type	Units
0x0002	FirmwareVersion	R	Block	√	—	hex	—
0x0003	HardwareVersion	R	Block	√	—	hex	—
0x0004	IFChecksum	R	Block	√	—	hex	—
0x0005	StaticDFSignature	R	Block	√	—	hex	—
0x0006	ChemID	R	Block	√	—	hex	—
0x0007	Prev_MacWrite	R	Block	√	—	hex	—
0x0008	StaticChemDFSignature	R	Block	√	—	hex	—
0x0009	AllDFSignature	R	Block	√	—	hex	—
0x012	Reset	W	—	—	—	hex	—
0x0017	QMax Day	R	Block	√	—	U2	days
0x0021	Gauging (IT Enable)	W	—	—	√	hex	—
0x0023	LifetimeDataCollection	W	—	—	√	hex	—
0x0028	LifetimeDataReset	W	—	—	√	hex	—
0x002D	CalibrationMode	W	—	—	√	hex	—
0x002E	LifetimeDataFlush	W	—	—	√	hex	—
0x002F	LifetimeDataSpeedUp Mode	W	—	—	√	hex	—
0x0030	SealDevice	W	—	—	—	hex	—
0x0035	SecurityKeys	R/W	Block	√	√	hex	—
0x0041	Reset	W	—	—	—	hex	—
0x0044	SetDeepSleep	W	—	—	—	hex	—
0x0045	ClearDeepSleep	W	—	—	—	hex	—
0x0046	PulseGPIO	W	—	—	—	hex	—
0x0047	TambientSync	W	—	—	—	hex	—
0x0048	ClearGPIO	W	—	—	—	hex	—
0x0049	SetGPIO	W	—	—	—	hex	—
0x004A	Device Name	R/W	Block	√	—	hex	—
0x004B	Device Chem	R/W	Block	√	—	hex	—
0x004C	Manufacturer Name	R/W	Block	√	—	hex	—
0x004D	Manufacture Date	R/W	Block	√	—	hex	—
0x004E	Serial Number	R/W	—	√	—	hex	—
0x0054	OperationStatus	R	Block	√	—	hex	—
0x0055	ChargingStatus	R	Block	√	—	hex	—
0x0056	GaugingStatus	R	Block	√	—	hex	—
0x0057	ManufacturingStatus	R	Block	√	—	hex	—
0x0060	LifetimeDataBlock1	R	Block	√	—	Mixed	Mixed
0x0061	LifetimeDataBlock2	R	Block	√	—	Mixed	Mixed
0x0062	LifetimeDataBlock3	R	Block	√	—	U4	s
0x0063	LifetimeDataBlock4	R	Block	√	—	Mixed	Mixed
0x0065	LifetimeDataBlock6	R	Block	√	—	Mixed	Mixed
0x0065	LifetimeDataBlock7	R	Block	√	—	Mixed	Mixed
0x0067	LifetimeDataBlock8	R	Block	√	—	Mixed	Mixed
0x0068	LifetimeDataBlock9	R	Block	√	—	Mixed	Mixed
0x0069	LifetimeDataBlock10	R	Block	√	—	Mixed	Mixed
0x006A	LifetimeDataBlock11	R	Block	√	—	Mixed	Mixed
0x006B	LifetimeDataBlock12	R	Block	√	—	Mixed	Mixed
0x0070	ManufacturerInfo	R/W	Block	√	—	hex	—
0x0071	DAStatus1	R	Block	√	—	Mixed	Mixed
0x0072	DAStatus2	R	Block	√	—	Mixed	Mixed
0x0073	ITStatus1	R	Block	√	—	Mixed	Mixed
0x0074	ITStatus2	R	Block	√	—	Mixed	Mixed
0x0075	ITStatus3	R	Block	√	—	Mixed	Mixed
0x0077	FCC_SOH	R	Block	√	—	hex	—
0x0078	Filtered Capacity	R	Block	√	—	Hex	Mixed

Table 12-2. AltManufacturerAccess() Command List (continued)

Command	Function	Access	Format	Data Read on MACData()	Not Available in SEALED Mode	Type	Units
0x007A	ManufacturerInfoB	R/W	Block	√	—	Hex	—
0x007B	ManufacturerInfoC	R/W	Block	√	—	Hex	—
0x00B0	ChargingVoltageOverride	R/W	Block	√	√	I2	mV
0x01yy	DFAccessRowAddress	R/W	Block	—	√	hex	—
0x0F00	ROMMode	W	—	—	√	hex	—
0x7C40	SwitchToHDQ	W	—	—	√	hex	—
0xF080	ExitCalibrationOutput	R/W	Block	√	√	hex	—
0xF081	OutputCCandADCforCalibration	R/W	Block	√	√	hex	—

12.8.1 AltManufacturerAccess() 0x0001 Device Type

The device can be checked for its part number.

Status	Condition	Action
Enable	0x0001 to <i>AltManufacturerAccess()</i>	Returns the device part number on a subsequent read on <i>MACData()</i> in the following format: aaAA, where: aaAA: Device type

12.8.2 AltManufacturerAccess() 0x0002 Firmware Version

The device can be checked for its firmware version.

Status	Condition	Action
Enable	0x0002 to <i>AltManufacturerAccess()</i>	Returns the firmware revision on <i>MACData()</i> in the following format: ddDDvvVVbbBBTTzzZZRREE, where: ddDD: Device number vvVV: Version bbBB: build number TT: Firmware type zzZZ: Impedance Track version RR: Reserved EE: Reserved

12.8.3 AltManufacturerAccess() 0x0003 Hardware Version

The device can be checked for its hardware version.

Status	Condition	Action
Enable	0x0003 to <i>AltManufacturerAccess()</i>	Returns the hardware version on a subsequent read on <i>MACData()</i>

12.8.4 AltManufacturerAccess() 0x0004 Instruction Flash Signature

The device can return the instruction flash signature.

Status	Condition	Action
Enable	0x0004 to <i>AltManufacturerAccess()</i>	Returns the IF signature on a subsequent read on <i>MACData()</i> after a wait time of 250 ms

12.8.5 AltManufacturerAccess() 0x0005 Static DF Signature

This command returns the signature of all static data flash parameters. The command does not update **Static DF Signature**.

Status	Condition	Action
Enable	0x0005 to <i>AltManufacturerAccess()</i>	Returns the signature of all static DF on a subsequent read on <i>MACData()</i> after a wait time of 250 ms. The MSB is set to 1 if the calculated signature does not match the signature stored in DF.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
System Data	Integrity	Static DF Signature	H2	0	0x7FFF	0x0000	—	Static data flash signature. Use the MAC <i>StaticDFSSignature()</i> (with MSB set to 0) to manually initialize this value.

12.8.6 AltManufacturerAccess() 0x0006 Chemical ID

This command returns the chemical ID of the OCV tables used in the gauging algorithm.

Status	Condition	Action
Enable	0x0006 to <i>AltManufacturerAccess()</i>	Returns the chemical ID on subsequent read on <i>MACData()</i>

12.8.7 AltManufacturerAccess() 0x0007 Pre_MACWrite

This command enables copying the last MAC into a 2-byte block.

Status	Condition	Action
Enable	0x0007 to <i>AltManufacturerAccess()</i>	Copies the last MAC information into a 2-byte block <i>MACData()</i>

12.8.8 AltManufacturerAccess() 0x0008 Static Chem DF Signature

This command returns the signature of all static, chemistry-related data flash parameters. The command does not update **Static Chem DF Signature**.

Status	Condition	Action
Enable	0x0008 to <i>AltManufacturerAccess()</i>	Returns the signature of all static chemistry DF on a subsequent read on <i>MACData()</i> after a wait time of 250 ms. The MSB is set to 1 if the calculated signature does not match the signature stored in DF.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
System Data	Integrity	Static Chem DF Signature	H2	0	0x7FFF	0x3A4C	—	Static chemistry data signature. Use the MAC <i>StaticChemDFSSignature()</i> (with MSB set to 0) to manually initialize this value.

12.8.9 AltManufacturerAccess() 0x0009 All DF Signature

This command returns the signature of all data flash parameters. The command does not update **All DF Signature**.

Status	Condition	Action
Enable	0x0009 to <i>AltManufacturerAccess()</i>	Returns the signature of all DF parameters on a subsequent read on <i>MACData()</i> after a wait time of 250 ms. The MSB is set to 1 if the calculated signature does not match the signature stored in DF. It is normally expected that this signature will change due to updates of lifetime, gauging, and other information.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
System Data	Integrity	All DF Signature	H2	0	0x7FFF	0x0000	—	All data flash signature. Use the MAC <i>AllDFSSignature()</i> (with MSB set to 0) to manually initialize this value.

12.8.10 AltManufacturerAccess() 0x0012 Device Reset

This command resets the device.

Status	Condition	Action
Enable	0x0012 to <i>AltManufacturerAccess()</i>	Resets the device

Note

Command 0x0041 also resets the device.

12.8.11 AltManufacturerAccess() 0x0017 QMax Day

Instructs the fuel gauge to return the last day QMax was updated. The value is updated with the *Elapsed Time Count()* converted to days whenever QMax is updated.

12.8.12 AltManufacturerAccess() 0x0021 Gauging

This command enables or disables the gauging function to ease testing during manufacturing.

Status	Condition	Action
Disable	<i>ManufacturingStatus()[GAUGE_EN]</i> = 1 AND 0x0021 to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[GAUGE_EN]</i> = 0 Disables the gauging feature
Enable	<i>ManufacturingStatus()[GAUGE_EN]</i> = 0 AND 0x0021 to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[GAUGE_EN]</i> = 1 Enables the gauging feature

12.8.13 AltManufacturerAccess() 0x0023 Lifetime Data Collection

This command disables/enables lifetime data collection for manufacturing.

Status	Condition	Action
Disable	<i>ManufacturingStatus()[LF_EN]</i> = 1 AND 0x0023 to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[LF_EN]</i> = 0 The lifetime data collection feature is disabled.
Enable	<i>ManufacturingStatus()[LF_EN]</i> = 0 AND 0x0023 to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[LF_EN]</i> = 1 The lifetime data collection feature is enabled.

12.8.14 AltManufacturerAccess() 0x0028 Lifetime Data Reset

This command resets lifetime data in data flash for manufacturing.

Status	Condition	Action
Reset	0x0028 to <i>AltManufacturerAccess()</i>	Clears lifetime data in DF

12.8.15 AltManufacturerAccess() 0x002D CALIBRATION Mode

This command disables/enables entry into CALIBRATION mode. The status is indicated by the *ManufacturingStatus()[CAL_EN]* flag. CALIBRATION mode is disabled upon a reset.

Status	Condition	Action
Disable	<i>ManufacturingStatus()[CAL_EN]</i> = 1 AND 0x002D to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[CAL_EN]</i> = 0 Disables output of ADC and CC raw data on <i>MACData()</i>
Enable	<i>ManufacturingStatus()[CAL_EN]</i> = 0 AND 0x002D to <i>AltManufacturerAccess()</i>	<i>ManufacturingStatus()[CAL_EN]</i> = 1 Enables output of ADC and CC raw data on <i>MACData()</i> , controllable with 0xF081 on <i>AltManufacturerAccess()</i>

12.8.16 ManufacturerAccess() 0x002E Lifetime Data Flush

This command flushes the RAM lifetime data to data flash to help streamline evaluation testing.

12.8.17 ManufacturerAccess() 0x002F Lifetime Data SPEED UP Mode

For ease of evaluation testing, this command enables a lifetime SPEED UP mode where every 1 s in real time counts as 1 hour in FW time. When the lifetime SPEED UP mode is enabled, the *ManufacturingStatus()[LT_TEST]* = 1.

The SPEED UP mode will be disabled if this command is sent again when *[LT_TEST]* = 1, the *MAC LifetimeDataReset()* command is sent, the *MAC SealDevice()* command is sent, or the device is reset.

12.8.18 AltManufacturerAccess() 0x0030 Seal Device

This command seals the device for the field, disabling certain commands and access to DF.

Status	Condition	Action
Sealed	$OperationStatusA()[SEC1, SEC0] = 0, 1$ or $1, 0$ AND $0x0030$ to $AltManufacturerAccess()$	$OperationStatusA()[SEC1, SEC0] = 1, 1$ Certain commands are not available. See Table 12-1 for details.

12.8.19 AltManufacturerAccess() 0x0035 Security Keys

This is a read/write command that changes the Unseal, Full Access, and Lifetime reset keys. To read the keys, send the *SecurityKeys()* command to either the *AltManufacturerAccess()* 0x00 or 0x3E, followed by a read from *AltManufacturerAccess()*.

To change the keys, the write operations must be sent through *AltManufacturerAccess()* 0x3E with the *SecurityKeys()* followed by the keys. Each parameter entry must be sent in little endian.

Note

Create each access key to be unique; otherwise, the copy key will not execute the intended function.

Example of changing the Unseal key to 0x0123, 0x4567; the Full Access key to 0x89AB, 0xCDEF; and the Lifetime reset key to 0x2244, 0x2131:

Byte 0: Unseal Key LSW

Byte 1: Unseal Key MSW

Byte 2: Full Access Key LSW

Byte 3: Full Access Key MSW

Byte 4: Lifetime Reset Key LSW

Byte 5: Lifetime Reset Key MSW

Write block: command through *AltManufacturerAccess()* starting address 0x3E:

data block (hex) = [35 00 23 01 67 45 AB 89 EF CD 44 22 31 21].

Starting address 0x60, data block(hex) = [0A 0C] (checksum followed by length)

Checksum = $0x52 = \sim(0x35 + 0x00 + 0x23 + 0x01 + 0x67 + 0x45 + 0xAB + 0x89 + 0xEF + 0xCD + 0x44 + 0x22 + 0x31 + 0x21)$. The checksum is the 8-bit sum of the MSB and LSB of the command plus the (command length) bytes in the buffer. The final sum is the bitwise inversion of the result.

12.8.20 AltManufacturerAccess() 0x0037 Authentication Key

This command enters a new authentication key into the device.

Status	Condition	Action
Initiate	$OperationStatusA()[SEC1, SEC0] = 0, 1$ AND $0x0037$ to $AltManufacturerAccess()$	$OperationStatusB()[AUTH] = 1$ 160-bit random number available at <i>MACData()</i>
Enter Key	Correct 128-bit key written to <i>MACData()</i> in the format 0xAABBCCDDEEFFGGHHIIJJKLLMMNNOOPP, where AA is LSB. In addition to this information, the checksum + length data block is required.	Wait time 250 ms $OperationStatusB()[AUTH] = 0$ The device returns a 160-bit HMAC digest at <i>MACData()</i> in the format: 0xAABBCCDDEEFFGGHHIIJJKLLMMNNOOPPQQRRSSTT, where AA is LSB. The HMAC digest was calculated using a challenge of all 0s + key. The result can be used to verify the key without allowing a plain text read back.

12.8.21 AltManufacturerAccess() 0x0041 Device Reset

This command resets the device.

Status	Condition	Action
Enable	0x0041 to <i>AltManufacturerAccess()</i>	Resets the device

Note

Command 0x0012 also resets the device.

12.8.22 *AltManufacturerAccess()* 0x0044 Set Deep Sleep

This command instructs the gauge to enter DEEP SLEEP mode when available.

Status	Condition	Action
Enable	0x0044 to <i>AltManufacturerAccess()</i>	<i>OperationStatusB()[DPSLEEP] = 1</i>

12.8.23 *AltManufacturerAccess()* 0x0045 Clear Deep Sleep

This command instructs the gauge to exit DEEP SLEEP mode.

Status	Condition	Action
Enable	0x0045 to <i>AltManufacturerAccess()</i>	<i>OperationStatusB()[DPSLEEP] = 0</i>

12.8.24 *AltManufacturerAccess()* 0x0046 Pulse GPIO

This command generates a single pulse or state change on the PULS pin.

Status	Condition	Action
Enable	0x0046 to <i>AltManufacturerAccess()</i>	If <i>IO Config[GPIO_LEVEL_EN] = 0</i> , it generates a single pulse on the PULS pin with a polarity of <i>IO Config[GPIO_POL]</i> and a width of <i>GPIO Pulse Width</i> . If <i>IO Config[GPIO_LEVEL_EN] = 1</i> , it changes the state of the PULS pin.

12.8.25 *AltManufacturerAccess()* 0x0047 Tambient Sync

This command synchronizes the ambient temperature in Impedance Track, *T_ambient*, to the presently measured cell temperature, *Temperature()*.

Status	Condition	Action
Enable	0x0047 to <i>AltManufacturerAccess()</i>	Synchronize <i>T_ambient</i> to <i>Temperature()</i> and trigger an IT simulation if <i>I2C Gauging Configuration[TAMB_SYNC_SIM] = 1</i>

12.8.26 *AltManufacturerAccess()* 0x0047 Clear GPIO

This command clears the state on the PULS pin.

Status	Condition	Action
Enable	0x0048 to <i>AltManufacturerAccess()</i>	If <i>IO Config[GPIO_LEVEL_EN] = 1</i> , it clears the state of the PULS pin and clears the <i>OperationStatus()[GPIO_LVL]</i> flag.

12.8.27 *AltManufacturerAccess()* 0x0047 Set GPIO

This command sets state on the PULS pin.

Status	Condition	Action
Enable	0x0049 to <i>AltManufacturerAccess()</i>	If <i>IO Config[GPIO_LEVEL_EN] = 1</i> , it sets the state of the PULS pin and sets the <i>OperationStatus()[GPIO_LVL]</i> flag.

12.8.28 AltManufacturerAccess() 0x004A Device Name

This command returns the assigned pack name, as programmed in data flash.

Status	Condition	Action
Enable	0x004A to <i>AltManufacturerAccess()</i>	Returns the value stored in Device Name

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
I2C Configuration	Data	Device Name	S21	—	—	BQ27Z561	ASCII	Assigned pack name

12.8.29 AltManufacturerAccess() 0x004B Device Chem

This command returns the battery chemistry used in the pack, as programmed in data flash.

Status	Condition	Action
Enable	0x004B to <i>AltManufacturerAccess()</i>	Returns the value stored in Device Chemistry

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
I2C Configuration	Data	Device Chemistry	S5	—	—	LION	ASCII	The battery chemistry used in the pack. This parameter does not change with chemistry programming and must be updated manually.

12.8.30 AltManufacturerAccess() 0x004C Manufacturer Name

This command returns the pack manufacturer name, as programmed in data flash.

Status	Condition	Action
Enable	0x004C to <i>AltManufacturerAccess()</i>	Returns the value stored in Manufacturer Name

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
I2C Configuration	Data	Manufacturer Name	S21	—	—	Texas Instruments	ASCII	Pack manufacturer name

12.8.31 AltManufacturerAccess() 0x004D Manufacture Date

This command returns the manufacture date of the pack, as programmed in data flash.

Status	Condition	Action
Enable	0x004D to <i>AltManufacturerAccess()</i>	Returns the value stored in Manufacture Date

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
I2C Configuration	Data	Manufacture Date	U2	0	65535	1980-1-1	date	Manufacture date of the pack, which follows the format: Day + Month×32 + (Year–1980) × 512 Example: 10/27/2017 = 19291 (or 0x4B5B, binary split: 100101, 1010, 11011)

12.8.32 AltManufacturerAccess() 0x004E Serial Number

This command returns the serial number of the pack, as programmed in data flash.

Status	Condition	Action
Enable	0x004E to <i>AltManufacturerAccess()</i>	Returns the value stored in Serial Number

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
I2C Configuration	Data	Serial Number	H2	0x0000	0xFFFF	0x0001	—	Serial number of the pack

12.8.33 AltManufacturerAccess() 0x0054 OperationStatus

This command returns the *OperationStatusA()* and *OperationStatusB()* flags on *MACData()*.

Status	Condition	Action
Activate	0x0054 to <i>AltManufacturerAccess()</i>	Outputs <i>OperationStatusA()</i> and <i>OperationStatusB()</i> flags on <i>MACData()</i> in the format AAaaBBbb where AAaa is Operation Status A and BBbb is Operation Status B

12.8.33.1 Operation Status A

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

SLEEP	RSVD	RSVD	RSVD	SS	RSVD	SEC1	SEC0	BTP_INT	DP_SLP	GPIO_LVL	RSVD	RSVD	RSVD	RSVD	RSVD
-------	------	------	------	----	------	------	------	---------	--------	----------	------	------	------	------	------

SLEEP (Bit 15): SLEEP mode conditions met

- 1 = Active
- 0 = Inactive

RSVD (Bits 14–10): Reserved

SEC1, SEC0 (Bits 9, 8): SECURITY Mode

- 0, 0 = Reserved
- 0, 1 = Full Access
- 1, 0 = Unsealed
- 1, 1 = Sealed

BTP_INT (Bit 7): Battery Trip Point Interrupt. Setting and clearing this bit depends on various conditions.

See [Section 4.12](#) for details.

DP_SLP (Bit 6): DEEP SLEEP mode status

- 1 = Active
- 0 = Inactive

GPIO_LVL (Bit 5): GPIO pin level when used in level mode (*IO Config[GPIO_LEVEL_EN] = 1*)

- 1 = High
- 0 = Low

RSVD (Bits 4–0): Reserved

12.8.33.2 Operation Status B

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

RSVD	RSVD	RSVD	RSVD	RSVD	SLPAD	RSVD	INIT	DPSLE EPM	XL	RSVD	CAL	RSVD	AUTH	RSVD	RSVD
------	------	------	------	------	-------	------	------	--------------	----	------	-----	------	------	------	------

RSVD (Bits 15–11): Reserved

SLPAD (Bit 10): SLPAD

- 1 = Active
- 0 = Inactive

RSVD (Bit 9): Reserved

- 1 = Active
- 0 = Inactive

INIT (Bit 8): Initialization after full reset

- 1 = Active
- 0 = Inactive

DPSLEEPM (Bit 7): DEEP SLEEP command received

- 1 = Active
- 0 = Inactive

XL (Bit 6): 400-kHz mode

- 1 = Active
- 0 = Inactive

RSVD (Bit 5): Reserved

CAL (Bit 4): Calibration output (raw ADC and CC data)

- 1 = Active when either the MAC *OutputCCADCCal()* or *OutputShortedCCADCCal()* is sent and the raw CC and ADC data for calibration is available.
- 0 = When the raw CC and ADC data for calibration is not available.

RSVD (Bit 3): Reserved

AUTH (Bit 2): Authentication in progress

- 1 = Active
- 0 = Inactive

RSVD (Bits 1–0): Reserved

12.8.34 AltManufacturerAccess() 0x0055 ChargingStatus

This command returns the *Temp Range* and *Charging Status* flags on *MACData()*.

Status	Condition	Action
Activate	0x0055 to <i>AltManufacturerAccess()</i>	Outputs three bytes of charging related data in the format AABbbb, where AA is <i>Temp Range</i> and Bbbb is <i>Charging Status</i> flags on <i>MACData()</i>

12.8.34.1 Temp Range

Temp Range status bits indicate the current operating temperature range.

7	6	5	4	3	2	1	0
RSVD	OT	HT	STH	RT	STL	LT	UT

RSVD (Bit 7): Reserved

OT (Bit 6): Overtemperature range

- 1 = Temperature > T4
- 0 = Inactive

HT (Bit 5): High temperature range

- 1 = T3 < Temperature < T4
- 0 = Inactive

STH (Bit 4): Standard temperature high range

- 1 = T6 < Temperature < T3
- 0 = Inactive

RT (Bit 3): Recommended temperature range

- 1 = T5 < Temperature < T6

0 = Inactive

STL (Bit 2): Standard temperature low range

1 = $T2 < \text{Temperature} < T5$

0 = Inactive

LT (Bit 1): Low temperature range

1 = $T1 < \text{Temperature} < T2$

0 = Inactive

UT (Bit 0): Undertemperature range

1 = $\text{Temperature} < T1$

0 = Inactive

12.8.34.2 Charging Status

Charging Status bits indicate various status bits related to charging.

15 14 13 12 11 10 9 8 7 6 5 4 3 2 1 0

RSVD	RSVD	RSVD	RSVD	NCT	RSVD	CV_D GRD1	CV_D GRD0	VCT	MCHG	SU	IN	HV	MV	LV	PV
------	------	------	------	-----	------	--------------	--------------	-----	------	----	----	----	----	----	----

RSVD (Bits 15–12): Reserved

NCT (Bit 11): NCT

1 = Active

0 = Inactive

RSVD (Bit 10): Reserved

CV_DGRD (Bits 9–8): Charge degradation

0,0 = No degradation

0,1 = Mode 1

1,0 = Mode 2

1,1 = Mode 3

VCT (Bit 7): Charge termination

1 = Active

0 = Inactive

MCHG (Bit 6): Maintenance charge

1 = Active

0 = Inactive

SU (Bit 5): Charge suspend

1 = Active

0 = Inactive

IN (Bit 4): Charge inhibit

1 = Active

0 = Inactive

HV (Bit 3): High voltage region

1 = Active

0 = Inactive

MV (Bit 2): Mid voltage region

1 = Active

0 = Inactive

LV (Bit 1): Low voltage region

1 = Active

0 = Inactive

PV (Bit 0): Precharge voltage region

1 = Active

0 = Inactive

12.8.35 AltManufacturerAccess() 0x0056 GaugingStatus

This command returns the *GaugingStatus()* flags on *MACData()*.

Note

The [Battery Management Studio \(BQSTUDIO\)](#) tool splits the returned value of *GaugingStatus()* into two separate registers: Gauging Status = lowest byte, and IT Status = 2nd and 3rd bytes, with the 4th byte reserved.

Status		Condition										Action				
Activate		0x0056 to <i>AltManufacturerAccess()</i>										Outputs <i>GaugingStatus()</i> flags on <i>MACData()</i>				
31	30	29	28	27	26	25	24	23	22	21	20	19	18	17	16	
RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD	QMAXDOD OK	OCV FR	LDMD	RX	QMax	VDQ
15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0	
NSFM	OCVP RED	SLP QMax	QEN	VOK	RDIS	RSVD	REST	RSVD	DSG	EDV	RSVD	TC	TD	FC	FD	

RSVD (Bits 31–22): Reserved. Do not use.

QMAXDODOK (Bit 21): Indicates whether the DOD is outside the cell chemistry's voltage flat zone. QMax updates do not happen if DOD is in the flat zone.

1 = Outside the flat zone

0 = In the flat zone

OCVFR (Bit 20): Open circuit voltage in flat region (during RELAX)

1 = Detected

0 = Not detected

LDMD (Bit 19): LOAD mode

1 = Constant power

0 = Constant current

RX (Bit 18): Resistance update (toggles after every resistance update)

QMax (Bit 17): QMax update (toggles after every QMax update)

VDQ (Bit 16): Discharge qualified for learning (based on RU flag)

NSFM (Bit 15): Negative scale factor mode

1 = Negative Ra scaling factor detected

0 = Negative Ra scaling factor not detected

OCVPRED (Bit 14): Open-circuit-voltage predicted

- 1 = Fast OCV prediction is performed in RELAX mode.
- 0 = Fast OCV prediction is not performed or not in RELAX mode.

SLPQMax (Bit 13): QMax update during sleep

- 1 = Active
- 0 = Inactive

QEN (Bit 12): Impedance Track gauging (Ra and QMax updates are enabled.)

- 1 = Enabled
- 0 = Disabled

VOK (Bit 11): Voltage OK for QMax update

- 1 = Detected
- 0 = Not detected

RDIS (Bit 10): Resistance updates

- 1 = Disabled
- 0 = Enabled

RSVD (Bit 9): Reserved. Do not use.**REST (Bit 8):** Rest

- 1 = The OCV reading is taken.
- 0 = The OCV reading is not taken or is not in RELAX mode.

RSVD (Bit 7): Reserved. Do not use.**DSG (Bit 6):** Discharge/relax

- 1 = Charging not detected
- 0 = Charging detected

EDV (Bit 5): End-of-discharge termination voltage

- 1 = Termination voltage reached during discharge
- 0 = Termination voltage not reached or not in DISCHARGE mode

RSVD (Bit 4): Reserved. Do not use.**TC (Bit 3):** Terminate charge

- 1 = Detected
- 0 = Not detected

TD (Bit 2): Terminate discharge

- 1 = Detected
- 0 = Not detected

FC (Bit 1): Fully charged

- 1 = Detected
- 0 = Not detected

FD (Bit 0): Fully discharged

- 1 = Detected
- 0 = Not detected

12.8.36 AltManufacturerAccess() 0x0057 ManufacturingStatus

This command returns the *ManufacturingStatus()* flags on *MACData()*.

Status	Condition	Action
Activate	0x0057 to <i>AltManufacturerAccess()</i>	Outputs <i>ManufacturingStatus()</i> flags on <i>MACData()</i>

15	14	13	12	11	10	9	8
CAL_EN	LT_TEST	RSVD	RSVD	RSVD	RSVD	RSVD	RSVD
7	6	5	4	3	2	1	0
RSVD	RSVD	LF_EN	RSVD	GAUGE_EN	RSVD	RSVD	RSVD

CAL_EN (Bit 15): CALIBRATION mode

- 1 = Enabled
- 0 = Disabled

LT_TEST (Bit 14): LIFETIME SPEED UP mode

- 1 = Enabled
- 0 = Disabled

RSVD (Bits 13–6): Reserved

LF_EN (Bit 5): Lifetime data collection

- 1 = Enabled
- 0 = Disabled

RSVD (Bit 4): Reserved

GAUGE_EN (Bit 3): Gas gauging

- 1 = Enabled
- 0 = Disabled

RSVD (Bits 2–0): Reserved

12.8.37 AltManufacturerAccess() 0x0060 Lifetime Data Block 1

This command returns the lifetime data on *MACData()* with the following format:

aaAAbbBBccCCddDDeeEEffFFGGHHIIJJ.

Value	Description
AAaa	Max cell voltage
BBbb	Min cell voltage
CCcc	Max charge current
DDdd	Max discharge current
EEee	Max average discharge current
FFff	Max average discharge power
GG	Max cell temperature
HH	Min cell temperature
II	Max circuit temperature
JJ	Min circuit temperature

12.8.38 AltManufacturerAccess() 0x0062 Lifetime Data Block 3

This command returns the lifetime data on *MACData()* with the following format:

aaAAbbBB

Value	Description
AAaBBbb	Total FW Runtime

12.8.39 ManufacturerAccess() 0x0063 Lifetime Data Block 4

This command returns the lifetime data with the following format:

aaAAabbBBccCCddDDeeEEffff.

Value	Description
AAaa	Count of valid charge terminations
BBbb	Cycle count at last valid charge termination
CCcc	Count of QMax updates
DDdd	Cycle count at last QMax update
EEee	Count or impedance table updates
FFff	Cycle count at last impedance update

12.8.40 ManufacturerAccess() 0x0065-0x006B Lifetime SOC Range Table Data Blocks

These commands return the lifetime data on *MACData()*. See [Table 5-1](#) for more information on the collected time based data.

Each block access returns data, as indicated below, where MAC 0x0065 returns SOC range one, MAC 0x0066 returns SOC range two, and so on:

aaAAabbBBCCccDDddEEeeFFffGGggHHhhIiiiJJjjKKkkLLlIMMmmNNnnOOooPPpp.

Value	Description
AAaBBbb	Seconds at temperature range 1 at SOC range = (MAC number – 0x0064)
CCcDDdd	Seconds at temperature range 2 at SOC range = (MAC number – 0x0064)
EEeeFFff	Seconds at temperature range 3 at SOC range = (MAC number – 0x0064)
GGggHHhh	Seconds at temperature range 4 at SOC range = (MAC number – 0x0064)
IiiiJJjj	Seconds at temperature range 5 at SOC range = (MAC number – 0x0064)
KKkkLLll	Seconds at temperature range 6 at SOC range = (MAC number – 0x0064)
MMmmNNnn	Seconds at temperature range 7 at SOC range = (MAC number – 0x0064)
OOooPPpp	Seconds at temperature range 8 at SOC range = (MAC number – 0x0064)

12.8.41 AltManufacturerAccess() 0x0070 ManufacturerInfo

This command read or writes the data flash values of **Manufacturer Info Block A01** through **Manufacturer Info Block A32** on *MACData()*.

Status	Condition	Action
Activate	0x0070 to <i>AltManufacturerAccess()</i>	Outputs 32 bytes of Manufacturer Info on <i>MACData()</i> in the following format: AABCCDDEEFFGGHHIIJJKKLLMMNN OOPPQQRRSSTTUUVVWWXXVZZ112233445566

Class	Subclass	Name	Type	Min	Max	Default	Unit
System Data	Manufacturer Data	Manufacturer Info Block A01	H1	0x00	0xFF	0x61	—
System Data	Manufacturer Data	Manufacturer Info Block A02	H1	0x00	0xFF	0x62	—
System Data	Manufacturer Data	Manufacturer Info Block A03	H1	0x00	0xFF	0x63	—
System Data	Manufacturer Data	Manufacturer Info Block A04	H1	0x00	0xFF	0x64	—
System Data	Manufacturer Data	Manufacturer Info Block A05	H1	0x00	0xFF	0x65	—
System Data	Manufacturer Data	Manufacturer Info Block A06	H1	0x00	0xFF	0x66	—
System Data	Manufacturer Data	Manufacturer Info Block A07	H1	0x00	0xFF	0x67	—
System Data	Manufacturer Data	Manufacturer Info Block A08	H1	0x00	0xFF	0x68	—
System Data	Manufacturer Data	Manufacturer Info Block A09	H1	0x00	0xFF	0x69	—

Class	Subclass	Name	Type	Min	Max	Default	Unit
System Data	Manufacturer Data	Manufacturer Info Block A10	H1	0x00	0xFF	0x6A	—
System Data	Manufacturer Data	Manufacturer Info Block A11	H1	0x00	0xFF	0x6B	—
System Data	Manufacturer Data	Manufacturer Info Block A12	H1	0x00	0xFF	0x6C	—
System Data	Manufacturer Data	Manufacturer Info Block A13	H1	0x00	0xFF	0x6D	—
System Data	Manufacturer Data	Manufacturer Info Block A14	H1	0x00	0xFF	0x6E	—
System Data	Manufacturer Data	Manufacturer Info Block A15	H1	0x00	0xFF	0x6F	—
System Data	Manufacturer Data	Manufacturer Info Block A16	H1	0x00	0xFF	0x70	—
System Data	Manufacturer Data	Manufacturer Info Block A17	H1	0x00	0xFF	0x71	—
System Data	Manufacturer Data	Manufacturer Info Block A18	H1	0x00	0xFF	0x72	—
System Data	Manufacturer Data	Manufacturer Info Block A19	H1	0x00	0xFF	0x73	—
System Data	Manufacturer Data	Manufacturer Info Block A20	H1	0x00	0xFF	0x74	—
System Data	Manufacturer Data	Manufacturer Info Block A21	H1	0x00	0xFF	0x75	—
System Data	Manufacturer Data	Manufacturer Info Block A22	H1	0x00	0xFF	0x76	—
System Data	Manufacturer Data	Manufacturer Info Block A23	H1	0x00	0xFF	0x77	—
System Data	Manufacturer Data	Manufacturer Info Block A24	H1	0x00	0xFF	0x7A	—
System Data	Manufacturer Data	Manufacturer Info Block A25	H1	0x00	0xFF	0x78	—
System Data	Manufacturer Data	Manufacturer Info Block A26	H1	0x00	0xFF	0x79	—
System Data	Manufacturer Data	Manufacturer Info Block A27	H1	0x00	0xFF	0x30	—
System Data	Manufacturer Data	Manufacturer Info Block A28	H1	0x00	0xFF	0x31	—
System Data	Manufacturer Data	Manufacturer Info Block A29	H1	0x00	0xFF	0x32	—
System Data	Manufacturer Data	Manufacturer Info Block A30	H1	0x00	0xFF	0x33	—
System Data	Manufacturer Data	Manufacturer Info Block A31	H1	0x00	0xFF	0x34	—
System Data	Manufacturer Data	Manufacturer Info Block A32	H1	0x00	0xFF	0x35	—

12.8.42 AltManufacturerAccess() 0x0071 DAStatus1

This command returns the cell voltage, cell current, cell power, power, and average power on *MACData()*.

Status	Condition	Action
Activate	0x0071 to <i>AltManufacturerAccess()</i>	Outputs 32 bytes of data on <i>MACData()</i> in the following format: aaAAbbBBccCCddDDeeEEffFGgGHhHhIiIjJkKkKlLlMmMnNn NNooOOpPpP where: AAaa: Cell 1 voltage BBbb: CCcc: DDdd: EEee: FFff: GGgg: Cell 1 current. simultaneous current measured during Cell 1 Voltage measurement HHhh: Iiii: Jjji: Kkkk: Cell 1 Power. Calculated using Cell 1 Voltage and Cell 1 Current data LLll: Mmmmm: Nnnn: Oooo: Power calculated by $Voltage() \times Current()$ Pppp: Average power. Calculated by $Voltage() \times AverageCurrent()$

12.8.43 AltManufacturerAccess() 0x0072 DAStatus2

This command returns the internal temp sensor, TS1 *MACData()*.

Status	Condition	Action
Activate	0x0072 to <i>AltManufacturerAccess()</i>	Outputs 20 bytes of temperature data values on <i>MacData()</i> in the following format: aaAAbbBBccCCddDDeeEEffFGggGGhhHHiiIJJ where: AAaa: Int temperature BBbb: TS1 temperature CCcc: DDdd: EEee: FFff: Cell temperature GGgg: HHhh: Cell 1 raw voltage Iiii: Cell 1 raw current JJjj: Wake comparator current

12.8.44 *AltManufacturerAccess()* 0x0073 ITStatus1

This command instructs the device to return Impedance Track related gauging information on *MACData()*.

Status	Condition	Action
Activate	0x0073 to <i>AltManufacturerAccess()</i>	Outputs 20 bytes of IT data values on <i>MACData()</i> in the following format: aaAAbbBBccCCddDDeeEEffFGggGGhhHHiiIJJ where: AAaa: True Rem Q. True remaining capacity in mAh from IT simulation before any filtering or smoothing function. This value can be negative or higher than FCC. BBbb: True Rem E. True remaining energy in cWh from IT simulation before any filtering or smoothing function. This value can be negative or higher than FCC. CCcc: Initial Q. Initial capacity calculated from IT simulation DDdd: Initial E. Initial energy calculated from IT simulation EEee: True Full Chg Q. True full charge capacity from IT simulation without the effects of any smoothing function FFff: True Full Chg E. True full charge energy from IT simulation without the effects of any smoothing function GGgg: T_sim. Temperature during the last simulation run HHhh: T_ambient. Current assumed ambient temperature used by the IT algorithm for thermal modeling Iiii: Cell 1 RaScale. Ra table scaling factor of Cell 1 JJjj: Cell 1 CompRes. Last temperature compensated resistance of Cell 1

12.8.45 *AltManufacturerAccess()* 0x0074 ITStatus2

This command instructs the device to return Impedance Track related gauging information on *MACData()*.

Status	Condition	Action
Activate	0x0074 to <i>AltManufacturerAccess()</i>	Outputs 20 bytes of IT data values on <i>MACData()</i> in the following format: AABBCDDDEEFFggGGhhHHiiiJJkkKKllLmmMM where: AA: BB: LStatus—Learned status of resistance table Bit 3 Bit 2 Bit 1 Bit 0 QMax ITEN CF1 CF0 CF1, CF0: QMax Status 0,0 = Battery OK 0,1 = QMax is first updated in the learning cycle. 1,0 = QMax and resistance table updated in the learning cycle ITEN: IT enable 0 = IT disabled 1 = IT enabled QMax: QMax field updates 0 = QMax is not updated in the field. 1 = QMax is updated in the field. CC: Cell Grid 0. Active grid point of Cell 1 DD: EE: FF: GGggHHhh: State Time. Time passed since last state change (DISCHARGE, CHARGE, RELAX) Iiii: DOD0_0. Depth of discharge for Cell 1 JJjj: DOD0 Passed Q. Passed capacity since the last DOD0 update KKkk: DOD0 Passed E. Passed energy since last DOD0 update LLll: DOD0 Time. Time passed since the last DOD0 update MMmm: Cell 1 DODEOC. Depth of discharge at valid charge termination for Cell 1

12.8.46 *AltManufacturerAccess()* 0x0075 ITStatus3

This command instructs the device to return Impedance Track related gauging information on *MACData()*.

Status	Condition	Action
Activate	0x0075 to <i>AltManufacturerAccess()</i>	Outputs 14 bytes of IT data values on <i>MACData()</i> in the following format: aaAAbbBBccCCddDDeeEEffFFggGG where: AAaa: QMax 0. QMax of Cell 1 BBbb: QMax DOD0 0. DOD0 at last QMax update of Cell 1 CCcc: QMax Passed Q. Pass capacity since last QMax update DDdd: QMax Time. Time passed since last QMax update EEee: Temp k. Thermal model temperature factor FFff: Temp a. Thermal model temperature time constant GGgg: Raw DOD0 1. Raw DOD0 of Cell 1

12.8.47 *AltManufacturerAccess()* 0x0077 FCC_SOH

This command returns the capacity and energy results of the IT simulation for state-of-health.

Status	Condition	Action
Enable	0x0077 to <i>AltManufacturerAccess()</i>	Returns the state-of-health capacities (4 bytes) on a subsequent read on <i>MACData()</i> in the following format: aaAAbbBB where: AAaa: SOH FC@25C Q. State-of-health simulated at 25°C in mAh BBbb: SOH FC@25C E. State-of-health simulated at 25°C in cWh

12.8.48 *AltManufacturerAccess()* 0x0078 Filtered Capacity

This command instructs the device to return Impedance Track related gauging information on *MACData()*.

Status	Condition	Action
Activate	0x0078 to <i>AltManufacturerAccess()</i>	Outputs 8 bytes of IT data values on <i>MACData()</i> in the following format: AAaaBBbbCCccDDdd where: AAaa: Fit Rem Q. Filtered remaining capacity (mAh) BBbb: Fit Rem E. Filtered remaining capacity (cWh) CCcc: Fit FCC Q. Filtered full charge capacity (mAh) DDdd: Fit FCC E. Filtered full charge capacity (cWh)

12.8.49 *AltManufacturerAccess()* 0x007A *ManufacturerInfoB*

This command reads or writes the data flash values of *Manufacturer Info Block B01* through *Manufacturer Info Block B32* on *MACData()*.

Status	Condition	Action
Activate	0x007A to <i>AltManufacturerAccess()</i>	Outputs 32 bytes of Manufacturer Info on <i>MACData()</i> in the following format: AABCCDDEEFFGGHHIIJJKKLLMMNN OOPPQQRRSSTTUUVVWWXXVZZ112233445566

Class	Subclass	Name	Type	Min	Max	Default	Unit
System Data	Manufacturer Info B	Manufacturer Info Block B01	H1	0x00	0xFF	0x61	—
System Data	Manufacturer Info B	Manufacturer Info Block B02	H1	0x00	0xFF	0x62	—
System Data	Manufacturer Info B	Manufacturer Info Block B03	H1	0x00	0xFF	0x63	—
System Data	Manufacturer Info B	Manufacturer Info Block B04	H1	0x00	0xFF	0x64	—
System Data	Manufacturer Info B	Manufacturer Info Block B05	H1	0x00	0xFF	0x65	—
System Data	Manufacturer Info B	Manufacturer Info Block B06	H1	0x00	0xFF	0x66	—
System Data	Manufacturer Info B	Manufacturer Info Block B07	H1	0x00	0xFF	0x67	—
System Data	Manufacturer Info B	Manufacturer Info Block B08	H1	0x00	0xFF	0x68	—
System Data	Manufacturer Info B	Manufacturer Info Block B09	H1	0x00	0xFF	0x69	—
System Data	Manufacturer Info B	Manufacturer Info Block B10	H1	0x00	0xFF	0x6A	—
System Data	Manufacturer Info B	Manufacturer Info Block B11	H1	0x00	0xFF	0x6B	—
System Data	Manufacturer Info B	Manufacturer Info Block B12	H1	0x00	0xFF	0x6C	—
System Data	Manufacturer Info B	Manufacturer Info Block B13	H1	0x00	0xFF	0x6D	—
System Data	Manufacturer Info B	Manufacturer Info Block B14	H1	0x00	0xFF	0x6E	—
System Data	Manufacturer Info B	Manufacturer Info Block B15	H1	0x00	0xFF	0x6F	—
System Data	Manufacturer Info B	Manufacturer Info Block B16	H1	0x00	0xFF	0x70	—
System Data	Manufacturer Info B	Manufacturer Info Block B17	H1	0x00	0xFF	0x71	—
System Data	Manufacturer Info B	Manufacturer Info Block B18	H1	0x00	0xFF	0x72	—
System Data	Manufacturer Info B	Manufacturer Info Block B19	H1	0x00	0xFF	0x73	—
System Data	Manufacturer Info B	Manufacturer Info Block B20	H1	0x00	0xFF	0x74	—
System Data	Manufacturer Info B	Manufacturer Info Block B21	H1	0x00	0xFF	0x75	—
System Data	Manufacturer Info B	Manufacturer Info Block B22	H1	0x00	0xFF	0x76	—
System Data	Manufacturer Info B	Manufacturer Info Block B23	H1	0x00	0xFF	0x77	—
System Data	Manufacturer Info B	Manufacturer Info Block B24	H1	0x00	0xFF	0x7A	—
System Data	Manufacturer Info B	Manufacturer Info Block B25	H1	0x00	0xFF	0x78	—
System Data	Manufacturer Info B	Manufacturer Info Block B26	H1	0x00	0xFF	0x79	—
System Data	Manufacturer Info B	Manufacturer Info Block B27	H1	0x00	0xFF	0x30	—
System Data	Manufacturer Info B	Manufacturer Info Block B28	H1	0x00	0xFF	0x31	—
System Data	Manufacturer Info B	Manufacturer Info Block B29	H1	0x00	0xFF	0x32	—
System Data	Manufacturer Info B	Manufacturer Info Block B30	H1	0x00	0xFF	0x33	—
System Data	Manufacturer Info B	Manufacturer Info Block B31	H1	0x00	0xFF	0x34	—

Class	Subclass	Name	Type	Min	Max	Default	Unit
System Data	Manufacturer Info B	Manufacturer Info Block B32	H1	0x00	0xFF	0x35	—

12.8.50 AltManufacturerAccess() 0x007B ManufacturerInfoC

This command reads or writes the data flash values of **Manufacturer Info Block C01** through **Manufacturer Info Block C32** on *MACData()*. Data is organized with default values such as, for example, Info Block B in its table.

12.8.51 ManufacturerAccess() 0x00B0 ChargingVoltageOverride

This command enables writing the five advanced charge algorithm charging voltage values in SEALED mode to data flash in the following format: aaAAbbBBccCCddDDeeEE where:

Value	Description	Unit
AAaa	Low Temperature Charging Voltage	mV
BBbb	Standard Temperature Low Charging Voltage	mV
CCcc	Standard Temperature High Charging Voltage	mV
DDdd	High Temperature Charging Voltage	mV
EEee	Recommended Temperature Charging Voltage	mV

12.8.52 AltManufacturerAccess() 0x0F00 ROM Mode

This command sends the device into ROM mode in preparation for reprogramming.

Status	Condition	Action
ROM Mode	<i>OperationStatusA()</i> [SEC1, SEC0] = 0,1 AND 0x0F00 to <i>AltManufacturerAccess()</i>	The device goes into ROM mode to prepare for updates. The ROM command 0x08 returns it to FIRMWARE mode. (Note: ROM commands are sent to address 0x16 using the I ² C protocol.)

12.8.53 Data Flash Access() 0x4000–0x5FFF

Accessing data flash (DF) is only supported by the *AltManufacturerAccess()* by addressing the physical address.

To write to the DF, send the starting address, followed by the DF data block. The DF data block is the intended revised DF data to be updated. The size of the DF data block ranges from 1 byte to 32 bytes. All individual data must be sent in little endian.

Write to DF example:

Assuming: data1 locates at address 0x4000 and data2 locates at address 0x4002.

Both data1 and data2 are U2 type.

To update data1 and data2, send a block write with command = 0x3E

block = starting address + DF data block

= 0x00 + 0x40 + data1_LowByte + data1_HighByte + data2_LowByte + data2_HighByte

To read the DF, send a block write to the *AltManufacturerAccess()* followed by the starting address, then send a block read to the *AltManufacturerAccess()*. The return data contains the starting address followed by 32 bytes of DF data in little endian.

Read from DF example:

Taking the same assuming from the read DF example, to read DF:

a. Send the write block with command 0x3E, block = 0x00 + 0x40

b. Send the read block with command 0x3E

The returned block = a starting address + 32 bytes of DF data

= 0x00 + 0x40 + data1_LowByte + data1_HighByte + data2_LowByte + data2_HighByte.... data32_LowByte + data32_HighByte

The gauge supports an auto-increment on the address during a DF read. This greatly reduces the time required to read out the entire DF. To trigger auto-increment on the address during DF reads, follow the example above, but read from *AltManufacturerAccess()* through *MACDataLength()* for a total of 36 bytes. If another read block is performed starting from *AltManufacturerAccess()*, the gauge returns another 32 bytes of DF data, starting with address 0x4020.

12.8.54 *AltManufacturerAccess()* 0x7C40 Switch to HDQ

This command PERMANENTLY switches the device's communication protocol from I²C to HDQ.

Status	Condition	Action
Activate	<i>OperationStatusA()[SEC1,SEC0]</i> = 0,1 or 1,0 AND 0x7C40 to <i>AltManufacturerAccess()</i>	The device permanently switches the communication protocol to HDQ (includes ROM mode).

Note

After switching to HDQ, *I2C Configuration[XL]* has no effect on gauge operation.

12.8.55 *AltManufacturerAccess()* 0xF080 Exit Calibration Output Mode

This command stops the output of calibration data to the *MACData()* command.

Status	Condition	Action
Activate	<i>MACData()</i> = 1 AND 0xF080 to <i>AltManufacturerAccess()</i>	Stops output of ADC or CC data on <i>MACData()</i>

12.8.56 *AltManufacturerAccess()* 0xF081 Output CC and ADC for Calibration

This command instructs the device to output the raw values for calibration purposes on *MACData()*. All values are updated every 1000 ms and the format of each value is 2's complement, MSB first.

Status	Condition	Action
Disable	<i>OperationStatusB()[CAL]</i> = 1 AND 0xF080 to <i>AltManufacturerAccess()</i>	<i>OperationStatusB()[CAL]</i> = 0 Stops output of ADC and CC data on <i>MACData()</i>
Enable	0xF081 to <i>AltManufacturerAccess()</i>	<i>OperationStatusB()[CAL]</i> = 1 Outputs the raw CC and AD values on <i>MACData()</i> in the format of ZZYyaaAAbbBBccCCddDDeeEEffFF ggGGhhHHiilljjJJkkKK: ZZ: Rolling 8-bit counter, increments when values are refreshed. YY: Status, 1 when <i>AltManufacturerAccess()</i> = 0xF081 AAaa: Current (coulomb counter) BBaa: Cell 1 Voltage CCaa: DDaa: EEee: FFff: GGgg: HHhh: Cell 1 Current Iiii: JJjj: KKkk:

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13.1 Data Flash Access

13.1.1 Minimum Voltage

Data flash can only be updated when the cell voltage is above the **Valid Update Voltage**.

Class	Subclass	Name	Type	Min	Max	Default	Unit	Description
Power	Power	Valid Update Voltage	I2	0	32767	2800	mV	Min cell voltage threshold for the flash update

13.2 Data Formats

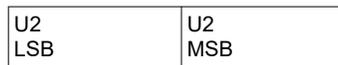
13.2.1 Unsigned Integer

Unsigned integers are stored without changes as 1-byte, 2-byte, or 4-byte values in little endian byte order.

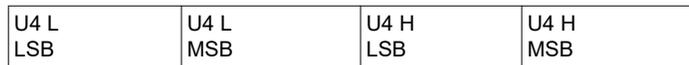
0



0 1



0 1 2 3



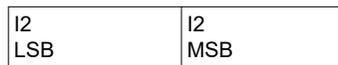
13.2.2 Integer

Integer values are stored in 2's-complement format in 1-byte, 2-byte, or 4-byte values in little endian byte order.

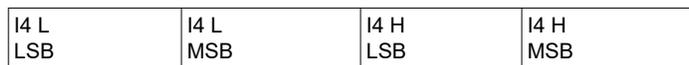
0



0 1



0 1 2 3



13.2.3 Floating Point

Floating point values are stored using the IEEE 754 single-precision, 4-byte format in little endian byte order.

0 1 2 3

Fract [0–7]	Fract [8–15]	Exp[0] + Fract[16–22]	Sign + Exp[1–7]
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Where:

Exp: 8-bit exponent stored with an offset bias of 127. The values 00 and FF have special meaning.

Fract: 23-bit fraction. If the exponent is > 0, then the mantissa is 1.fract. If the exponent is 0, then the mantissa is 0.fract.

The floating point value depends on the special cases of the exponent:

- If the exponent is FF and the fraction is 0, this represents \pm infinity.
- If the exponent is FF and the fraction is non-0, this represents "not a number" (NaN).
- If the exponent is 00, then the value is a subnormal number represented by $(-1)^{\text{sign}} \times 2^{-126} \times 0.\text{fraction}$.
- Otherwise, the value is a normalized number represented by $(-1)^{\text{sign}} \times 2^{(\text{exponent} - 127)} \times 1.\text{fraction}$.

13.2.4 Hex

Bit register definitions are stored in unsigned integer format.

13.2.5 String

String values are stored with the length byte first, followed by a number of data bytes defined with the length byte.

0 1 ... N

Length	Data0	...	DataN
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14.1 Data Flash Table

Table 14-1. Data Flash Table

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Calibration	Voltage	0x4000	Cell Gain	I2	-32767	32767	12101	—
Calibration	Current	0x4006	CC Gain	F4	1.00E-01	4.00E+00	3.68	—
Calibration	Current	0x400A	Capacity Gain	F4	2.98262E+02	1.193046E+08	4390411.01	—
Calibration	Temperature	0x4014	Internal Temp Offset	I1	-128	127	0	0.1°C
Calibration	Temperature	0x4015	External1 Temp Offset	I1	-128	127	0	0.1°C
Calibration	Internal Temp Model	0x4440	Int Gain	I2	-32768	32767	-13908	—
Calibration	Internal Temp Model	0x4442	Int base offset	I2	-32768	32767	6959	—
Calibration	Internal Temp Model	0x4444	Int Minimum AD	I2	-32768	32767	0	—
Calibration	Internal Temp Model	0x4446	Int Maximum Temp	I2	-32768	32767	6959	0.1°K
Calibration	Cell Temperature Model	0x4448	Coeff a1	I2	-32768	32767	-17447	—
Calibration	Cell Temperature Model	0x444A	Coeff a2	I2	-32768	32767	29322	—
Calibration	Cell Temperature Model	0x444C	Coeff a3	I2	-32768	32767	-25430	—
Calibration	Cell Temperature Model	0x444E	Coeff a4	I2	-32768	32767	29836	—
Calibration	Cell Temperature Model	0x4450	Coeff a5	I2	-32768	32767	1200	—
Calibration	Cell Temperature Model	0x4452	Coeff b1	I2	-32768	32767	-293	—
Calibration	Cell Temperature Model	0x4454	Coeff b2	I2	-32768	32767	552	—
Calibration	Cell Temperature Model	0x4456	Coeff b3	I2	-32768	32767	-2887	—
Calibration	Cell Temperature Model	0x4458	Coeff b4	I2	-32768	32767	4591	—
Calibration	Cell Temperature Model	0x445A	Rc0	I2	-32768	32767	11703	—
Calibration	Cell Temperature Model	0x445C	Adc0	I2	-32768	32767	11703	—
Calibration	Cell Temperature Model	0x445E	Rpad	I2	-32768	32767	0	—
Calibration	Cell Temperature Model	0x4460	Rint	I2	-32768	32767	0	—
Calibration	Current Deadband	0x4465	Deadband	U1	0	255	3	mA
Calibration	Current Deadband	0x4466	Coulomb Counter Deadband	U1	0	255	9	116 nV
Settings	Configuration	0x4640	I2C Gauging Configuration	H1	0x0	0x3F	0x20	Hex
Settings	Configuration	0x4641	I2C Configuration	H1	0x0	0xFF	0x08	Hex

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Settings	Configuration	0x4642	Auth Config	H1	0x0	0x03	0x00	Hex
Settings	Configuration	0x4643	Power Config	H1	0x0	0xFF	0x10	Hex
Settings	Configuration	0x4644	IO Config	H1	0x0	0xFF	0x00	Hex
Settings	Configuration	0x464B	Init Voltage High Set	I2	0	5000	4500	mV
Settings	Configuration	0x464D	Init Voltage High Clear	I2	0	5000	4400	mV
Settings	Configuration	0x464F	Init Voltage Low Set	I2	0	5000	2500	mV
Settings	Configuration	0x4651	Init Voltage Low Clear	I2	0	5000	2600	mV
Settings	Configuration	0x4653	Init Temperature High Set	I1	-128	127	60	°C
Settings	Configuration	0x4654	Init Temperature High Clear	I1	-128	127	55	°C
Settings	Configuration	0x4655	Init Temperature Low Set	I1	-128	127	0	°C
Settings	Configuration	0x4656	Init Temperature Low Clear	I1	-128	127	5	°C
Settings	Configuration	0x4657	SOC Delta	U1	0	100	1	%
Settings	Configuration	0x4658	GPIO Pulse Width	U1	0	255	7	25 ms
Settings	Configuration	0x466E	SOC Flag Config A	H2	0x0	0x0FFF	0x0C8C	Hex
Settings	Configuration	0x4670	SOC Flag Config B	H1	0x0	0xFF	0x8C	Hex
Settings	Configuration	0x4689	IT Gauging Configuration	H2	0x0	0xFFFF	0xF5FE	Hex
Settings	Configuration	0x468D	IT Gauging Ext	H2	0x0000	0x003F	0x007B	Hex
Settings	Configuration	0x46A6	Charging Configuration	H2	0x0	0xFFFF	0x00	Hex
Settings	Configuration	0x471D	Temperature Enable	H1	0x0	0x03	0x02	Hex
Settings	Configuration	0x471E	DA Configuration	H2	0x0	0x10	0x0010	Hex
Settings	BTP	0x4645	Init Discharge Set	I2	0	32767	150	mAh
Settings	BTP	0x4647	Init Charge Set	I2	0	32767	175	mAh
Settings	BTP	0x4649	Init Discharge Set RSOC	U1	0	100	10	%
Settings	BTP	0x464A	Init Charge Set RSOC	U1	0	100	15	%
Settings	Lifetimes	0x4729	Lifetimes Configuration	H2	0x0	0x00FF	0x0000	Hex
Settings	Lifetimes	0x472C	Time RSOC Threshold A	U1	0	100	95	%
Settings	Lifetimes	0x472D	Time RSOC Threshold B	U1	0	100	90	%
Settings	Lifetimes	0x472E	Time RSOC Threshold C	U1	0	100	80	%
Settings	Lifetimes	0x472F	Time RSOC Threshold D	U1	0	100	50	%
Settings	Lifetimes	0x4730	Time RSOC Threshold E	U1	0	100	20	%
Settings	Lifetimes	0x4731	Time RSOC Threshold F	U1	0	100	10	%
Settings	Lifetimes	0x4732	Time RSOC Threshold G	U1	0	100	5	%
Settings	Manufacturing	0x440C	Mfg Status init	H2	0x0	0xFFFF	0x0000	Hex
Advanced Charge Algorithm	Temperature Ranges	0x46A8	T1 Temp	I1	-128	127	0	°C
Advanced Charge Algorithm	Temperature Ranges	0x46A9	T2 Temp	I1	-128	127	10	°C
Advanced Charge Algorithm	Temperature Ranges	0x46AA	T5 Temp	I1	-128	127	20	°C
Advanced Charge Algorithm	Temperature Ranges	0x46AB	T6 Temp	I1	-128	127	25	°C
Advanced Charge Algorithm	Temperature Ranges	0x46AC	T3 Temp	I1	-128	127	45	°C
Advanced Charge Algorithm	Temperature Ranges	0x46AD	T4 Temp	I1	-128	127	55	°C
Advanced Charge Algorithm	Temperature Ranges	0x46AE	Hysteresis Temp	I1	0	127	1	°C
Advanced Charge Algorithm	Low Temp Charging	0x4382	Voltage	I2	0	32767	4400	mV
Advanced Charge Algorithm	Low Temp Charging	0x46AF	Current Low	I2	0	32767	132	mA

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Advanced Charge Algorithm	Low Temp Charging	0x46B1	Current Med	I2	0	32767	352	mA
Advanced Charge Algorithm	Low Temp Charging	0x46B3	Current High	I2	0	32767	264	mA
Advanced Charge Algorithm	Standard Temp Low Charging	0x4384	Voltage	I2	0	32767	4400	mV
Advanced Charge Algorithm	Standard Temp Low Charging	0x46B5	Current Low	I2	0	32767	1980	mA
Advanced Charge Algorithm	Standard Temp Low Charging	0x46B7	Current Med	I2	0	32767	4004	mA
Advanced Charge Algorithm	Standard Temp Low Charging	0x46B9	Current High	I2	0	32767	2992	mA
Advanced Charge Algorithm	Standard Temp High Charging	0x4386	Voltage	I2	0	32767	4400	mV
Advanced Charge Algorithm	Standard Temp High Charging	0x46BB	Current Low	I2	0	32767	1980	mA
Advanced Charge Algorithm	Standard Temp High Charging	0x46BD	Current Med	I2	0	32767	4004	mA
Advanced Charge Algorithm	Standard Temp High Charging	0x46BF	Current High	I2	0	32767	2992	mA
Advanced Charge Algorithm	High Temp Charging	0x4388	Voltage	I2	0	32767	4100	mV
Advanced Charge Algorithm	High Temp Charging	0x46C1	Current Low	I2	0	32767	1012	mA
Advanced Charge Algorithm	High Temp Charging	0x46C3	Current Med	I2	0	32767	1980	mA
Advanced Charge Algorithm	High Temp Charging	0x46C5	Current High	I2	0	32767	1496	mA
Advanced Charge Algorithm	Rec Temp Charging	0x438A	Voltage	I2	0	32767	4400	mV
Advanced Charge Algorithm	Rec Temp Charging	0x46C7	Current Low	I2	0	32767	2508	mA
Advanced Charge Algorithm	Rec Temp Charging	0x46C9	Current Med	I2	0	32767	4488	mA
Advanced Charge Algorithm	Rec Temp Charging	0x46CB	Current High	I2	0	32767	3520	mA
Advanced Charge Algorithm	Pre-Charging	0x46CD	Current	I2	0	32767	88	mA
Advanced Charge Algorithm	Maintenance Charging	0x46CF	Current	I2	0	32767	44	mA
Advanced Charge Algorithm	Voltage Range	0x46D1	Precharge Start Voltage	I2	0	32767	2500	mV
Advanced Charge Algorithm	Voltage Range	0x46D3	Charging Voltage Low	I2	0	32767	2900	mV
Advanced Charge Algorithm	Voltage Range	0x46D5	Charging Voltage Med	I2	0	32767	3600	mV
Advanced Charge Algorithm	Voltage Range	0x46D7	Charging Voltage High	I2	0	32767	4000	mV
Advanced Charge Algorithm	Voltage Range	0x46D9	Charging Voltage Hysteresis	U1	0	255	0	mV
Advanced Charge Algorithm	SoC Range	0x46DA	Charging SoC Med	U1	0	100	50	%
Advanced Charge Algorithm	SoC Range	0x46DB	Charging SoC High	U1	0	100	75	%
Advanced Charge Algorithm	SoC Range	0x46DC	Charging SoC Hysteresis	U1	0	100	1	%
Advanced Charge Algorithm	Degrade Mode 1	0x46DD	Cycle Threshold	U2	0	65535	50	—

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Advanced Charge Algorithm	Degrade Mode 1	0x46DF	SOH Threshold	U1	0	100	95	%
Advanced Charge Algorithm	Degrade Mode 1	0x46E0	Runtime Threshold	U2	0	65535	8760	h
Advanced Charge Algorithm	Degrade Mode 1	0x46E2	High SOC Threshold	U2	0	65535	8760	h
Advanced Charge Algorithm	Degrade Mode 1	0x46E4	High Temp Threshold	U2	0	65535	8760	h
Advanced Charge Algorithm	Degrade Mode 1	0x46E6	High Temp at SOC Threshold	U2	0	65535	8760	h
Advanced Charge Algorithm	Degrade Mode 1	0x46E8	Voltage Degradation	I2	0	32767	10	mV
Advanced Charge Algorithm	Degrade Mode 1	0x46EA	Current Degradation	U1	0	100	10	%
Advanced Charge Algorithm	Degrade Mode 2	0x46EB	Cycle Threshold	U2	0	65535	150	—
Advanced Charge Algorithm	Degrade Mode 2	0x46ED	SOH Threshold	U1	0	100	80	%
Advanced Charge Algorithm	Degrade Mode 2	0x46EE	Runtime Threshold	U2	0	65535	17520	h
Advanced Charge Algorithm	Degrade Mode 2	0x46F0	High SOC Threshold	U2	0	65535	17520	h
Advanced Charge Algorithm	Degrade Mode 2	0x46F2	High Temp Threshold	U2	0	65535	17520	h
Advanced Charge Algorithm	Degrade Mode 2	0x46F4	High Temp at SOC Threshold	U2	0	65535	17520	h
Advanced Charge Algorithm	Degrade Mode 2	0x46F6	Voltage Degradation	U2	0	65535	150	mV
Advanced Charge Algorithm	Degrade Mode 2	0x46F8	Current Degradation	U1	0	100	20	%
Advanced Charge Algorithm	Degrade Mode 3	0x46F9	Cycle Threshold	U2	0	65535	350	—
Advanced Charge Algorithm	Degrade Mode 3	0x46FB	SOH Threshold	U1	0	100	60	%
Advanced Charge Algorithm	Degrade Mode 3	0x46FC	Runtime Threshold	U2	0	65535	26280	h
Advanced Charge Algorithm	Degrade Mode 3	0x46FE	High SOC Threshold	U2	0	65535	26280	h
Advanced Charge Algorithm	Degrade Mode 3	0x4700	High Temp Threshold	U2	0	65535	26280	h
Advanced Charge Algorithm	Degrade Mode 3	0x4702	High Temp at SOC Threshold	U2	0	65535	26280	h
Advanced Charge Algorithm	Degrade Mode 3	0x4704	Voltage Degradation	U2	0	65535	250	mV
Advanced Charge Algorithm	Degrade Mode 3	0x4706	Current Degradation	U1	0	100	40	%
Advanced Charge Algorithm	Degrade Mode	0x4200	Runtime Degradate	U2	0	65535	0	hours
Advanced Charge Algorithm	Degrade Mode	0x4707	Cycle Count Start Runtime	U1	0	255	1	—
Advanced Charge Algorithm	Degrade Mode	0x4708	Runtime Update Interval	U1	0	18	10	h
Advanced Charge Algorithm	CS Degrade	0x4709	Temperature Threshold	I2	0	32767	3232	0.1°K
Advanced Charge Algorithm	CS Degrade	0x470B	Voltage Threshold	I2	0	32767	4200	mV
Advanced Charge Algorithm	CS Degrade	0x470D	Time Interval	U2	0	14400	300	s

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Advanced Charge Algorithm	CS Degrade	0x470F	Delta Voltage	I2	0	32767	25	mV
Advanced Charge Algorithm	CS Degrade	0x4711	Min CV	I2	0	32767	3000	mV
Advanced Charge Algorithm	Termination Config	0x4713	Charge Term Taper Current	I2	0	32767	100	mA
Advanced Charge Algorithm	Termination Config	0x4717	Charge Term Voltage Offset	I2	0	32767	100	mV
Advanced Charge Algorithm	Termination Config	0x4719	Charge Term Charging Voltage	I2	0	32767	4400	mV
Advanced Charge Algorithm	IR Correction	0x471C	Averaging Interval	U1	1	255	12	s
Gas Gauging	Current Thresholds	0x4721	Dsg Current Threshold	I2	-32768	32767	60	mA
Gas Gauging	Current Thresholds	0x4723	Chg Current Threshold	I2	-32768	32767	75	mA
Gas Gauging	Current Thresholds	0x4725	Quit Current	I2	0	32767	40	mA
Gas Gauging	Current Thresholds	0x4727	Dsg Relax Time	U1	0	255	60	s
Gas Gauging	Current Thresholds	0x4728	Chg Relax Time	U1	0	255	60	s
Gas Gauging	Max Load	0x4663	Max Load Current	I2	-32768	0	-500	mA
Gas Gauging	Max Load	0x4665	Max Load Rsoc	U1	0	100	50	%
Gas Gauging	Design	0x4666	Design Capacity mAh	I2	0	32767	5300	mAh
Gas Gauging	Design	0x4668	Design Capacity cWh	I2	0	32767	2040	cWh
Gas Gauging	Design	0x466A	Design Voltage	I2	0	32767	3850	mV
Gas Gauging	Cycle	0x466C	Cycle Count Percentage	U1	0	100	90	%
Gas Gauging	FD	0x4671	Set Voltage Threshold	I2	0	5000	3000	mV
Gas Gauging	FD	0x4673	Clear Voltage Threshold	I2	0	5000	3100	mV
Gas Gauging	FD	0x4675	Set % RSOC Threshold	U1	0	100	0	%
Gas Gauging	FD	0x4676	Clear % RSOC Threshold	U1	0	100	5	%
Gas Gauging	FC	0x4677	Set Voltage Threshold	I2	0	5000	4400	mV
Gas Gauging	FC	0x4679	Clear Voltage Threshold	I2	0	5000	4300	mV
Gas Gauging	FC	0x467B	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging	FC	0x467C	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging	TD	0x467D	Set Voltage Threshold	I2	0	5000	3200	mV
Gas Gauging	TD	0x467F	Clear Voltage Threshold	I2	0	5000	3300	mV
Gas Gauging	TD	0x4681	Set % RSOC Threshold	U1	0	100	6	%
Gas Gauging	TD	0x4682	Clear % RSOC Threshold	U1	0	100	8	%
Gas Gauging	TC	0x4683	Set Voltage Threshold	I2	0	5000	4400	mV
Gas Gauging	TC	0x4685	Clear Voltage Threshold	I2	0	5000	4300	mV
Gas Gauging	TC	0x4687	Set % RSOC Threshold	U1	0	100	100	%
Gas Gauging	TC	0x4688	Clear % RSOC Threshold	U1	0	100	95	%
Gas Gauging	State	0x4186	Qmax Cell 1	I2	0	32767	5359	mAh
Gas Gauging	State	0x4188	Qmax Day	U2	0	65535	0	—
Gas Gauging	State	0x418A	Qmax Cycle Count	U2	0	65535	0	—
Gas Gauging	State	0x418C	Update Status	H1	0x0	0x0E	0x0	—
Gas Gauging	State	0x418D	Cell 1 Chg Voltage at EoC	I2	0	32767	4375	mV
Gas Gauging	State	0x418F	Current at EoC	I2	0	32767	100	mA
Gas Gauging	State	0x4191	Avg I Last Run	I2	-32768	32767	-500	mA
Gas Gauging	State	0x4193	Avg P Last Run	I2	-32768	32767	-192	cW
Gas Gauging	State	0x4195	Delta Voltage	I2	-32768	32767	0	mV
Gas Gauging	State	0x4197	Temp k	I2	0	32767	200	0.1°C/25 6 cW
Gas Gauging	State	0x4199	Temp a	I2	0	32767	1000	s

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Gas Gauging	State	0x419B	Max Avg I Last Run	I2	-32768	32767	-500	mA
Gas Gauging	State	0x419D	Max Avg P Last Run	I2	-32768	32767	-192	cW
Gas Gauging	State	0x41C0	Cycle Count	U2	0	65535	0	—
Gas Gauging	State	0x463A	SOH Temp k	I2	0	32767	100	0.1°C/25 6 cW
Gas Gauging	State	0x463C	SOH Temp a	I2	0	32767	1000	s
Gas Gauging	IT Cfg	0x4180	Design Resistance	I2	1	32767	90	mΩ
Gas Gauging	IT Cfg	0x4182	Pack Resistance	I2	0	32767	0	mΩ
Gas Gauging	IT Cfg	0x4184	System Resistance	I2	0	32767	0	mΩ
Gas Gauging	IT Cfg	0x45CE	Ra Filter	U2	0	999	800	0.1%
Gas Gauging	IT Cfg	0x45D1	Ra Max Delta	U1	0	255	15	%
Gas Gauging	IT Cfg	0x45D4	Resistance Parameter Filter	U2	1	65535	65142	—
Gas Gauging	IT Cfg	0x45D6	Near EDV Ra Param Filter	U2	1	65535	62184	—
Gas Gauging	IT Cfg	0x45D8	Cell 1 Interconnect Resistance	I2	0	32767	0	2 ⁻¹⁰ Ω
Gas Gauging	IT Cfg	0x45DA	Max Current Change %	U1	0	100	10	%
Gas Gauging	IT Cfg	0x45DB	Resistance Update Voltage	I2	0	32767	50	mV
Gas Gauging	IT Cfg	0x4601	Qmax Delta	U1	3	100	5	%
Gas Gauging	IT Cfg	0x4602	Qmax Upper Bound	U1	100	255	130	%
Gas Gauging	IT Cfg	0x4603	Cycle Adjust Threshold	U1	0	255	20	—
Gas Gauging	IT Cfg	0x4604	Cycle Adj Incr	U1	0	255	5	0.01%
Gas Gauging	IT Cfg	0x4605	OCV Pred Active T Limit	U2	100	65535	200	s
Gas Gauging	IT Cfg	0x4607	OCV Pred Transient T	U2	100	65535	300	s
Gas Gauging	IT Cfg	0x4609	OCV Pred Measure Time	U2	0	65535	200	s
Gas Gauging	IT Cfg	0x460B	Term Voltage	I2	0	32767	3000	mV
Gas Gauging	IT Cfg	0x460D	Term V Hold Time	U1	0	255	2	s
Gas Gauging	IT Cfg	0x460E	Term Voltage Delta	I2	0	32767	200	mV
Gas Gauging	IT Cfg	0x4619	Max Simulation Iterations	U1	20	50	50	—
Gas Gauging	IT Cfg	0x461A	Simulation Near Term Delta	I2	0	32767	250	mV
Gas Gauging	IT Cfg	0x462C	Fast Scale Start SOC	U1	0	100	10	%
Gas Gauging	IT Cfg	0x4635	Min Delta Voltage	I2	-32768	32767	0	mV
Gas Gauging	IT Cfg	0x468F	Load Select	U1	0	7	1	—
Gas Gauging	IT Cfg	0x4690	Load Mode	U1	0	1	1	—
Gas Gauging	IT Cfg	0x4691	User Rate-mA	I2	-9000	0	0	mA
Gas Gauging	IT Cfg	0x4693	User Rate-cW	I2	-32768	0	0	cW
Gas Gauging	IT Cfg	0x4695	Reserve Cap-mAh	I2	0	9000	0	mAh
Gas Gauging	IT Cfg	0x4697	Reserve Cap-cWh	I2	0	32000	0	cWh
Gas Gauging	IT Cfg	0x46A4	Predict Ambient Time	U2	0	65535	2000	s
Gas Gauging	Smoothing	0x4699	Smooth Relax Time	U2	1	32767	1000	s
Gas Gauging	Smoothing	0x469B	Term Smooth Start Cell V Delta	I2	0	32767	150	mV
Gas Gauging	Smoothing	0x469D	Term Smooth Final Cell V Delta	I2	0	32767	100	mV
Gas Gauging	Smoothing	0x469F	Term Smooth Time	U1	1	32767	20	s
Gas Gauging	SoH	0x4639	SoH Load Rate	U1	0	255	50	0.1 Hr rate
Power	Power	0x4659	Valid Update Voltage	I2	0	32767	2800	mV
Power	Sleep	0x465B	Sleep Current	I2	0	32767	15	mA
Power	Sleep	0x465D	Voltage Time	U1	1	20	5	s
Power	Sleep	0x465E	Deep Sleep Voltage Time	U1	1	20	20	s
Power	Sleep	0x465F	Wake Check Time	U1	0	20	1	s
Power	Sleep	0x4660	Deep Sleep Current	I2	0	32767	10	mA

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Power	Hibernate	0x4662	Auto Time	U1	0	20	2	s
System Data	Manufacturer Data	0x4041	Manufacturer Info Block A01	H1	0x0	0xFF	0x61	Hex
System Data	Manufacturer Data	0x4042	Manufacturer Info Block A02	H1	0x0	0xFF	0x62	Hex
System Data	Manufacturer Data	0x4043	Manufacturer Info Block A03	H1	0x0	0xFF	0x63	Hex
System Data	Manufacturer Data	0x4044	Manufacturer Info Block A04	H1	0x0	0xFF	0x64	Hex
System Data	Manufacturer Data	0x4045	Manufacturer Info Block A05	H1	0x0	0xFF	0x65	Hex
System Data	Manufacturer Data	0x4046	Manufacturer Info Block A06	H1	0x0	0xFF	0x66	Hex
System Data	Manufacturer Data	0x4047	Manufacturer Info Block A07	H1	0x0	0xFF	0x67	Hex
System Data	Manufacturer Data	0x4048	Manufacturer Info Block A08	H1	0x0	0xFF	0x68	Hex
System Data	Manufacturer Data	0x4049	Manufacturer Info Block A09	H1	0x0	0xFF	0x69	Hex
System Data	Manufacturer Data	0x404A	Manufacturer Info Block A10	H1	0x0	0xFF	0x6A	Hex
System Data	Manufacturer Data	0x404B	Manufacturer Info Block A11	H1	0x0	0xFF	0x6B	Hex
System Data	Manufacturer Data	0x404C	Manufacturer Info Block A12	H1	0x0	0xFF	0x6C	Hex
System Data	Manufacturer Data	0x404D	Manufacturer Info Block A13	H1	0x0	0xFF	0x6D	Hex
System Data	Manufacturer Data	0x404E	Manufacturer Info Block A14	H1	0x0	0xFF	0x6E	Hex
System Data	Manufacturer Data	0x404F	Manufacturer Info Block A15	H1	0x0	0xFF	0x6F	Hex
System Data	Manufacturer Data	0x4050	Manufacturer Info Block A16	H1	0x0	0xFF	0x70	Hex
System Data	Manufacturer Data	0x4051	Manufacturer Info Block A17	H1	0x0	0xFF	0x71	Hex
System Data	Manufacturer Data	0x4052	Manufacturer Info Block A18	H1	0x0	0xFF	0x72	Hex
System Data	Manufacturer Data	0x4053	Manufacturer Info Block A19	H1	0x0	0xFF	0x73	Hex
System Data	Manufacturer Data	0x4054	Manufacturer Info Block A20	H1	0x0	0xFF	0x74	Hex
System Data	Manufacturer Data	0x4055	Manufacturer Info Block A21	H1	0x0	0xFF	0x75	Hex
System Data	Manufacturer Data	0x4056	Manufacturer Info Block A22	H1	0x0	0xFF	0x76	Hex
System Data	Manufacturer Data	0x4057	Manufacturer Info Block A23	H1	0x0	0xFF	0x77	Hex
System Data	Manufacturer Data	0x4058	Manufacturer Info Block A24	H1	0x0	0xFF	0x7A	Hex
System Data	Manufacturer Data	0x4059	Manufacturer Info Block A25	H1	0x0	0xFF	0x78	Hex
System Data	Manufacturer Data	0x405A	Manufacturer Info Block A26	H1	0x0	0xFF	0x79	Hex
System Data	Manufacturer Data	0x405B	Manufacturer Info Block A27	H1	0x0	0xFF	0x30	Hex
System Data	Manufacturer Data	0x405C	Manufacturer Info Block A28	H1	0x0	0xFF	0x31	Hex
System Data	Manufacturer Data	0x405D	Manufacturer Info Block A29	H1	0x0	0xFF	0x32	Hex
System Data	Manufacturer Data	0x405E	Manufacturer Info Block A30	H1	0x0	0xFF	0x33	Hex
System Data	Manufacturer Data	0x405F	Manufacturer Info Block A31	H1	0x0	0xFF	0x34	Hex
System Data	Manufacturer Data	0x4060	Manufacturer Info Block A32	H1	0x0	0xFF	0x35	Hex
System Data	Manufacturer Info B	0x4062	Manufacturer Info Block B01	H1	0x0	0xFF	0x61	Hex
System Data	Manufacturer Info B	0x4063	Manufacturer Info Block B02	H1	0x0	0xFF	0x62	Hex
System Data	Manufacturer Info B	0x4064	Manufacturer Info Block B03	H1	0x0	0xFF	0x63	Hex
System Data	Manufacturer Info B	0x4065	Manufacturer Info Block B04	H1	0x0	0xFF	0x64	Hex
System Data	Manufacturer Info B	0x4066	Manufacturer Info Block B05	H1	0x0	0xFF	0x65	Hex
System Data	Manufacturer Info B	0x4067	Manufacturer Info Block B06	H1	0x0	0xFF	0x66	Hex
System Data	Manufacturer Info B	0x4068	Manufacturer Info Block B07	H1	0x0	0xFF	0x67	Hex
System Data	Manufacturer Info B	0x4069	Manufacturer Info Block B08	H1	0x0	0xFF	0x68	Hex
System Data	Manufacturer Info B	0x406A	Manufacturer Info Block B09	H1	0x0	0xFF	0x69	Hex
System Data	Manufacturer Info B	0x406B	Manufacturer Info Block B10	H1	0x0	0xFF	0x6A	Hex
System Data	Manufacturer Info B	0x406C	Manufacturer Info Block B11	H1	0x0	0xFF	0x6B	Hex
System Data	Manufacturer Info B	0x406D	Manufacturer Info Block B12	H1	0x0	0xFF	0x6C	Hex
System Data	Manufacturer Info B	0x406E	Manufacturer Info Block B13	H1	0x0	0xFF	0x6D	Hex
System Data	Manufacturer Info B	0x406F	Manufacturer Info Block B14	H1	0x0	0xFF	0x6E	Hex
System Data	Manufacturer Info B	0x4070	Manufacturer Info Block B15	H1	0x0	0xFF	0x6F	Hex
System Data	Manufacturer Info B	0x4071	Manufacturer Info Block B16	H1	0x0	0xFF	0x70	Hex

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
System Data	Manufacturer Info B	0x4072	Manufacturer Info Block B17	H1	0x0	0xFF	0x71	Hex
System Data	Manufacturer Info B	0x4073	Manufacturer Info Block B18	H1	0x0	0xFF	0x72	Hex
System Data	Manufacturer Info B	0x4074	Manufacturer Info Block B19	H1	0x0	0xFF	0x73	Hex
System Data	Manufacturer Info B	0x4075	Manufacturer Info Block B20	H1	0x0	0xFF	0x74	Hex
System Data	Manufacturer Info B	0x4076	Manufacturer Info Block B21	H1	0x0	0xFF	0x75	Hex
System Data	Manufacturer Info B	0x4077	Manufacturer Info Block B22	H1	0x0	0xFF	0x76	Hex
System Data	Manufacturer Info B	0x4078	Manufacturer Info Block B23	H1	0x0	0xFF	0x77	Hex
System Data	Manufacturer Info B	0x4079	Manufacturer Info Block B24	H1	0x0	0xFF	0x7A	Hex
System Data	Manufacturer Info B	0x407A	Manufacturer Info Block B25	H1	0x0	0xFF	0x78	Hex
System Data	Manufacturer Info B	0x407B	Manufacturer Info Block B26	H1	0x0	0xFF	0x79	Hex
System Data	Manufacturer Info B	0x407C	Manufacturer Info Block B27	H1	0x0	0xFF	0x30	Hex
System Data	Manufacturer Info B	0x407D	Manufacturer Info Block B28	H1	0x0	0xFF	0x31	Hex
System Data	Manufacturer Info B	0x407E	Manufacturer Info Block B29	H1	0x0	0xFF	0x32	Hex
System Data	Manufacturer Info B	0x407F	Manufacturer Info Block B30	H1	0x0	0xFF	0x33	Hex
System Data	Manufacturer Info B	0x4080	Manufacturer Info Block B31	H1	0x0	0xFF	0x34	Hex
System Data	Manufacturer Info B	0x4081	Manufacturer Info Block B32	H1	0x0	0xFF	0x35	Hex
System Data	Manufacturer Info C	0x4083	Manufacturer Info Block C01	H1	0x0	0xFF	0x61	Hex
System Data	Manufacturer Info C	0x4084	Manufacturer Info Block C02	H1	0x0	0xFF	0x62	Hex
System Data	Manufacturer Info C	0x4085	Manufacturer Info Block C03	H1	0x0	0xFF	0x63	Hex
System Data	Manufacturer Info C	0x4086	Manufacturer Info Block C04	H1	0x0	0xFF	0x64	Hex
System Data	Manufacturer Info C	0x4087	Manufacturer Info Block C05	H1	0x0	0xFF	0x65	Hex
System Data	Manufacturer Info C	0x4088	Manufacturer Info Block C06	H1	0x0	0xFF	0x66	Hex
System Data	Manufacturer Info C	0x4089	Manufacturer Info Block C07	H1	0x0	0xFF	0x67	Hex
System Data	Manufacturer Info C	0x408A	Manufacturer Info Block C08	H1	0x0	0xFF	0x68	Hex
System Data	Manufacturer Info C	0x408B	Manufacturer Info Block C09	H1	0x0	0xFF	0x69	Hex
System Data	Manufacturer Info C	0x408C	Manufacturer Info Block C10	H1	0x0	0xFF	0x6A	Hex
System Data	Manufacturer Info C	0x408D	Manufacturer Info Block C11	H1	0x0	0xFF	0x6B	Hex
System Data	Manufacturer Info C	0x408E	Manufacturer Info Block C12	H1	0x0	0xFF	0x6C	Hex
System Data	Manufacturer Info C	0x408F	Manufacturer Info Block C13	H1	0x0	0xFF	0x6D	Hex
System Data	Manufacturer Info C	0x4090	Manufacturer Info Block C14	H1	0x0	0xFF	0x6E	Hex
System Data	Manufacturer Info C	0x4091	Manufacturer Info Block C15	H1	0x0	0xFF	0x6F	Hex
System Data	Manufacturer Info C	0x4092	Manufacturer Info Block C16	H1	0x0	0xFF	0x70	Hex
System Data	Manufacturer Info C	0x4093	Manufacturer Info Block C17	H1	0x0	0xFF	0x71	Hex
System Data	Manufacturer Info C	0x4094	Manufacturer Info Block C18	H1	0x0	0xFF	0x72	Hex
System Data	Manufacturer Info C	0x4095	Manufacturer Info Block C19	H1	0x0	0xFF	0x73	Hex
System Data	Manufacturer Info C	0x4096	Manufacturer Info Block C20	H1	0x0	0xFF	0x74	Hex
System Data	Manufacturer Info C	0x4097	Manufacturer Info Block C21	H1	0x0	0xFF	0x75	Hex
System Data	Manufacturer Info C	0x4098	Manufacturer Info Block C22	H1	0x0	0xFF	0x76	Hex
System Data	Manufacturer Info C	0x4099	Manufacturer Info Block C23	H1	0x0	0xFF	0x77	Hex
System Data	Manufacturer Info C	0x409A	Manufacturer Info Block C24	H1	0x0	0xFF	0x7A	Hex
System Data	Manufacturer Info C	0x409B	Manufacturer Info Block C25	H1	0x0	0xFF	0x78	Hex
System Data	Manufacturer Info C	0x409C	Manufacturer Info Block C26	H1	0x0	0xFF	0x79	Hex
System Data	Manufacturer Info C	0x409D	Manufacturer Info Block C27	H1	0x0	0xFF	0x30	Hex
System Data	Manufacturer Info C	0x409E	Manufacturer Info Block C28	H1	0x0	0xFF	0x31	Hex
System Data	Manufacturer Info C	0x409F	Manufacturer Info Block C29	H1	0x0	0xFF	0x32	Hex
System Data	Manufacturer Info C	0x40A0	Manufacturer Info Block C30	H1	0x0	0xFF	0x33	Hex
System Data	Manufacturer Info C	0x40A1	Manufacturer Info Block C31	H1	0x0	0xFF	0x34	Hex
System Data	Manufacturer Info C	0x40A2	Manufacturer Info Block C32	H1	0x0	0xFF	0x35	Hex
System Data	Integrity	0x40A3	Static DF Signature	H2	0x0	0x7FFF	0x0	Hex

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
System Data	Integrity	0x40A5	Static Chem DF Signature	H2	0x0	0x7FFF	0x3A4C	Hex
System Data	Integrity	0x40A7	All DF Signature	H2	0x0	0x7FFF	0x0	Hex
I2C Configuration	Data	0x40A9	Manufacture Date	U2	0	65535	0	date
I2C Configuration	Data	0x40AB	Serial Number	H2	0x0	0xFFFF	0x0001	Hex
I2C Configuration	Data	0x40AD	Manufacturer Name	S21	x	x	Texas Instruments	—
I2C Configuration	Data	0x40C2	Device Name	S21	x	x	BQ27Z561	—
I2C Configuration	Data	0x40D7	Device Chemistry	S5	x	x	LION	—
Lifetimes	Voltage	0x4202	Cell 1 Max Voltage	I2	0	32767	0	mV
Lifetimes	Voltage	0x4204	Cell 1 Min Voltage	I2	0	32767	32767	mV
Lifetimes	Current	0x4206	Max Charge Current	I2	0	32767	0	mA
Lifetimes	Current	0x4208	Max Discharge Current	I2	-32768	0	0	mA
Lifetimes	Current	0x420A	Max Avg Dsg Current	I2	-32768	0	0	mA
Lifetimes	Current	0x420C	Max Avg Dsg Power	I2	-32768	0	0	cW
Lifetimes	Temperature	0x420E	Max Temp Cell	I1	-128	127	-128	°C
Lifetimes	Temperature	0x420F	Min Temp Cell	I1	-128	127	127	°C
Lifetimes	Temperature	0x4210	Max Temp Int Sensor	I1	-128	127	-128	°C
Lifetimes	Temperature	0x4211	Min Temp Int Sensor	I1	-128	127	127	°C
Lifetimes	Charging Events	0x4212	No Valid Charge Term	U2	0	32767	0	events
Lifetimes	Charging Events	0x4214	Last Valid Charge Term	U2	0	32767	0	cycles
Lifetimes	Gauging Events	0x4216	No Of Qmax Updates	U2	0	32767	0	events
Lifetimes	Gauging Events	0x4218	Last Qmax Update	U2	0	32767	0	cycles
Lifetimes	Gauging Events	0x421A	No Of Ra Updates	U2	0	32767	0	events
Lifetimes	Gauging Events	0x421C	Last Ra Update	U2	0	32767	0	cycles
Lifetimes	Time	0x4221	Total Fw Runtime	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4225	Time Spent In UT RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4229	Time Spent In UT RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x422D	Time Spent In UT RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4231	Time Spent In UT RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4235	Time Spent In UT RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4239	Time Spent In UT RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x423D	Time Spent In UT RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4241	Time Spent In UT RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4245	Time Spent In LT RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4249	Time Spent In LT RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x424D	Time Spent In LT RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4251	Time Spent In LT RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4255	Time Spent In LT RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4259	Time Spent In LT RSOC F	U4	0	4.2949672 95e+009	0	s

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Lifetimes	Time	0x425D	Time Spent In LT RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4261	Time Spent In LT RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4265	Time Spent In STL RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4269	Time Spent In STL RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x426D	Time Spent In STL RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4271	Time Spent In STL RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4275	Time Spent In STL RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4279	Time Spent In STL RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x427D	Time Spent In STL RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4281	Time Spent In STL RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4285	Time Spent In RT RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4289	Time Spent In RT RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x428D	Time Spent In RT RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4291	Time Spent In RT RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4295	Time Spent In RT RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4299	Time Spent In RT RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x429D	Time Spent In RT RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42A1	Time Spent In RT RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42A5	Time Spent In STH RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42A9	Time Spent In STH RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42AD	Time Spent In STH RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42B1	Time Spent In STH RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42B5	Time Spent In STH RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42B9	Time Spent In STH RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42BD	Time Spent In STH RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42C1	Time Spent In STH RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42C5	Time Spent In HT RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42C9	Time Spent In HT RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42CD	Time Spent In HT RSOC C	U4	0	4.2949672 95e+009	0	s

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Lifetimes	Time	0x42D1	Time Spent In HT RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42D5	Time Spent In HT RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42D9	Time Spent In HT RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42DD	Time Spent In HT RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42E1	Time Spent In HT RSOC H	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42E5	Time Spent In OT RSOC A	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42E9	Time Spent In OT RSOC B	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42ED	Time Spent In OT RSOC C	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42F1	Time Spent In OT RSOC D	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42F5	Time Spent In OT RSOC E	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42F9	Time Spent In OT RSOC F	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x42FD	Time Spent In OT RSOC G	U4	0	4.2949672 95e+009	0	s
Lifetimes	Time	0x4301	Time Spent In OT RSOC H	U4	0	4.2949672 95e+009	0	s
Ra Table	R_a0	0x4100	Cell0 R_a flag	H2	0x0	0xFFFF	0xFF55	—
Ra Table	R_a0	0x4102	Cell0 R_a 0	I2	0	32767	159	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4104	Cell0 R_a 1	I2	0	32767	58	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4106	Cell0 R_a 2	I2	0	32767	65	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4108	Cell0 R_a 3	I2	0	32767	79	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x410A	Cell0 R_a 4	I2	0	32767	90	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x410C	Cell0 R_a 5	I2	0	32767	63	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x410E	Cell0 R_a 6	I2	0	32767	76	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4110	Cell0 R_a 7	I2	0	32767	82	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4112	Cell0 R_a 8	I2	0	32767	82	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4114	Cell0 R_a 9	I2	0	32767	87	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4116	Cell0 R_a 10	I2	0	32767	87	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x4118	Cell0 R_a 11	I2	0	32767	101	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x411A	Cell0 R_a 12	I2	0	32767	118	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x411C	Cell0 R_a 13	I2	0	32767	191	2 ⁻¹⁰ Ω
Ra Table	R_a0	0x411E	Cell0 R_a 14	I2	0	32767	282	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4140	xCell0 R_a flag	H2	0x0	0xFFFF	0xFFFF	—
Ra Table	R_a0x	0x4142	xCell0 R_a 0	I2	0	32767	159	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4144	xCell0 R_a 1	I2	0	32767	58	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4146	xCell0 R_a 2	I2	0	32767	65	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4148	xCell0 R_a 3	I2	0	32767	79	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x414A	xCell0 R_a 4	I2	0	32767	90	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x414C	xCell0 R_a 5	I2	0	32767	63	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x414E	xCell0 R_a 6	I2	0	32767	76	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4150	xCell0 R_a 7	I2	0	32767	82	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4152	xCell0 R_a 8	I2	0	32767	82	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4154	xCell0 R_a 9	I2	0	32767	87	2 ⁻¹⁰ Ω

Table 14-1. Data Flash Table (continued)

Class	Subclass	Address	Name	Type	Min Value	Max Value	Default	Units
Ra Table	R_a0x	0x4156	xCell0 R_a 10	I2	0	32767	87	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x4158	xCell0 R_a 11	I2	0	32767	101	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x415A	xCell0 R_a 12	I2	0	32767	118	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x415C	xCell0 R_a 13	I2	0	32767	191	2 ⁻¹⁰ Ω
Ra Table	R_a0x	0x415E	xCell0 R_a 14	I2	0	32767	282	2 ⁻¹⁰ Ω

Revision History



NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision B (March 2020) to Revision C (March 2024)	Page
• Added BQ27Z558 device.....	9
• Changed IT Gauging Cofiguration to IT Gauging Ext for location of this bit.....	29

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